

***Depletion interaction measured by colloidal probe atomic force microscopy***

Author(s): W.K. Wijting, W. Knoben, N.A.M. Besseling, F.A.M. Leermakers, M.A. Cohen Stuart  
Source: PCCP: Physical Chemistry Chemical Physics, 6 (2004), 18 (September 02), 4432-4439

***Microstructure of amorphous carbon nitride films fabricated by facing-target reactive magnetron sputtering***

Author(s): X.C. Wang, P. Wu, Z.Q. Li, E.Y. Jiang, H.L. Bai  
Source: Journal of Physics D: Applied Physics, 37 (2004), 15 (August 07), 2127-2134

***Correlation between crystallinity and magnetism in a series of laser-ablated anatase  $Ti_{1-x}Co_xO_2$  thin films***

Author(s): Nguyen Hoa Hong, W. Prellier, Joe Sakai, Antoine Ruyter  
Source: Journal of Physics: Condensed Matter, 16 (2004), 30 (August 04), 5549-5554

***Nanometre moire fringes in scanning tunnelling microscopy of surface lattices***

Author(s): H.M. Guo, H.W. Liu, Y.L. Wang, H.J. Gao, H.X. Shang, Z.W. Liu, H.M. Xie, F.L. Dai  
Source: Nanotechnology, 15 (2004), 8 (August 01), 991-995

***Influence of strontium concentration on the structural, morphological, and electrical properties of lead zirconate titanate thin films***

Author(s): C.E.F. Costa, F.M. Pontes, A.G. Souza, E.R. Leite, P.S. Pizani, E. Longo  
Source: Applied Physics A: Materials Science & Processing, 79 (2004), 3 (August), 593-597

***Dental enamel-a biological ceramic: regular substructures in enamel hydroxyapatite crystals revealed by atomic force microscopy***

Author(s): Colin Robinson, Simon Connell, Jennifer Kirkham, Roger Shore, Alastair Smith  
Source: Journal of Materials Chemistry, 14 (2004), 14 (July 14), 2242-2248

***Failure mechanism of free standing single-walled carbon nanotube thin films under tensile load***

Author(s): Sharali Malik, Harald Rosner, Frank Hennrich, Artur Bottcher, Manfred M. Kappes, Tilmann Beck, Markus Auhorn  
Source: PCCP: Physical Chemistry Chemical Physics, 6 (2004), 13 (July 05), 3540-3544

***Evidence for c-axis correlated vortex pinning in  $YBa_2Cu_3O_{7-d}$  films on sapphire buffered with an atomically flat  $CeO_2$  layer having a high density of nanodots***

Author(s): J.C. Nie, H. Yamasaki, H. Yamada, Y. Nakagawa, K. Develos-Bagarinao, Y. Mawatari  
Source: Superconductor Science and Technology, 17 (2004), 7 (July 01), 845-852

***Tungsten-oxide thin films as novel materials with high sensitivity and selectivity to  $NO_2$ ,  $O_3$  and  $H_2S$ . Part I: Preparation and microstructural characterization of the tungsten-oxide thin films***

Author(s): O. Berger, W.-J. Fischer, V. Melev  
Source: Journal of Materials Science: Materials in Electronics, 15 (2004), 7 (July), 463-482

***Chemical Structure and Micro-Mechanical Properties of Ultra-Thin Films of Boron Carbide Prepared by Pulsed-Laser Deposition***

Author(s): J. Sun, H. Ling, W.J. Pan, N. Xu, Z.F. Ying, W.D. Shen, J.D. Wu  
Source: Tribology Letters, 17 (2004), 1 (July), 99-104

***Surface-controlled self-assembly of chiral sexithiophenes***

Author(s): Philippe Leclere, Mathieu Surin, Roberto Lazzaroni, Andreas F.M. Kilbinger, Oliver Henze, Pascal Jonkheijm, Fabio Biscarini, Massimiliano Cavallini, W. James Feast, E.W. Meijer, Albertus P.H.J. Schenning  
Source: Journal of Materials Chemistry, 14 (2004), 13 (June 28), 1959-1963

***Crystallite structure formation at the collapse pressure of fatty acid Langmuir films***

Author(s): M.A. Valdes-Covarrubias, R.D. Cadena-Nava, E. Vásquez-Martínez, D. Valdez-Pérez, J. Ruiz-García  
Source: Journal of Physics: Condensed Matter, 16 (2004), 22 (June 09), S2097-S2107

***Preparation and optimization of ZnO films on single-crystal diamond substrate by metal-organic chemical vapour deposition***

Author(s): Baijun Zhao, Hongjun Yang, Guotong Du, Xiujun Fang, Dali Liu, Chunxiao Gao, Xizhe Liu, Bin Xie  
Source: Semiconductor Science and Technology, 19 (2004), 6 (June 01), 770-773

***Functionalization of Electrode Surfaces with Monolayers of Azocompounds and Gold Clusters***

Author(s): Krzysztof Stolarczyk, Renata Bilewicz, Anna Skwierawska, Jan F. Biernat

Source: Journal of Inclusion Phenomena, 49 (2004), 1 (June), 173-179

***Layered structures of shear-oriented and multilayered PEO/silicate nanocomposite films***

Author(s): Matthew M. Malwitz, Avinash Dundigalla, Vincent Ferreira, Paul D. Butler, Margaret C. Henk, Gudrun Schmidt

Source: PCCP: Physical Chemistry Chemical Physics, 6 (2004), 11 (May 25), 2977-2982

***Growth of Ga<sub>2</sub>O<sub>3</sub> thin films on Si(100) substrates using a trimethylgallium and oxygen mixture***

Author(s): Hyoun Woo Kim, Nam Ho Kim, Chongmu Lee

Source: Journal of Materials Science (full set), 39 (2004), 10 (May 15), 3461-3463

***Adsorbed layer structure of a weak polyelectrolyte studied by colloidal probe microscopy and QCM-D as a function of pH and ionic strength***

Author(s): Shannon M. Notley, Simon Biggs, Vincent S.J. Craig, Lars Wagberg

Source: PCCP: Physical Chemistry Chemical Physics, 6 (2004), 9 (May 06), 2379-2386

***Fabrication and Corrosion Behaviour of Platinum-Coated Titanium Electrodes from Low Temperature Molten Salt Electrolytes***

Author(s): W-H. Wu, C-C. Lin, C-C. Yang

Source: Journal of Applied Electrochemistry, 34 (2004), 5 (May), 525-531

***Protective Properties of An Inhibitor Layer Formed on Copper in Neutral Chloride Solution***

Author(s): H. Otmacic, J. Telegdi, K. Papp, E. Stupnisek-Lisac

Source: Journal of Applied Electrochemistry, 34 (2004), 5 (May), 545-550

***Effects R<sup>3+</sup> on the photoluminescent properties of Ca<sub>2</sub>R<sub>8</sub>(SiO<sub>4</sub>)<sub>6</sub>O<sub>2</sub>:A (R = Y,La,Gd;A = Eu<sup>3+</sup>,Tb<sup>3+</sup>) phosphor films prepared by the sol-gel process***

Author(s): X.M. Han, J. Lin, H.L. Zhou, M. Yu, Y.H. Zhou, M.L. Pang

Source: Journal of Physics: Condensed Matter, 16 (2004), 15 (April 21), 2745-2755

***Do alkyl tunnelling barriers contribute to molecular rectification?***

Author(s): Geoffrey J. Ashwell, Robert J. Stokes

Source: Journal of Materials Chemistry, 14 (2004), 8 (April 07), 1228-1230

***Interactions between bovine serum albumin layers adsorbed on different substrates measured with an atomic force microscope***

Author(s): Juan Jose Valle-Delgado, Jose Antonio Molina-Bolivar, Francisco Galisteo-Gonzalez, Maria Jose Galvez-Ruiz, Adam Feiler, Mark Rutland

Source: PCCP: Physical Chemistry Chemical Physics, 6 (2004), 7 (March 24), 1482-1486

***Colloid probe investigation of the stabilization mechanism in aqueous 1,2-propanediol nano-zirconia dispersions***

Author(s): C. Renger, P. Kuschel, A. Kristoffersson, B. Clauss, W. Oppermann, W. Sigmund

Source: PCCP: Physical Chemistry Chemical Physics, 6 (2004), 7 (March 24), 1467-1474

***Surface micelles of semifluorinated alkanes in Langmuir-Blodgett monolayers***

Author(s): Guifang Zhang, Mounir Maaloum, Pierre Muller, Nicole Benoit, Marie Pierre Krafft

Source: PCCP: Physical Chemistry Chemical Physics, 6 (2004), 7 (March 24), 1566-1569

***Forces between sulfonate self-assembled monolayers (SAMs) and zirconia particles in aqueous solutions***

Author(s): Yin Tang, Mark R. De Guire

Source: Journal of Materials Chemistry, 14 (2004), 7 (March 23), 1173-1179

***Growth of aligned SWNT arrays from water-soluble molecular clusters for nanotube device fabrication***

Author(s): Shaoming Huang, Qiang Fu, Lei An, Jie Liu

Source: PCCP: Physical Chemistry Chemical Physics, 6 (2004), 6 (March 10), 1077-1079

***Two-dimensional large-size YBa<sub>2</sub>Cu<sub>3</sub>O<sub>7</sub> films (30 × 10 cm<sup>2</sup>) on CeO<sub>2</sub>-buffered sapphire by a coating pyrolysis process***

Author(s): T. Manabe, M. Sohma, I. Yamaguchi, W. Kondo, K. Tsukada, S. Mizuta, T. Kumagai

Source: Superconductor Science and Technology, 17 (2004), 3 (March 01), 354-357

***Ni overlayers on biaxially textured Ni-alloy and Cu substrates by DC sputtering***

Author(s): N.A. Rutter, A. Goyal, C.E. Vallet, F.A. List, D.F. Lee, L. Heatherly, D.M. Kroeger

Source: Superconductor Science and Technology, 17 (2004), 3 (March 01), 527-531

***Surface morphological properties of sol-gel derived SiO<sub>2</sub> fiber***

Author(s): Kyu-Seog Hwang, Jeong-Tae Kwon, Jeong-Sun Oh, Jun-Hyung An, Byung-Hoon Kim  
Source: Journal of Materials Science (full set), 39 (2004), 5 (March 01), 1683-1687

***Grain boundary energy vs. misorientation in Inconel<sup>®</sup> 600 alloy as measured by thermal groove and OIM analysis correlation***

Author(s): T. Skidmore, R.G. Buchheit, M.C. Juhas  
Source: Scripta Materialia, 50 (2004), 6 (March), 873-877

***The effects of annealing on the structures and electrical conductivities of fullerene-derived nanowires***

Author(s): Yu-Guo Guo, Li-Jun Wan, Cong-Ju Li, Dong-Min Chen, Chen Wang, Chun-Ru Wang, Chun-Li Bai, Yan-Guo Wang  
Source: Journal of Materials Chemistry, 14 (2004), 5 (February 26), 914-918

***Hydriding properties of nanocrystalline Mg<sub>2-x</sub>M<sub>x</sub>Ni alloys synthesized by mechanical alloying (M=Mn, Al)***

Author(s): A. Gasiorowski, W. Iwasieczko, D. Skoryna, H. Drulis, M. Jurczyk  
Source: Journal of Alloys and Compounds, 364 (2004), 1-2 (February 11), 283-288

***The structure and tribological properties of gradient layers prepared by plasma-based ion implantation on 2024 Al alloy***

Author(s): J.X. Liao, L.F. Xia, M.R. Sun, W.M. Liu, T. Xu, Q.J. Xue  
Source: Journal of Physics D: Applied Physics, 37 (2004), 3 (February 07), 392-399

***Role of molecular oxygen in the dissolution of siderite and rhodochrosite***

Author(s): O.W. Duckworth, S.T. Martin  
Source: Geochimica et Cosmochimica Acta, 68 (2004), 3 (February 01), 607-621

***Growth of epitaxial CeO<sub>2</sub> thin films on r-cut sapphire by molecular beam epitaxy***

Author(s): J. Kurian, M. Naito  
Source: Physica C: Superconductivity and its Applications, 402 (2004), 1-2 (February 01), 31-37

***Atomic force microscopy of growth and dissolution of calcium oxalate monohydrate (COM) crystals***

Author(s): N.V. Gvozdev, E.V. Petrova, T.G. Chernevich, O.A. Shustin, L.N. Rashkovich  
Source: Journal of Crystal Growth, 261 (2004), 4 (February 01), 539-548

***Observation of stable mixed alkanethiolate-chloride adlayer on Ag(111): structural correlation with pure alkanethiolate monolayers***

Author(s): M. Kawasaki, H. Nagayama  
Source: Surface Science, 549 (2004), 3 (February 01), 237-245

***Relation between surface preconditioning and metal deposition in direct galvanic metallization of insulating surfaces***

Author(s): T.T. Mai, J.W. Schultze, G. Staikov  
Source: Journal of Solid State Electrochemistry, 8 (2004), 3 (February), 201-208

***Influence of Surfactant and Humidity on Sol-Gel Macroporous Organosilicate Coatings***

Author(s): K. Wongcharee, M. Brungs, R. Chaplin, Y.J. Hong, E. Sizgek  
Source: Journal of Sol-Gel Science and Technology, 29 (2004), 2 (February), 115-124

***Microstructural and optical characterization of CaWO<sub>4</sub> and SrWO<sub>4</sub> thin films prepared by a chemical solution method***

Author(s): M.A.M.A. Maurera, A.G. Souza, L.E.B. Soledade, F.M. Pontes, E. Longo, E.R. Leite, J.A. Varela  
Source: Materials Letters, 58 (2004), 5 (February), 727-732

***Structural and optical properties of Bi<sub>4-x</sub>Nd<sub>x</sub>Ti<sub>3</sub>O<sub>12</sub> thin films prepared by metal-organic solution deposition***

Author(s): Y. Wang, G. Xu, X. Zhang, Y. Feng, W. Tang, G. Cheng, Y. Zhu  
Source: Materials Letters, 58 (2004), 5 (February), 813-816

***Properties of a Co/Cu/Co spin-valve system prepared by an optimized 193 nm pulsed laser deposition process***

Author(s): M. Krieger, A. Plettl, R. Steiner, H.-G. Boyen, P. Ziemann  
Source: Applied Physics A: Materials Science & Processing, 78 (2004), 3 (February), 327-333

***Temperature effects on the growth of oxide islands on Cu(110)***

Author(s): G. Zhou, J.C. Yang

Source: Applied Surface Science, 222 (2004), 1-4 (January 30), 357-364

***Directed, selective insertion of single molecules into patterned self-assembled monolayers of alkanethiols with different chain lengths***

Author(s): Xue-Mei Li, Tommaso Auletta, Frank C.J.M. van Veggel, Jurriaan Huskens, David N. Reinhoudt

Source: Organic & Biomolecular Chemistry, 2 (2004), 3 (January 28), 296-300

***Fullerene monolayers adsorbed on high index gold single crystal surfaces***

Author(s): Akiyoshi Kuzume, Enrique Herrero, Juan M. Feliu, Richard J. Nichols, David J. Schiffrin

Source: PCCP: Physical Chemistry Chemical Physics, 6 (2004), 3 (January 26), 619-625

***Controls by saturation state on etch pit formation during calcite dissolution***

Author(s): H.H. Teng

Source: Geochimica et Cosmochimica Acta, 68 (2004), 2 (January 15), 253-262

***Phenomena and mechanisms of mixed crystal formation in solutions II. Mechanism of interface processes***

Author(s): A.E. Voloshin, S.I. Kovalev, E.B. Rudneva, A.E. Glikin

Source: Journal of Crystal Growth, 261 (2004), 1 (January 15), 105-117

***Growth mode and structural characterization of epitaxial TM/RE thin films***

Author(s): P. Pankowski, S. Pizzini, J.B. Pelka, A. Wawro, L.T. Baczewski

Source: Journal of Alloys and Compounds, 362 (2004), 1-2 (January 14), 56-60

***The fabrication of self-aligned InAs nanostructures on GaAs(331)A substrates***

Author(s): Z. Gong, Z.D. Fang, X.H. Xu, Z.H. Miao, H.Q. Ni, Z.C. Niu, S.L. Feng

Source: Journal of Physics: Condensed Matter, 16 (2004), 1 (January 14), 29-35

***AFM investigation of step kinetics and hillock morphology of the {100} face of KDP***

Author(s): T.N. Thomas, T.A. Land, T. Martin, W.H. Casey, J.J. DeYoreo

Source: Journal of Crystal Growth, 260 (2004), 3-4 (January 09), 566-579

***Self-organized novel morphologies of lamellar aluminophosphates***

Author(s): James G.C. Shen

Source: Journal of Materials Chemistry, 14 (2004), 2 (January 08), 258-262

***Exfoliation and film preparation of a layered titanate, Na<sub>2</sub>Ti<sub>3</sub>O<sub>7</sub>, and intercalation of pseudoisocyanine dye***

Author(s): Nobuyoshi Miyamoto, Kazuyuki Kuroda, Makoto Ogawa

Source: Journal of Materials Chemistry, 14 (2004), 2 (January 08), 165-170

***Self-assembly and film stability of a micelle of a single-chain quaternary ammonium amphiphile containing azobenzene on mica***

Author(s): X. Hou, L. Sun, B. Zou, L. Wu

Source: Materials Letters, 58 (2004), 3-4 (January), 369-372

***Synthesis of nanostructured zirconia electrodeposited films on AISI 316L stainless steel and its behaviour in corrosion resistance assessment***

Author(s): I. Espitia-Cabrera, H. Orozco-Hernandez, R. Torres-Sanchez, M.E. Contreras-Garcia, P. Bartolo-Perez, L. Martinez

Source: Materials Letters, 58 (2004), 1-2 (January), 191-195

***In situ STM study of the duplex passive films formed on Cu(111) and Cu(001) in 0.1 M NaOH***

Author(s): J. Kunze, V. Maurice, L.H. Klein, H.-H. Strehblow, P. Marcus

Source: Corrosion Science, 46 (2004), 1 (January), 245-264

***Site-selective deposition and micropatterning of tantalum oxide thin films using a monolayer***

Author(s): Y. Masuda, S. Wakamatsu, K. Koumoto

Source: Journal of the European Ceramic Society, 24 (2004), 2, 301-307

***Hydrothermal processing of nanocrystalline anatase films from tetraethylammonium hydroxide peptized titania sols***

Author(s): J. Yang, S. Mei, J.M.F. Ferreira  
Source: Journal of the European Ceramic Society, 24 (2004), 2, 335-339

***Characteristics of carbon films prepared by plasma-based ion implantation***

Author(s): J.X. Liao, W.M. Liu, T. Xu, Q.J. Xue  
Source: Carbon, 42 (2004), 2, 387-393

***SrBi<sub>2</sub>Nb<sub>2</sub>O<sub>9</sub> Thin films crystallized using a low power microwave oven***

Author(s): S.M. Zanetti, J.S. Vasconcelos, N.S.L.S. Vasconcelos, E.R. Leite, E. Longo, J.A. Varela  
Source: Journal of the European Ceramic Society, 24 (2004), 6, 1597-1602

***Initial surface topography changes during divalent dissolution of silicon electrodes***

Author(s): J. Jakubowicz, H. Jungblut, H.J. Lewerenz  
Source: Electrochimica Acta, 49 (2003), 1 (December 30), 137-146

***Growth, structural, and magnetic properties of iron nitride thin films deposited by dc magnetron sputtering***

Author(s): X. Wang, W.T. Zheng, H.W. Tian, S.S. Yu, W. Xu, S.H. Meng, X.D. He, J.C. Han, C.Q. Sun, B.K. Tay  
Source: Applied Surface Science, 220 (2003), 1-4 (December 30), 30-39

***Frictional force microscopic detection of frictional asymmetry and anisotropy at (1014) surface of calcite***

Author(s): Musun Kwak, Hitoshi Shindo  
Source: PCCP: Physical Chemistry Chemical Physics, 6 (2003), 1 (December 19), 129-133

***Preparation of a novel clay/metal complex hybrid film and its catalytic oxidation to chiral 1,1'-binaphthol***

Author(s): J. He, H. Sato, P. Yang, A. Yamagishi  
Source: Journal of Electroanalytical Chemistry, 560 (2003), 2 (December 15), 169-174

***Properties of fluorinated amorphous diamond like carbon films by PECVD***

Author(s): G.Q. Yu, B.K. Tay, Z. Sun, L.K. Pan  
Source: Applied Surface Science, 219 (2003), 3-4 (December 15), 228-237

***Self-assembled stripes on the anodic aluminum oxide by atomic force microscope observation***

Author(s): H.W. Liu, H.M. Guo, Y.L. Wang, Y.T. Wang, C.M. Shen, L. Wei  
Source: Applied Surface Science, 219 (2003), 3-4 (December 15), 282-289

***Mesodomain separation in amalgamated J aggregate formation of cyanine dyes at a mica/solution interface***

Author(s): H. Yao, Y. Morita, K. Kimura  
Source: Surface Science, 546 (2003), 2-3 (December 01), 97-106

***Friction and wear at nanometer scale: a comparative study of hard carbon films***

Author(s): R. Prioli, M. Chhowalla, F.L. Freire  
Source: Diamond and Related Materials, 12 (2003), 12 (December), 2195-2202

***Formulation effects on the distribution of pigment particles in paints***

Author(s): F. Tiarks, T. Frechen, S. Kirsch, J. Leuninger, M. Melan, A. Pfau, F. Richter, B. Schuler, C.-L. Zhao  
Source: Progress in Organic Coatings, 48 (2003), 2-4 (December), 140-152

***Surface textures induced by convection in thin films of polymeric and polymerizable fluids***

Author(s): S. Xu, M. Li, Z. Mitov, E. Kumacheva  
Source: Progress in Organic Coatings, 48 (2003), 2-4 (December), 227-235

***Multianalytical in-situ investigations of the early stages of corrosion of copper, zinc and binary copper/zinc alloys***

Author(s): C. Kleber, M. Schreiner  
Source: Corrosion Science, 45 (2003), 12 (December), 2851-2866

***Enhancement of near-band-edge photoluminescence from ZnO films by face-to-face annealing***

Author(s): Y.G. Wang, S.P. Lau, X.H. Zhang, H.H. Hng, H.W. Lee, S.F. Yu, B.K. Tay  
Source: Journal of Crystal Growth, 259 (2003), 4 (December), 335-342

***Molecular aggregation and shape effects in the optical spectra of organic dye molecules in SiO<sub>2</sub> and SiO<sub>2</sub>-PMMA matrices***

Author(s): L.L. Diaz-Flores, P.P. Horley, J. Gonzalez-Hernandez, J.J. Perez-Bueno, Y.V. Vorobiev, P.M. Gorley  
Source: Journal of Physics and Chemistry of Solids, 64 (2003), 12 (December), 2409-2415

***Surface modification of a segmented polyetherurethane using a low-powered gas plasma and its influence on the activation of the coagulation system***

Author(s): D.J. Wilson, N.P. Rhodes, R.L. Williams  
Source: *Biomaterials*, 24 (2003), 28 (December), 5069-5081

***Frictional properties of poly(MPC-co-BMA) phospholipid polymer for catheter applications***

Author(s): S.P. Ho, N. Nakabayashi, Y. Iwasaki, T. Boland, M. LaBerge  
Source: *Biomaterials*, 24 (2003), 28 (December), 5121-5129

***Peptide functionalized poly(L-lysine)-g-poly(ethylene glycol) on titanium: resistance to protein adsorption in full heparinized human blood plasma***

Author(s): S. Tosatti, S.M.D. Paul, A. Askendal, S. VandeVondele, J.A. Hubbell, P. Tengvall, M. Textor  
Source: *Biomaterials*, 24 (2003), 27 (December), 4949-4958

***Molecular rectification: self-assembled monolayers of a donor-(p-bridge)-acceptor chromophore connected via a truncated Au-S-(CH<sub>2</sub>)<sub>3</sub> bridge***

Author(s): Geoffrey J. Ashwell, Wayne D. Tyrrell, Anne J. Whittam  
Source: *Journal of Materials Chemistry*, 13 (2003), 12 (November 26), 2855-2857

***Microstructural and transport properties of LaNiO<sub>3-d</sub> films grown on Si (111) by chemical solution deposition***

Author(s): M.T. Escote, F.M. Pontes, E.R. Leite, J.A. Varela, R.F. Jardim, E. Longo  
Source: *Thin Solid Films*, 445 (2003), 1 (November 24), 54-58

***Issues on development of (La,Sr)MnO<sub>3</sub> cathode for solid oxide fuel cells***

Author(s): S.P. Jiang  
Source: *Journal of Power Sources*, 124 (2003), 2 (November 24), 390-402

***In situ observation on Au(100) surface in molten EMImBF<sub>4</sub> by electrochemical atomic force microscopy (EC-AFM)***

Author(s): K. Kubo, N. Hirai, T. Tanaka, S. Hara  
Source: *Surface Science*, 546 (2003), 1 (November 20), L785-L788

***Formation of In<sub>2</sub>Se<sub>3</sub> thin films and nanostructures using electrochemical atomic layer epitaxy***

Author(s): R. Vaidyanathan, J.L. Stickney, S.M. Cox, S.P. Compton, U. Happek  
Source: *Journal of Electroanalytical Chemistry*, 559 (2003), (November 15), 55 - 61

***Survey of the metal nucleation processes on silicon surfaces in fluoride solutions: from dilute HF to concentrated NH<sub>4</sub>F solutions***

Author(s): M. Chemla, T. Homma, V. Bertagna, R. Erre, N. Kubo, T. Osaka  
Source: *Journal of Electroanalytical Chemistry*, 559 (2003), (November 15), 111 - 123

***Ozone sensing properties of DC-sputtered, c-axis oriented ZnO films at room temperature***

Author(s): N. Katsarakis, M. Bender, V. Cimalla, E. Gagaoudakis, G. Kiriakidis  
Source: *Sensors and Actuators B: Chemical*, 96 (2003), 1-2 (November 15), 76-81

***Annealing effects of highly homogeneous a-Si<sub>1-x</sub>C<sub>x</sub>:H***

Author(s): R.J. Prado, T.F. D'Addio, M.C.A. Fantini, I. Pereyra, A.M. Flank  
Source: *Journal of Non-Crystalline Solids*, 330 (2003), 1-3 (November 15), 196-215

***Heterobifunctional crosslinkers for tethering single ligand molecules to scanning probes***

Author(s): C.K. Riener, F. Kienberger, C.D. Hahn, G.M. Buchinger, I.O.C. Egwim, T. Haselgrubler, A. Ebner, C. Romanin, C. Klampfl, B. Lackner, H. Prinz, D. Blaas, P. Hinterdorfer, H.J. Gruber  
Source: *Analytica Chimica Acta*, 497 (2003), 1-2 (November 14), 101-114

***Microscopy of large-scale porphyrin aggregates formed from protonated TPP dimers in water-organic solutions***

Author(s): A.V. Udaltsov, M. Tosaka, G. Kaupp  
Source: *Journal of Molecular Structure*, 660 (2003), 1-3 (November 12), 15-23

***Growth of manganese oxide thin films by atomic layer deposition***

Author(s): O. Nilsen, H. Fjellvag, A. Kjekshus  
Source: *Thin Solid Films*, 444 (2003), 1-2 (November 01), 44-51

***Growth, structure and morphology of CoFe<sub>2</sub>/CoFe<sub>2</sub>O<sub>4</sub> multilayers***

Author(s): I.S. Jurca, C. Meny, N. Viart, C. Ulhaq-Bouillet, P. Panissod, G. Pourroy

Source: Thin Solid Films, 444 (2003), 1-2 (November 01), 58-63

***Field emission properties of vertically aligned carbon nanotubes grown on bias-enhanced hydrogen plasma-pretreated Cr film***

Author(s): C.-F. Chen, C.-L. Lin, C.-M. Wang

Source: Thin Solid Films, 444 (2003), 1-2 (November 01), 64-69

***Microstructural changes of stearic acid films by immersion in salt solution***

Author(s): X.-H. Li, M. Li, L. Huang, Z.-H. Mai

Source: Thin Solid Films, 444 (2003), 1-2 (November 01), 174-178

***Structure and dynamics of oxy-overlayer on Cu(111) electrode surfaces in alkaline aqueous solution revealed by electrochemical STM and quartz crystal microbalance measurement***

Author(s): O. Matsuoka, S. Sugiyama Ono, H. Nozoye, S. Yamamoto

Source: Surface Science, 545 (2003), 1-2 (November 01), 8-18

***The influence of the precursor clusters on the structural and morphological evolution of nanostructured TiO<sub>2</sub> under thermal annealing***

Author(s): I.N. Kholmanov, E. Barborini, S. Vinati, P. Piseri, A. Podest?, C. Ducati, C. Lenardi, P. Milani

Source: Nanotechnology, 14 (2003), 11 (November 01), 1168-1173

***MOD approach for the growth of epitaxial CeO<sub>2</sub> buffer layers on biaxially textured Ni-W substrates for YBCO coated conductors***

Author(s): M.S. Bhuiyan, M. Paranthaman, S. Sathyamurthy, T. Aytug, S. Kang, D.F. Lee, A. Goyal, E.A. Payzant, K. Salama

Source: Superconductor Science and Technology, 16 (2003), 11 (November 01), 1305-1309

***Ion crater healing and variable temperature ellipsometry as complementary probes for the glass transition in thin polymer films***

Author(s): Y. Grohens, R.M. Papaleo, L. Hamon

Source: The European Physical Journal E (EPJ E), 12 (2003), S1 (November), 81-85

***Phase transition behavior of highly (100) textured sol-gel-derived Ba<sub>0.5</sub>Sr<sub>0.5</sub>TiO<sub>3</sub> thin films***

Author(s): M. Jain, S.B. Majumder, R.S. Katiyar, S.B. Desu

Source: Applied Physics A: Materials Science & Processing, 77 (2003), 6 (November), 789-792

***Photocrosslinked surface relief gratings on azobenzene-containing copolymer films***

Author(s): H. Takase, A. Natansohn, P. Rochon

Source: Polymer, 44 (2003), 24 (November), 7345-7351

***The adhesion of amorphous polystyrene surfaces below T<sub>g</sub>***

Author(s): G. Guerin, F. Mauger, R.E. Prud'homme

Source: Polymer, 44 (2003), 24 (November), 7477-7484

***Electrical properties of W/Si interfaces with embedded Ge/Si islands***

Author(s): A. Hattab, F. Meyer, V. Yam, D. Bouchier, R. Meyer, O. Schneegans, C. Clerc

Source: Microelectronic Engineering, 70 (2003), 2-4 (November), 240-245

***Reactively sputtered tantalum pentoxide thin films for integrated capacitors***

Author(s): T. Riekkinen, J. Molarius

Source: Microelectronic Engineering, 70 (2003), 2-4 (November), 392-397

***Alteration of wettability and inhibition of corrosion in narrow aluminium 7075 gaps by thin polymer films***

Author(s): O.M. Matarredona, K. Mach, M.M. Rieger, E.A. O'Rear

Source: Corrosion Science, 45 (2003), 11 (November), 2541-2562

***Crystal growth rates of diblock copolymers in thin films: Influence of film thickness***

Author(s): G. Reiter, L. Vidal

Source: The European Physical Journal E (EPJ E), 12 (2003), 3 (November), 497-505

***Ohmic contact properties of Ni/C film on 4H-SiC***

Author(s): W. Lu, W.C. Mitchel, G.R. Landis, T.R. Crenshaw, W.E. Collins  
Source: Solid-State Electronics, 47 (2003), 11 (November), 2001-2010

***Influence of particle size on the conductance of SnO<sub>2</sub> thick films***

Author(s): M.A. Ponce, C.M. Aldao, M.S. Castro  
Source: Journal of the European Ceramic Society, 23 (2003), 12 (November), 2105-2111

***Gold and alloy nanoparticles in solution and thin film assembly: spectrophotometric determination of molar absorptivity***

Author(s): M.M. Maye, L. Han, N.N. Kariuki, N.K. Ly, W.-B. Chan, J. Luo, C.-J. Zhong  
Source: Analytica Chimica Acta, 496 (2003), 1-2 (October 31), 17-27

***Redox and solution chemistry of the SeSO<sub>3</sub><sup>2-</sup>-Zn-EDTA<sup>2-</sup> system and electrodeposition behavior of ZnSe from alkaline solutions***

Author(s): G. Riveros, D. Lincot, J.F. Guillemoles, R. Henriquez, R. Schrebler, R. Cordova, H. Gomez  
Source: Journal of Electroanalytical Chemistry, 558 (2003), (October 30), 9 - 17

***Scanning probe microscopy investigation of gold clusters deposited on atomically flat substrates***

Author(s): N. Vandamme, E. Janssens, F. Vanhoutte, P. Lievens, C. Van Haesendonck  
Source: Journal of Physics: Condensed Matter, 15 (2003), 42 (October 29), S2983-S2999

***XPS studies of chemically etched surfaces of (La,Sr)(Al,Ta)O<sub>3</sub> single crystals***

Author(s): E. Talik, M. Kruczek, H. Sakowska, W. Szyrski  
Source: Journal of Alloys and Compounds, 361 (2003), 1-2 (October 27), 282-288

***The preparation of novel nano-structured polymer blends of ultra high molecular weight polyethylene with polymethacrylates using supercritical carbon dioxide***

Author(s): Andrew J. Busby, Jianxin Zhang, Andrew Naylor, Clive J. Roberts, Martyn C. Davies, Saul J.B. Tendler, Steven M. Howdle  
Source: Journal of Materials Chemistry, 13 (2003), 11 (October 27), 2838-2844

***A study of the surface deformation behaviour at grain boundaries in an ultra-low-carbon steel***

Author(s): D. Chandrasekaran, M. Nygard  
Source: Acta Materialia, 51 (2003), 18 (October 20), 5375-5384

***Self-assembled multilayer superstructures as immobilization support for bioreceptors***

Author(s): B.A. Snopok, Y.G. Goltsov, E.V. Kostyukevich, L.A. Matkovskaja, Y.M. Shirshov, E.F. Venger  
Source: Sensors and Actuators B: Chemical, 95 (2003), 1-3 (October 15), 336-343

***Coherent emission from crystalline oligothiophenes with an even number of rings***

Author(s): M. Cerminara, F. Meinardi, A. Borghesi, M. Campione, A. Sassella, P. Spearman, G. Bongiovanni, A. Mura, R. Tubino  
Source: Synthetic Metals, 139 (2003), 3 (October 09), 765-768

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Author(s): K. Tanaka  
Source: Journal of Non-Crystalline Solids, 326-327 (2003), (October 01), 21-28

***Measurement and interpretation of molecular-level forces of interaction between the siderophore azotobactin and mineral surfaces***

Author(s): T.A. Kendall, M.F. Hochella  
Source: Geochimica et Cosmochimica Acta, 67 (2003), 19 (October 01), 3537-3546

***Ultrathin micropatterned porphyrin films assembled via zirconium phosphonate chemistry***

Author(s): A.M. Massari, R.W. Gurney, M.D. Wightman, C.-H.K. Huang, S.T. Nguyen, J.T. Hupp  
Source: Polyhedron, 22 (2003), 22 (October 01), 3065-3072

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Author(s): C. Marieta, P.M. Remiro, G. Garmendia, I. Harismendy, I. Mondragon  
Source: European Polymer Journal, 39 (2003), 10 (October), 1965-1973

***The effect of hard and soft segment composition and molecular architecture on the morphology and mechanical properties of polystyrene-polyisobutylene thermoplastic elastomeric block copolymers***

Author(s): J.E. Puskas, P. Antony, M. El Fray, V. Altstadt  
Source: European Polymer Journal, 39 (2003), 10 (October), 2041-2049

***Effect of anneal temperature on GaN nucleation layer transformation***

Author(s): M. Lada, A.G. Cullis, P.J. Parbrook  
Source: Journal of Crystal Growth, 258 (2003), 1-2 (October), 89-99

***Morphological instabilities during growth of a rough interface: AFM observations of cobbles on the (0001) face of synthetic quartz crystals***

Author(s): M. Kawasaki, K. Onuma, I. Sunagawa  
Source: Journal of Crystal Growth, 258 (2003), 1-2 (October), 188-196

***Electrical properties of Sr<sub>3</sub>Bi<sub>4</sub>Ti<sub>6</sub>O<sub>21</sub> thin films***

Author(s): S.T. Zhang, B. Yang, X.J. Zhang, Y.F. Chen, Z.G. Liu, N.B. Ming, X.Q. Pan  
Source: Applied Physics A: Materials Science & Processing, 77 (2003), 5 (October), 645-647

***Spectroscopic ellipsometry of 3,4,9,10-perylenetetracarboxylic dianhydride (PTCDA)***

Author(s): A.B. Djuricic, C.Y. Kwong, W.L. Guo, Z.T. Liu, H.S. Kwok, W.K. Chan  
Source: Applied Physics A: Materials Science & Processing, 77 (2003), 5 (October), 649-653

***The mechanism of adhesion and printability of plasma processed PET films***

Author(s): Rajendra R. Deshmukh, Narendra V. Bhat  
Source: Materials Research Innovations, 7 (2003), 5 (October), 283-290

***Comprehensive study of pulsed UV-laser modified polyamide fibers***

Author(s): Joanne Yip, Kwong Chan, Kwan Moon Sin, Kai Shui Lau  
Source: Materials Research Innovations, 7 (2003), 5 (October), 302-307

***Electrochemistry of nano-scale bacterial surface protein layers on gold***

Author(s): M. Handrea, M. Sahre, A. Neubauer, U.B. Sleytr, W. Kautek  
Source: Bioelectrochemistry, 61 (2003), 1-2 (October), 1-8

***Controlled biological response on blends of a phosphorylcholine-based copolymer with poly(butyl methacrylate)***

Author(s): S.F. Long, S. Clarke, M.C. Davies, A.L. Lewis, G.W. Hanlon, A.W. Lloyd  
Source: Biomaterials, 24 (2003), 23 (October), 4115-4121

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Author(s): T. Homma, N. Kubo, T. Osaka  
Source: Electrochimica Acta, 48 (2003), 20-22 (September 30), 3115 - 3122

***Selective palladium electrochemical deposition onto AFM-scratched silicon surfaces***

Author(s): L. Santinacci, T. Djenizian, H. Hildebrand, S. Ecoffey, H. Mokdad, T. Campanella, P. Schmuki  
Source: Electrochimica Acta, 48 (2003), 20-22 (September 30), 3123 - 3130

***Growth of anodic porous alumina with square cells***

Author(s): H. Asoh, S. Ono, T. Hirose, M. Nakao, H. Masuda  
Source: Electrochimica Acta, 48 (2003), 20-22 (September 30), 3171 - 3174

***Nano-mechano-electrochemical properties of passive titanium surfaces evaluated by in-situ nano-indentation and nano-scratching***

Author(s): M. Seo, Y. Kurata  
Source: Electrochimica Acta, 48 (2003), 20-22 (September 30), 3221 - 3228

***Electrochemical characterisation of aluminium AA7075-T6 and solution heat treated AA7075 using a micro-capillary cell***

Author(s): F. Andreatta, M.M. Lohrengel, H. Terryn, J.H.W. de Wit  
Source: Electrochimica Acta, 48 (2003), 20-22 (September 30), 3239 - 3247

***Influence of annealing temperature on the properties of titanium oxide thin film***

Author(s): Y.-Q. Hou, D.-M. Zhuang, G. Zhang, M. Zhao, M.-S. Wu  
Source: Applied Surface Science, 218 (2003), 1-4 (September 30), 98-106

***Study of the surface roughness of CVD-tungsten oxide thin films***

Author(s): R.E. Tanner, A. Szekeres, D. Gogova, K. Gesheva  
Source: Applied Surface Science, 218 (2003), 1-4 (September 30), 163-169

***Atomic force microscopy of the electrochemical reductive dissolution of sub-micrometer sized crystals of goethite immobilized on gold electrodes***

Author(s): U. Hasse, J. Nieszen, F. Scholz  
Source: Journal of Electroanalytical Chemistry, 556 (2003), (September 30), 13 - 22

***In situ scanning tunneling microscopy of electrodeposition of mercury on a well-ordered Ir(111) electrode***

Author(s): Y.-S. Yang, C.-H. Shu, C.-C. Liao, S.-L. Yau  
Source: Journal of Electroanalytical Chemistry, 556 (2003), (September 30), 53 - 62

***In situ STM study of the anodic oxidation of Cu(001) in 0.1 M NaOH***

Author(s): J. Kunze, V. Maurice, L.H. Klein, H.-H. Strehblow, P. Marcus  
Source: Journal of Electroanalytical Chemistry, 554-555 (2003), (September 15), 113 - 125

***Molecular adsorption at well-defined electrode surfaces: benzene on Pd(111) studied by EC-STM and HREELS***

Author(s): Y.-G. Kim, J.E. Soto, X. Chen, Y.-S. Park, M.P. Soriaga  
Source: Journal of Electroanalytical Chemistry, 554-555 (2003), (September 15), 167 - 174

***In situ STM studies of sulfur and thiocyanate adlayers on Cu(111) in alkaline solution***

Author(s): M. Sugimasa, J. Inukai, K. Itaya  
Source: Journal of Electroanalytical Chemistry, 554-555 (2003), (September 15), 285 - 291

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Author(s): F. Raimondi, J. Wambach, A. Wokaun  
Source: PCCP: Physical Chemistry Chemical Physics, 5 (2003), 18 (September 08), 4015-4024

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Author(s): L. Itzel Meza, Jonathan R. Agger, Natasa Z. Logar, Venceslav Kaucic, Michael W. Anderson  
Source: Chemical Communications, (2003), 18 (September 02), 2300-2301

***Tunnel barrier height oscillations at the solid/liquid interface***

Author(s): M. Hugelmann, W. Schindler  
Source: Surface Science, 541 (2003), 1-3 (September 01), L643-L648

***Influence of Si(100) surface pretreatment on the morphology of TiO<sub>2</sub> films grown by atomic layer deposition***

Author(s): K.S. Finnie, G. Triani, K.T. Short, D.R.G. Mitchell, D.J. Attard, J.R. Bartlett, C.J. Barbe  
Source: Thin Solid Films, 440 (2003), 1-2 (September 01), 109-116

***Atomic force microscopy studies of lateral phase separation in mixed monolayers of dipalmitoylphosphatidylcholine and dilauroylphosphatidylcholine***

Author(s): J. Sanchez, A. Badia  
Source: Thin Solid Films, 440 (2003), 1-2 (September 01), 223-239

***Micro-Raman spectroscopy study of surface transformations induced by excimer laser irradiation of TiO<sub>2</sub>***

Author(s): T.D. Robert, L.D. Laude, V.M. Geskin, R. Lazzaroni, R. Gouttebaron  
Source: Thin Solid Films, 440 (2003), 1-2 (September 01), 268-277

***Crystallization and phase separation in blends of high stereoregular poly(lactide) with poly(ethylene glycol)***

Author(s): Y. Hu, Y.S. Hu, V. Topolkaev, A. Hiltner, E. Baer  
Source: Polymer, 44 (2003), 19 (September), 5681-5689

***Aging of poly(lactide)/poly(ethylene glycol) blends. Part 1. Poly(lactide) with low stereoregularity***

Author(s): Y. Hu, M. Rogunova, V. Topolkaev, A. Hiltner, E. Baer  
Source: Polymer, 44 (2003), 19 (September), 5701-5710

***Aging of poly(lactide)/poly(ethylene glycol) blends. Part 2. Poly(lactide) with high stereoregularity***

Author(s): Y. Hu, Y.S. Hu, V. Topolkaev, A. Hiltner, E. Baer  
Source: Polymer, 44 (2003), 19 (September), 5711-5720

***Use of atomic force microscopy to quantify slip irreversibility in a nickel-base superalloy***

Author(s): M. Risbet, X. Feaugas, C. Guillemer-Neel, M. Clavel

Source: Scripta Materialia, 49 (2003), 6 (September), 533-538

***Measurement of residual-stress effect by nanoindentation on elastically strained (100) W***

Author(s): Y.-H. Lee, D. Kwon

Source: Scripta Materialia, 49 (2003), 5 (September), 459-465

***Surface morphology of titanium irradiated by high-intensity pulsed ion beam***

Author(s): X.P. Zhu, M.K. Lei, T.C. Ma

Source: Nuclear Instruments and Methods in Physics Research Section B: Beam Interactions with Materials and Atoms, 211 (2003), 1 (September), 69-79

***Electrical transconduction through organic layers Si-C bonded to silicon substrates***

Author(s): A. Scandurra, G. Indelli, G. Compagnini, S. Pignataro

Source: Microelectronic Engineering, 69 (2003), 2-4 (September), 532-535

***Molecular cluster based nanoelectronics***

Author(s): E.S. Soldatov, S.P. Gubin, I.A. Maximov, G.B. Khomutov, V.V. Kolesov, A.N. Sergeev-Cherenkov, V.V. Shorokhov, K.S. Sulaimankulov, D.B. Suyatin

Source: Microelectronic Engineering, 69 (2003), 2-4 (September), 536-548

***Bio-inspired approaches and biologically derived materials for coatings***

Author(s): R.R. Naik, L.L. Brott, F. Rodriguez, G. Agarwal, S.M. Kirkpatrick, M.O. Stone

Source: Progress in Organic Coatings, 47 (2003), 3-4 (September), 249-255

***Biomimetic multifunctional molecular coatings using engineered proteins***

Author(s): C. Tamerler, S. Dincer, D. Heidel, M. Hadi Zareie, M. Sarikaya

Source: Progress in Organic Coatings, 47 (2003), 3-4 (September), 267-274

***Synthetic and bio-hybrid nanoscale layers with tailored surface functionalities***

Author(s): V.V. Tsukruk, M. Ornatska, A. Sidorenko

Source: Progress in Organic Coatings, 47 (2003), 3-4 (September), 288-291

***Self-Assembly of Gold Nanoclusters on Molecularly Modified GaAs***

Author(s): Olivia Vidoni, Stefan Neumeier, Nathalie Bardou, Jean-Luc Pelouard, Gunter Schmid

Source: Journal of Cluster Science, 14 (2003), 3 (September), 325-336

***DNA-bound lipids: computer modeling of DNA interaction with stearic acid and unsaturated fatty acids***

Author(s): R.I. Zhdanov, E.P. Dyachkov, V.A. Struchkov, N.B. Strazhevskaya, P.N. Dyachkov

Source: Russian Chemical Bulletin, 52 (2003), 9 (September), 1893-1899

***Functionalized Self-Assembled Monolayers on Gold as Binding Matrices for the Screening of Antibody-Antigen Interactions***

Author(s): Michael Schaferling, Michael Riepl, Petra Pavlickova, Hubert Paul, Dev Kambhampati, Bo Liedberg

Source: Mikrochimica Acta, 142 (2003), 4 (August 25), 193-203

***AFM observations of self-assembled lambda DNA network on silanized mica***

Author(s): Z. Xiao, M. Xu, K. Sagisaka, D. Fujita

Source: Thin Solid Films, 438-439 (2003), (August 22), 114-117

***Fabrication and electrochemical properties of layer-by-layer deposited films containing phthalocyanine dyes***

Author(s): K. Shinbo, K. Onishi, S. Miyabayashi, K. Takahashi, S. Katagiri, K. Kato, F. Kaneko, R.C. Advincula

Source: Thin Solid Films, 438-439 (2003), (August 22), 177-181

***The properties of pulsed laser deposited YH<sub>2</sub> films for switchable devices***

Author(s): A.C. Lokhorst, M.C.R. Heijna, J.H. Rector, I.A.M.E. Giebels, N.J. Koeman, B. Dam

Source: Journal of Alloys and Compounds, 356-357 (2003), (August 11), 536-540

***Growth of ultrathin Ti films deposited on SnO<sub>2</sub> by magnetron sputtering***

Author(s): T. Godfroid, R. Gouttebaron, J.P. Dauchot, P. Leclere, R. Lazzaroni, M. Hecq

Source: Thin Solid Films, 437 (2003), 1-2 (August 01), 57-62

***STM investigation on interaction between superstructure and grain boundary in graphite***

Author(s): Y. Gan, W. Chu, L. Qiao

Source: Surface Science, 539 (2003), 1-3 (August 01), 120-128

***Gas response of reactively sputtered ZnO films on Si-based micro-array***

Author(s): Y. Min, H.L. Tuller, S. Palzer, J. Wollenstein, H. Bottner

Source: Sensors and Actuators B: Chemical, 93 (2003), 1-3 (August 01), 435-441

***Flash evaporated tungsten oxide thin films for electrochromic applications***

Author(s): P. Losier, P.V. Ashrit

Source: Journal of Materials Science Letters, 22 (2003), 15 (August 01), 1095-1098

***Influence of the roughness of molybdenum back electrode on the photodiode characteristics under He-Ne illumination***

Author(s): M. Ristova, Y. Kuo, S. Lee

Source: Semiconductor Science and Technology, 18 (2003), 8 (August 01), 788-793

***Effect of molecular structure of self-assembled monolayers on their tribological behaviors in nano- and microscales***

Author(s): H.-S. Ahn, P.D. Cuong, S. Park, Y.-W. Kim, J.-C. Lim

Source: Wear, 255 (2003), 7-12 (August), 819-825

***Modeling and simulation of the tool wear in nanometric cutting***

Author(s): K. Cheng, X. Luo, R. Ward, R. Holt

Source: Wear, 255 (2003), 7-12 (August), 1427-1432

***Track formation in amorphous  $Fe_{0.55}Zr_{0.45}$  alloys irradiated by MeV  $C_{60}$  ions: Influence of intrinsic stress on induced surface deformations***

Author(s): J.C. Girard, A. Michel, C. Tromas, C. Jaouen, S. Della-Negra

Source: Nuclear Instruments and Methods in Physics Research Section B: Beam Interactions with Materials and Atoms, 209 (2003), (August), 85-92

***Study of swift heavy ion tracks on crystalline quartz surfaces***

Author(s): N. Khalfaoui, C.C. Rotaru, S. Bouffard, E. Jacquet, H. Lebius, M. Toulemonde

Source: Nuclear Instruments and Methods in Physics Research Section B: Beam Interactions with Materials and Atoms, 209 (2003), (August), 165-169

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Author(s): J.W. Kurutz, M. Carvalho, Y. Nakagawa

Source: Journal of Crystal Growth, 255 (2003), 3-4 (August), 392-402

***Action of chelators on solid iron in phosphate-containing aqueous solutions***

Author(s): H. Harms, H.-P. Volkland, G. Repphun, A. Hiltolt, O. Wanner, A.J.B. Zehnder

Source: Corrosion Science, 45 (2003), 8 (August), 1717-1732

***Effect of solution heat treatment on galvanic coupling between intermetallics and matrix in AA7075-T6***

Author(s): F. Andreatta, H. Terry, J.H.W. de Wit

Source: Corrosion Science, 45 (2003), 8 (August), 1733-1746

***Nanostructured Gold Thin Films: Young Modulus Measurement***

Author(s): M.C. Salvadori, A.R. Vaz, L.L. Melo, M. Cattani

Source: Surface Review and Letters, 10 (2003), 4 (August), 571-575

***Nanoindentation stress-strain curves as a method for thin-film complete mechanical characterization: application to nanometric CrN/Cr multilayer coatings***

Author(s): E. Martinez, J. Romero, A. Lousa, J. Esteve

Source: Applied Physics A: Materials Science & Processing, 77 (2003), 3-4 (August), 419-427

***Seed layer corrosion of Damascene structures in copper sulfate electrolytes***

Author(s): N.M. Martyak, P. Ricou

Source: Materials Science in Semiconductor Processing, 6 (2003), 4 (August), 225-233

***Epitaxial growth of LiNbO<sub>3</sub> thin films in a microwave oven***

Author(s): N.S.L.S. Vasconcelos, J.S. Vasconcelos, V. Bouquet, S.M. Zanetti, E.R. Leite, E. Longo, L.E.B. Soledade, F.M. Pontes, M. Guilloux-Viry, A. Perrin, M.I. Bernardi, J.A. Varela  
Source: Thin Solid Films, 436 (2003), 2 (July 31), 213-219

***Surface roughness, mechanical and tribological properties of ultrathin tetrahedral amorphous carbon coatings from atomic force measurements***

Author(s): D. Liu, G. Benstetter, E. Lodermeier  
Source: Thin Solid Films, 436 (2003), 2 (July 31), 244-249

***Determination of the potentials of zero total charge of Pt(100) stepped surfaces in the [011] zone. Effect of the step density and anion adsorption***

Author(s): K. Domke, E. Herrero, A. Rodes, J.M. Feliu  
Source: Journal of Electroanalytical Chemistry, 552 (2003), (July 30), 115 - 128

***Electrochemical deposition of Ni-W alloys from ammonia-citrate electrolyte***

Author(s): M.D. Obradovic, R.M. Stevanovic, A.R. Despic  
Source: Journal of Electroanalytical Chemistry, 552 (2003), (July 30), 185 - 196

***XPS and AFM characterisation of selective monolayers for cationic detection: application to field effect chemical micro-sensors***

Author(s): S. Rochefeuille, R. Berjoan, P. Seta, C. Jimenez, J.-P. Desfours  
Source: Chemical Physics Letters, 376 (2003), 3-4 (July 24), 274-281

***On the correlation between morphology and electronic properties of copper phthalocyanine (CuPc) thin films***

Author(s): L. Grzadziel, J. Zak, J. Szuber  
Source: Thin Solid Films, 436 (2003), 1 (July 22), 70-75

***Molecular resolution images of the surfaces of natural zeolites by atomic force microscopy***

Author(s): M. Voltolini, G. Artioli, M. Moret  
Source: Microporous and Mesoporous Materials, 61 (2003), 1-3 (July 18), 79-84

***Adlayers of methyl-substituted benzene derivatives formed on Rh(111) in HF solution***

Author(s): K. Suto, J. Inukai, K. Itaya  
Source: Journal of Electroanalytical Chemistry, 550-551 (2003), (July 17), 105 - 112

***Selective observation of hydroxy and carboxylate moieties by scanning tunneling microscopy using chemically modified tips with differing extents of hydrogen bond acidity or basicity***

Author(s): T. Nishino, T. Ito, Y. Umezawa  
Source: Journal of Electroanalytical Chemistry, 550-551 (2003), (July 17), 125 - 129

***Isomeric effect on the oxidative formation of bilayers of benzenedimethanethiol on Au(111)***

Author(s): S. Rifai, M. Morin  
Source: Journal of Electroanalytical Chemistry, 550-551 (2003), (July 17), 277 - 289

***Formation of nanostructured eutectic network in  $\alpha$ -Al<sub>2</sub>O<sub>3</sub> reinforced Al-Cu alloy matrix composite***

Author(s): P. Yu, C.-J. Deng, N.-G. Ma, M.-Y. Yau, D.H.L. Ng  
Source: Acta Materialia, 51 (2003), 12 (July 16), 3445-3454

***In situ TM-AFM investigations of the influence of zinc and tin as alloy constituents of copper to the early stages of corrosion***

Author(s): C. Kleber, M. Schreiner  
Source: Applied Surface Science, 217 (2003), 1-4 (July 15), 294-301

***The two-dimensional self-assembled n-alkoxy-substituted stilbenoid compounds and triphenylenes studied by scanning tunneling microscopy***

Author(s): S. Xu, Q. Zeng, J. Lu, C. Wang, L. Wan, C.-L. Bai  
Source: Surface Science, 538 (2003), 1-2 (July 10), L451-L459

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Author(s): H.N.J. Fernando, J. Canning, L. Wosinski, B. Jaskorzynska, M. Dainese  
Source: Journal of Optics A: Pure and Applied Optics, 5 (2003), 4 (July 01), 335-340

***Gold nanoparticle/PPI-dendrimer based chemiresistors - Vapor-sensing properties as a function of the dendrimer size***

Author(s): N. Krasteva, B. Guse, I. Besnard, A. Yasuda, T. Vossmeier  
Source: Sensors and Actuators B: Chemical, 92 (2003), 1-2 (July 01), 137-143

***Nanopipes and their relationship to the growth mode in thick HVPE-GaN layers***

Author(s): E. Valcheva, T. Paskova, B. Monemar  
Source: Journal of Crystal Growth, 255 (2003), 1-2 (July), 19-26

***Effects of two-stage deposition on the structure and properties of heteroepitaxial BaTiO<sub>3</sub> thin films***

Author(s): D.J. Towner, J. Ni, T.J. Marks, B.W. Wessels  
Source: Journal of Crystal Growth, 255 (2003), 1-2 (July), 107-113

***Optimal target-substrate distance in the growth of oxides thin films by pulsed laser deposition***

Author(s): R. Castro-Rodriguez, S. Palomares-Sanchez, F. Leccabue, E. Arisi, B.E. Watts  
Source: Materials Letters, 57 (2003), 22-23 (July), 3320-3324

***The effects of air gap length on the internal and external morphology of hollow fiber membranes***

Author(s): M. Khayet  
Source: Chemical Engineering Science, 58 (2003), 14 (July), 3091-3104

***"Magic size" effect in the packing of n-alkanes on Au(111): evidence of lowered sliding force for molecules with specific length***

Author(s): A. Marchenko, J. Cousty  
Source: Wear, 254 (2003), 10 (July), 941-944

***An experimental study on the adhesion at a nano-contact***

Author(s): E.-S. Yoon, S.H. Yang, H.-G. Han, H. Kong  
Source: Wear, 254 (2003), 10 (July), 974-980

***High load AFM friction and wear experiments on V<sub>2</sub>O<sub>5</sub> thin films***

Author(s): W. Gulbinski, T. Suszko, D. Pailharey  
Source: Wear, 254 (2003), 10 (July), 988-993

***Effects of film thickness and contact load on nanotribological properties of sputtered amorphous carbon thin films***

Author(s): X.-G. Ma, K. Komvopoulos, D. Wan, D.B. Bogy, Y.-S. Kim  
Source: Wear, 254 (2003), 10 (July), 1010-1018

***Theoretical and experimental study on the photoluminescence in BaTiO<sub>3</sub> amorphous thin films prepared by the chemical route***

Author(s): F.M. Pontes, C.D. Pinheiro, E. Longo, E.R. Leite, S.R. de Lazaro, R. Magnani, P.S. Pizani, T.M. Boschi, F. Lanciotti  
Source: Journal of Luminescence, 104 (2003), 3 (July), 175-185

***Effects of reactor pressure on GaN nucleation layers and subsequent GaN epilayers grown on sapphire substrate***

Author(s): J. Chen, S.M. Zhang, B.S. Zhang, J.J. Zhu, G. Feng, X.M. Shen, Y.T. Wang, H. Yang, W.C. Zheng  
Source: Journal of Crystal Growth, 254 (2003), 3-4 (July), 348-352

***Controlled domain wall motion in micron-scale permalloy square rings***

Author(s): A. Imre, G. Csaba, V. Metlushko, G.H. Bernstein, W. Porod  
Source: Physica E: Low-dimensional Systems and Nanostructures, 19 (2003), 1-2 (July), 240-245

***AFM observation of OMVPE-grown ErP on InP substrates using a new organometal tris(ethylcyclopentadienyl)erbium (Er(EtCp)<sub>3</sub>)***

Author(s): T. Akane, S. Jinno, Y. Yang, T. Kuno, T. Hirata, Y. Isogai, N. Watanabe, Y. Fujiwara, A. Nakamura, Y. Takeda  
Source: Applied Surface Science, 216 (2003), 1-4 (June 30), 537-541

***Study of epitaxial SrTiO<sub>3</sub> (STO) thin films grown on Si(001)-2 x 1 substrates by molecular beam epitaxy***

Author(s): M.N.K. Bhuiyan, A. Matsuda, T. Yasumura, T. Tambo, C. Tatsuyama  
Source: Applied Surface Science, 216 (2003), 1-4 (June 30), 590-595

***The formation and growth mechanisms of silica thin film and spherical particles through the Stober process***

Author(s): H. Okudera, A. Hozumi  
Source: Thin Solid Films, 434 (2003), 1-2 (June 23), 62-68

***The influence of deposition conditions on structure and morphology of aluminum nitride films deposited by radio frequency reactive sputtering***

Author(s): H. Cheng, Y. Sun, P. Hing  
Source: Thin Solid Films, 434 (2003), 1-2 (June 23), 112-120

***Surface-bound nanoparticles for initiating metal deposition***

Author(s): L. Xu, J. Liao, L. Huang, D. Ou, Z. Guo, H. Zhang, C. Ge, N. Gu, J. Liu  
Source: Thin Solid Films, 434 (2003), 1-2 (June 23), 121-125

***Fabrication, characterization and electrochemical behaviors of the orientated film of a C<sub>60</sub> derivative***

Author(s): S.-Z. Kang, S.-L. Xu, H.-M. Zhang, L.-B. Gan, C. Wang, L.-J. Wan, C.-L. Bai  
Source: Surface Science, 536 (2003), 1-3 (June 20), L408-L414

***The adsorption of aromatic acids onto the graphite basal surface***

Author(s): D.S. Martin  
Source: Surface Science, 536 (2003), 1-3 (June 20), 15-23

***Growth dynamics of quaterthiophene thin films***

Author(s): M. Campione, A. Borghesi, M. Moret, A. Sassella  
Source: Journal of Materials Chemistry, 13 (2003), 7 (June 20), 1669-1675

***Metalorganic chemical vapor deposition of SrRuO<sub>3</sub> thin film and its characterization***

Author(s): Hung-Chih Lee, Dah-Shyang Tsai  
Source: Journal of Materials Science (full set), 38 (2003), 12 (June 15), 2633-2638

***Effects of N ion energy on titanium nitride films deposited by ion assisted filtered cathodic vacuum arc***

Author(s): G.Q. Yu, B.K. Tay, S.P. Lau, K. Prasad, L.K. Pan, J.W. Chai, D. Lai  
Source: Chemical Physics Letters, 374 (2003), 3-4 (June 11), 264-270

***High enhancement factor gold films for surface enhanced Raman spectroscopy***

Author(s): R. Gupta, W.A. Weimer  
Source: Chemical Physics Letters, 374 (2003), 3-4 (June 11), 302-306

***Structural changes of model Cu/ZnO catalysts during exposure to methanol reforming conditions***

Author(s): F. Raimondi, B. Schnyder, R. Kotz, R. Schelldorfer, T. Jung, J. Wambach, A. Wokaun  
Source: Surface Science, 532-535 (2003), (June 10), 383-389

***Thermal oxidation of As and Ge implanted Si(100)***

Author(s): S. Colonna, A. Terrasi, S. Scalese, F. Iacona, V. Raineri, F. La Via, S. Mobilio  
Source: Surface Science, 532-535 (2003), (June 10), 746-753

***Effect of photo-irradiation and external electric field on structural change of metal nanodots in solution***

Author(s): K. Murakoshi, H. Tanaka, Y. Sawai, Y. Nakato  
Source: Surface Science, 532-535 (2003), (June 10), 1109-1115

***Electrochromic coatings for smart windows***

Author(s): H.N. Cui, M.F. Costa, V. Teixeira, I. Porqueras, E. Bertran  
Source: Surface Science, 532-535 (2003), (June 10), 1127-1131

***Enhancements in conductivity and Raman spectroscopy of polypyrrole electropolymerized on electrochemically roughened Au substrates***

Author(s): Y.-C. Liu, K.-H. Yang, C.-C. Wang  
Source: Journal of Electroanalytical Chemistry, 549 (2003), (June 05), 151 - 155

***Oriented organic semiconductor thin films***

Author(s): A. Andreev, R. Resel, D.-M. Smilgies, H. Hoppe, G. Matt, H. Sitter, N.S. Sariciftci, D. Meissner, H. Plank, O. Zrzavecka  
Source: Synthetic Metals, 138 (2003), 1-2 (June 02), 59-63

***Phase transition of thiophene molecules on Au(111) in solution***

Author(s): G.-J. Su, H.-M. Zhang, L.-J. Wan, C.-L. Bai  
Source: Surface Science, 531 (2003), 3 (June 01), L363-L368

***Adlayer structure of 4-ethyl naphthalene-1-sulfonate on Cu(111)***

Author(s): X.-L. Yin, L.-J. Wan, Z.-Y. Yang, J.-Y. Yu, C.-L. Bai  
Source: Surface Science, 531 (2003), 3 (June 01), 226-230

***Estimation of heterogeneous surface structure of submicron-sized, composite polymer particles consisting of hydrophobic and hydrophilic components by atomic force microscopy\****

Author(s): Masayoshi Okubo, Toyoko Suzuki, Yasuhiro Fukuhara  
Source: Colloid and Polymer Science, 281 (2003), 6 (June), 569-574

***Synthesis, Ferroelectric and Optical Properties of (Pb,Ca)TiO<sub>3</sub> Thin Films by Soft Solution Processing***

Author(s): F.M. Pontes, D.S.L. Pontes, E.R. Leite, E. Longo, E.M.S. Santos, S. Mergulhao, J.A. Varela  
Source: Journal of Sol-Gel Science and Technology, 27 (2003), 2 (June), 137-147

***DNA Assembly on 2-Dimensional Array of Colloidal Gold***

Author(s): Cunwang Ge, Jianhui Liao, Yihong Wang, Kunji Chen, Ning Gu  
Source: Biomedical Microdevices, 5 (2003), 2 (June), 157-162

***AFM studies of swift heavy ion-irradiated surface modification in Si and GaAs***

Author(s): P.C. Srivastava, V. Ganesan, O.P. Sinha  
Source: Radiation Measurements, 36 (2003), 1-6 (June), 671-674

***Surface Structure and Transport Properties of YBa<sub>2</sub>Cu<sub>3</sub>O<sub>7-d</sub> Using La<sub>2/3</sub>Ca<sub>1/3</sub>MnO<sub>3</sub> as Buffer***

Author(s): W.S. Tan, L. Yang, H. Sha, X.S. Wu, J. Gao, S.S. Jiang  
Source: Surface Review and Letters, 10 (2003), 2-3 (June), 317-323

***Spontaneous Formation of Air Nanobubbles on Hydrocarbons Deposited on the Au(111)/Water Interface***

Author(s): I. Otsuka, M. Yaoita, M. Higano, S. Nagashima  
Source: Surface Review and Letters, 10 (2003), 2-3 (June), 337-343

***Microstructural Study of a Passivation Layer on GaAs: An Application of X-Ray Reflectivity Under Grazing Angles Using a Synchrotron Source***

Author(s): K.E. Crompton, T.R. Finlayson, C. Kirchner, M. Seitz, U. Klemradt  
Source: Surface Review and Letters, 10 (2003), 2-3 (June), 373-379

***Helical-type surface defects in GaN thin films epitaxially grown on GaN templates at reduced temperatures***

Author(s): P.Q. Miraglia, E.A. Preble, A.M. Roskowski, S. Einfeldt, R.F. Davis  
Source: Journal of Crystal Growth, 253 (2003), 1-4 (June), 16-25

***Surface morphology and strain of GaN layers grown using 6H-SiC(0001) substrates with different buffer layers***

Author(s): S. Einfeldt, Z.J. Reitmeier, R.F. Davis  
Source: Journal of Crystal Growth, 253 (2003), 1-4 (June), 129-141

***Studies on inclined nuclei as a cause of crystallinity deterioration in epitaxial CeO<sub>2</sub>(110) layers on Si(100) substrates***

Author(s): T. Inoue, S. Shida, N. Sakamoto, A. Horikawa, M. Ohashi  
Source: Journal of Crystal Growth, 253 (2003), 1-4 (June), 366-373

***Growth and characterization of cesium halides with cubic morphologies***

Author(s): J. Arsic, I.C. Reynhout, W.J.P. van Enkevort, E. Vlieg  
Source: Journal of Crystal Growth, 253 (2003), 1-4 (June), 472-480

***Atomic force microscope study of the interface of twinned martensite in copper-aluminium-nickel***

Author(s): D.Z. Liu, D. Dunne  
Source: Scripta Materialia, 48 (2003), 12 (June), 1611-1616

***GaN films annealed under high pressure***

Author(s): F. Kelly, R. Chodelka, R.K. Singh, S.J. Pearton, M. Overberg, J. Fitz-Gerald  
Source: Solid-State Electronics, 47 (2003), 6 (June), 1081-1087

***Nanostructuring of anti-adhesive layers by hot embossing lithography***

Author(s): S. Park, C. Padeste, H. Schiff, J. Gobrecht  
Source: Microelectronic Engineering, 67-68 (2003), (June), 252-258

***Dot formation with 170-nm dimensions using a thermal lithography technique***

Author(s): M. Kuwahara, J.H. Kim, J. Tominaga  
Source: Microelectronic Engineering, 67-68 (2003), (June), 651-656

***On the effects of surface coatings on the high-temperature oxidation of nickel***

Author(s): R. Haugsrud  
Source: Corrosion Science, 45 (2003), 6 (June), 1289-1311

***A two steps CVD process for the growth of silicon nano-crystals***

Author(s): F. Mazen, T. Baron, A.M. Papon, R. Truche, J.M. Hartmann  
Source: Applied Surface Science, 214 (2003), 1-4 (May 31), 359-363

***Formation and STM tip-induced reduction of ultra thin SnO film on Au(111)***

Author(s): J.W. Yan, Z.X. Xie, Z.X. Cao, C.J. Zhou, J.Y. Kang, B.W. Mao  
Source: Chemical Physics Letters, 373 (2003), 5-6 (May 28), 575-579

***An in situ STM study on Sb electrodeposition on Au(1 1 1): irreversible adsorption and reduction, underpotential deposition and mutual influences***

Author(s): Q. Wu, W.-H. Shang, J.-W. Yan, B.-W. Mao  
Source: Journal of Molecular Catalysis A: Chemical, 199 (2003), 1-2 (May 16), 49-56

***Connections between surface complexation and geometric models of mineral dissolution investigated for rhodochrosite***

Author(s): O.W. Duckworth, S.T. Martin  
Source: Geochimica et Cosmochimica Acta, 67 (2003), 10 (May 15), 1787-1801

***The dual role of self-assembled monolayers of a tetraazamacrocyclic copper(II) complex in ascorbate oxidation catalysis***

Author(s): K. Stolarczyk, R. Bilewicz, L. Siegfried, T. Kaden  
Source: Inorganica Chimica Acta, 348 (2003), (May 15), 129 - 134

***Structural, morphological and electrochromic properties of Nb<sub>2</sub>O<sub>5</sub> films deposited by reactive sputtering***

Author(s): Y. Huang, Y. Zhang, X. Hu  
Source: Solar Energy Materials & Solar Cells, 77 (2003), 2 (May 15), 155-162

***Effect of end-substitution of hexyl chains on the growth and electrical properties of quaterthiophene thin films***

Author(s): J. Ackermann, C. Videlot, P. Raynal, A. El Kassmi, P. Dumas  
Source: Applied Surface Science, 212-213 (2003), (May 15), 26-32

***Morphology changes of Si(0 0 1) surfaces during wet chemical halogenation***

Author(s): L. Pedemonte, G. Bracco, A. Relini, R. Rolandi, D. Narducci  
Source: Applied Surface Science, 212-213 (2003), (May 15), 595-600

***ZnO nanoparticles prepared by thermal decomposition of b-cyclodextrin coated zinc acetate***

Author(s): Y. Yang, X. Li, J. Chen, H. Chen, X. Bao  
Source: Chemical Physics Letters, 373 (2003), 1-2 (May 13), 22-27

***The electrical potential difference across cracks in PZT measured by Kelvin Probe Microscopy and the implications for fracture***

Author(s): G.A. Schneider, F. Felten, R.M. McMeeking  
Source: Acta Materialia, 51 (2003), 8 (May 07), 2235-2241

***Structural and electrical studies on sol-gel derived spun TiO<sub>2</sub> thin films***

Author(s): A.K. Hassan, N.B. Chaure, A.K. Ray, A.V. Nabok, S. Habesch  
Source: Journal of Physics D: Applied Physics, 36 (2003), 9 (May 07), 1120-1125

***Preparation of chitosan/glucose oxidase nanolayered films for electrode modification by the technique of layer-by-layer self-assembly***

Author(s): Xin Hua Xu, Bo Han, Ying Song Fu, Jun Han, Hai Bin Shi, Baoyan Wu, Songyan Han, Qiang Chen

Source: Journal of Materials Science Letters, 22 (2003), 9 (May 01), 695-697

***Understanding tapping-mode atomic force microscopy data on the surface of soft block copolymers***

Author(s): Y. Wang, R. Song, Y. Li, J. Shen

Source: Surface Science, 530 (2003), 3 (May 01), 136-148

***Electrical characterization of InGaN quantum well p-n heterostructures***

Author(s): J.C. Gonzalez, M.I.N. da Silva, K.L. Bunker, A.D. Batchelor, P.E. Russell

Source: Microelectronics Journal, 34 (2003), 5-8 (May), 455-457

***Cross-sectional Scanning Probe Microscopy of GaN-based p-n heterostructures***

Author(s): M.I.N. da Silva, J.C. Gonzalez, P.E. Russell

Source: Microelectronics Journal, 34 (2003), 5-8 (May), 571-573

***Co-dot-array formation along scratches on Si(111) surface by electroless deposition***

Author(s): C. Kim, Y. Oikawa, J. Shin, H. Ozaki

Source: Microelectronics Journal, 34 (2003), 5-8 (May), 607-609

***Low growth rate InAs/GaAs quantum dots for room-temperature luminescence over 1.3 nm***

Author(s): M.J. da Silva, S. Martini, T.E. Lamas, A.A. Quivy, E.C.F. da Silva, J.R. Leite

Source: Microelectronics Journal, 34 (2003), 5-8 (May), 631-633

***Morphological and optical properties of p-type GaAs(001) layers doped with silicon***

Author(s): T.E. Lamas, S. Martini, M.J. da Silva, A.A. Quivy, J.R. Leite

Source: Microelectronics Journal, 34 (2003), 5-8 (May), 701-703

***Abnormal temperature dependence of photoluminescence from self-assembled InAs quantum dots covered by an InAlAs/InGaAs combination layer***

Author(s): Z.Y. Zhang, C.L. Yang, Y.Q. Wei, X.L. Ye, P. Jin, C.M. Li, X.Q. Meng, B. Xu, Z.G. Wang

Source: Solid State Communications, 126 (2003), 7 (May), 391-394

***Optical and surface properties of SiO<sub>2</sub> by flame hydrolysis deposition for silica waveguide***

Author(s): L. Zhang, W. Xie, Y. Wu, H. Xing, A. Li, W. Zheng, Y. Zhang

Source: Optical Materials, 22 (2003), 3 (May), 283-287

***Growth of BaFe<sub>12</sub>O<sub>19</sub> thin films formed by reactive diffusion***

Author(s): V. Pankov, A. Bartholdson, O. Stukalov, S. Smolenchuk, O. Babushkin, V. Gremenok

Source: Journal of Crystal Growth, 252 (2003), 1-3 (May), 382-390

***Cratering by MeV-GeV ions as a function of angle of incidence***

Author(s): R.M. Papaleo, R. Leal, C. Trautmann, E.M. Bringa

Source: Nuclear Instruments and Methods in Physics Research Section B: Beam Interactions with Materials and Atoms, 206 (2003), (May), 7-12

***Formation of micrometer sized crater shaped pits in silicon by low-energy <sup>22</sup>Ne<sup>+</sup> implantation and electron beam annealing***

Author(s): A. Markwitz, V.J. Kennedy, H. Baumann

Source: Nuclear Instruments and Methods in Physics Research Section B: Beam Interactions with Materials and Atoms, 206 (2003), (May), 179-183

***Processing of nano-holes and pores on SiO<sub>2</sub> thin films by MeV heavy ions***

Author(s): C. Milanez Silva, P. Varisco, A. Moehlecke, P.P. Fichtner, R.M. Papaleo, J. Eriksson

Source: Nuclear Instruments and Methods in Physics Research Section B: Beam Interactions with Materials and Atoms, 206 (2003), (May), 486-489

***The effect of thickness on the dielectric properties of highly (111) oriented Pb(Zr<sub>0.53</sub>Ti<sub>0.47</sub>)O<sub>3</sub> thin films prepared by a simple sol-gel route***

Author(s): X.G. Tang, L.L. Jiang, A.L. Ding

Source: Microelectronic Engineering, 65 (2003), 4 (May), 387-393

***Adsorption of Heavy Metals on Mixed Fe-Al Oxides in the Absence or Presence of Organic Ligands***

Author(s): Antonio Violante, Mariarosaria Ricciardella, Massimo Pigna

Source: Water, Air, and Soil Pollution, 145 (2003), 1 (May), 289-306

***Effect of annealing in processing of strontium titanate thin films by ALD***

Author(s): A. Kosola, M. Putkonen, L.-S. Johansson, L. Niinisto  
Source: Applied Surface Science, 211 (2003), 1-4 (April 30), 102-112

***Pendant thiol groups-attached Pd(II) for initiating metal deposition***

Author(s): L. Xu, J. Liao, L. Huang, N. Gu, H. Zhang, J. Liu  
Source: Applied Surface Science, 211 (2003), 1-4 (April 30), 184-188

***Photoluminescence and morphological studies of porous silicon***

Author(s): J. Lee, K. Chakrabarty, J. Yi  
Source: Applied Surface Science, 211 (2003), 1-4 (April 30), 373-378

***Effect of ageing on wettability of quartz surfaces modified by Ar implantation***

Author(s): G.G. Ross, M. Chasse, M. Bolduc  
Source: Journal of Physics D: Applied Physics, 36 (2003), 8 (April 21), 1001-1008

***A combined experimental and theoretical study of the generation of palladium clusters on Au(111) with a scanning tunnelling microscope***

Author(s): M.G. Del Popolo, E.P.M. Leiva, H. Kleine, J. Meier, U. Stimming, M. Mariscal, W. Schmickler  
Source: Electrochimica Acta, 48 (2003), 9 (April 20), 1287 - 1294

***Impact of compatible solutes on the mechanical properties of fibronectin: a single molecule analysis***

Author(s): York Oberdorfer, Sebastian Schrot, Harald Fuchs, Erwin Galinski, Andreas Janshoff  
Source: PCCP: Physical Chemistry Chemical Physics, 5 (2003), 9 (April 16), 1876-1881

***Direct fabrication of monodispersed ultrasmall CdS nanocrystals from self-assembled monolayers on Au(111) substrate***

Author(s): Peng Jiang, Zhong-Fan Liu, Sheng-Min Cai  
Source: Journal of Materials Science Letters, 22 (2003), 8 (April 15), 577-579

***Formation of tubular silicon carbide from a carbon-silica material by using a reactive replica technique: infrared characterisation***

Author(s): C. Vix-Guterl, I. Alix, P. Gibot, P. Ehrburger  
Source: Applied Surface Science, 210 (2003), 3-4 (April 15), 329-337

***Temperature effect on the Cu<sub>2</sub>O oxide morphology created by oxidation of Cu(0 0 1) as investigated by in situ UHV TEM***

Author(s): G. Zhou, J.C. Yang  
Source: Applied Surface Science, 210 (2003), 3-4 (April 15), 165-170

***Chlorite dissolution in the acid pH-range: a combined microscopic and macroscopic approach***

Author(s): F. Brandt, D. Bosbach, E. Krawczyk-Barsch, T. Arnold, G. Bernhard  
Source: Geochimica et Cosmochimica Acta, 67 (2003), 8 (April 15), 1451-1461

***Electrochemical lithography: fabrication of nanoscale Si tips by porous anodization of Al/Si wafer***

Author(s): L. Pu, Y. Shi, J.M. Zhu, X.M. Bao, R. Zhang, Y.D. Zheng  
Source: Chemical Communications, (2003), 8 (April 03), 942-943

***Analysis of thin film surface barrier solar cells with a microrelief interface***

Author(s): N.L. Dmitruk, O.Y. Borkovskaya, I.N. Dmitruk, I.B. Mamontova  
Source: Solar Energy Materials & Solar Cells, 76 (2003), 4 (April 01), 625-635

***Etching characteristics of chromium thin films by an electron beam induced surface reaction***

Author(s): Jianhua Wang, D.P. Griffis, R. Garcia, P.E. Russell  
Source: Semiconductor Science and Technology, 18 (2003), 4 (April 01), 199-205

***Thin films of the double perovskite Sr<sub>2</sub>FeMoO<sub>6</sub> deposited by pulsed laser deposition***

Author(s): R.P. Borges, S. Lhostis, M.A. Bari, J.J. Versluijs, J.G. Lunney, J.M.D. Coey, M. Besse, J.-P. Contour  
Source: Thin Solid Films, 429 (2003), 1-2 (April 01), 5-12

***An atomic force microscopy study of ozone etching of a polystyrene/polyisoprene block copolymer***

Author(s): S. Collins, I.W. Hamley, T. Mykhaylyk

Source: *Polymer*, 44 (2003), 8 (April), 2403-2410

***Improvement of cubic GaN film crystal quality by use of an AlN/GaN ordered alloy on GaAs (100) by plasma assisted molecular beam epitaxy***

Author(s): R. Kimura, A. Shigemori, J. Shike, K. Ishida, K. Takahashi

Source: *Journal of Crystal Growth*, 251 (2003), 1-4 (April), 455-459

***Properties of metamorphic materials and device structures on GaAs substrates***

Author(s): W.E. Hoke, T.D. Kennedy, A. Torabi, C.S. Whelan, P.F. Marsh, R.E. Leoni, S.M. Lardizabal, Y. Zhang, J.H. Jang, I. Adesida, C. Xu, K.C. Hsieh

Source: *Journal of Crystal Growth*, 251 (2003), 1-4 (April), 804-810

***Mesoscopic island structure at GaAs/(AlGa)As interfaces grown by MBE***

Author(s): L. Gottwaldt, K. Pierz, F.J. Ahlers, E.O. Gobel, S. Nau, T. Torunski, W. Stolz

Source: *Journal of Crystal Growth*, 251 (2003), 1-4 (April), 85-89

***Optical response at 1.3  $\mu\text{m}$  and 1.5  $\mu\text{m}$  with InAs quantum dots embedded in a pure GaAs matrix***

Author(s): M.J. da Silva, A.A. Quivy, S. Martini, T.E. Lamas, E.C.F. da Silva, J.R. Leite

Source: *Journal of Crystal Growth*, 251 (2003), 1-4 (April), 181-185

***Influence of initial GaAs and AlAs cap layers on InAs quantum dots grown by molecular beam epitaxy***

Author(s): F. Ferdos, S. Wang, Y. Wei, M. Sadeghi, Q. Zhao, A. Larsson

Source: *Journal of Crystal Growth*, 251 (2003), 1-4 (April), 145-149

***Self-assembled nanoholes and lateral QD bi-molecules by molecular beam epitaxy and atomically precise in situ etching***

Author(s): S. Kiravittaya, R. Songmuang, N.Y. Jin-Phillipp, S. Panyakeow, O.G. Schmidt

Source: *Journal of Crystal Growth*, 251 (2003), 1-4 (April), 258-263

***Photoluminescence investigation of low-temperature capped self-assembled InAs/GaAs quantum dots***

Author(s): R. Songmuang, S. Kiravittaya, M. Sawadsaringkarn, S. Panyakeow, O.G. Schmidt

Source: *Journal of Crystal Growth*, 251 (2003), 1-4 (April), 166-171

***Thermal and morphological properties of main chain liquid crystalline polymers***

Author(s): B.B. Sauer, W.G. Kampert, R.S. McLean

Source: *Polymer*, 44 (2003), 9 (April), 2721-2738

***Polyamide-12 layered silicate nanocomposites by melt blending***

Author(s): T. McNally, W. Raymond Murphy, C.Y. Lew, R.J. Turner, G.P. Brennan

Source: *Polymer*, 44 (2003), 9 (April), 2761-2772

***Controlling the nanoscale morphology of organic films deposited by polyatomic ions***

Author(s): L. Hanley, Y. Choi, E.R. Fuoco, F. Ahu Akin, M.B.J. Wijesundara, M. Li, A. Tikhonov, M. Schlossman

Source: *Nuclear Instruments and Methods in Physics Research Section B: Beam Interactions with Materials and Atoms*, 203 (2003), (April), 116-123

***Study of PMMA recoveries on micrometric patterns replicated by nano-imprint lithography***

Author(s): C. Martin, L. Ressler, J.P. Peyrade

Source: *Physica E: Low-dimensional Systems and Nanostructures*, 17 (2003), (April), 523-525

***Tribological studies of Zr-implanted PVD TiN coatings deposited on stainless steel substrates***

Author(s): K.P. Purushotham, L.P. Ward, N. Brack, P.J. Pigram, P. Evans, H. Noorman, R.R. Manory

Source: *Wear*, 254 (2003), 7-8 (April), 589-596

***Multiple surface properties of worn RGP lenses and adhesion of Pseudomonas aeruginosa***

Author(s): G.M. Bruinsma, M. Rustema-Abbing, J. de Vries, H.J. Busscher, M.L. van der Linden, J.M.M.

Hooymans, H.C. van der Mei

Source: *Biomaterials*, 24 (2003), 9 (April), 1663-1670

***Wetting and Phase Separation in Polymer Blend Films: Identification of Four Thickness Regimes with Distinct Morphological Pathways***

Author(s): Howard Wang, Russell J. Composto

Source: *Interface Science*, 11 (2003), 2 (April), 237-248

***Microstructure of Silica Particle Monolayer Films Formed by Capillary Immersion Force***

Author(s): Toru Okubo, Shigeki Chujo, Shinya Maenosono, Yukio Yamaguchi

Source: Journal of Nanoparticle Research, 5 (2003), 1 (April), 111-117

***Wetting and Scanning Force Microscopy on Rough Polymer Surfaces: Wenzel's Roughness Factor and the Thermodynamic Contact Angle***

Author(s): H. Kamusewitz, W. Possart

Source: Applied Physics A: Materials Science & Processing, 76 (2003), 6 (April), 899-902

***Pseudo-Non-Contact Mode: Why It Can Give True Atomic Resolution***

Author(s): I.Y. Sokolov

Source: Applied Surface Science, 210 (2003), 1-2 (March 31), 37-42

***Frequency Shift Feedback Imaging in Liquid for Biological Molecules***

Author(s): H. Sekiguchi, T. Okajima, H. Arakawa, S. Maeda, A. Takashima, A. Ikai

Source: Applied Surface Science, 210 (2003), 1-2 (March 31), 61-67

***Self-Oscillation Technique for AFM in Liquids***

Author(s): T. Okajima, H. Sekiguchi, H. Arakawa, A. Ikai

Source: Applied Surface Science, 210 (2003), 1-2 (March 31), 68-72

***Single Molecule Imaging of RNA Polymerase II using Atomic Force Microscopy***

Author(s): T. Rhodin, J. Fu, K. Umemura, M. Gad, S. Jarvis, M. Ishikawa

Source: Applied Surface Science, 210 (2003), 1-2 (March 31), 105-111

***Crystal-Face and Illumination Intensity Dependences of the Quantum Efficiency of Photoelectrochemical Etching, in Relation to Those of Water Photooxidation, at n-TiO<sub>2</sub> (Rutile) Semiconductor Electrodes***

Author(s): T. Kisumi, A. Tsujiko, K. Murakoshi, Y. Nakato

Source: Journal of Electroanalytical Chemistry, 545 (2003), (March 27), 99 - 107

***Improvements of the Lateral Resolution of the MFM Technique***

Author(s): M.R. Koblischka, U. Hartmann, T. Sulzbach

Source: Thin Solid Films, 428 (2003), 1-2 (March 20), 93-97

***Adsorption Processes in Layer-by-Layer Films of Poly(o-methoxyaniline): The Role of Aggregation***

Author(s): N.C. de Souza, J.R. Silva, C.A. Rodrigues, L.d.F. Costa, J.A. Giacometti, O.N. Oliveira

Source: Thin Solid Films, 428 (2003), 1-2 (March 20), 232-236

***Remote Hydrogen-Nitrogen Plasma Chemical Vapor Deposition from a Tetramethyldisilazane Source. Part I. Mechanism of the Process, Structure and Surface Morphology of Deposited Amorphous Hydrogenated Silicon Carbonitride Films***

Author(s): A.M. Wrobel, I. Blaszczyk, A. Walkiewicz-Pietrzykowska, A. Tracz, J.E. Klemberg-Sapieha, T. Aoki, Y. Hatanaka

Source: Journal of Materials Chemistry, 13 (2003), 4 (March 19), 731-737

***Morphological Study of PLD Grown Carbon Films***

Author(s): Z. Geretovszky, T. Haraszti, T. Szorenyi, F. Antoni, E. Fogarassy

Source: Applied Surface Science, 208-209 (2003), (March 15), 566-574

***Nanoscale Observation of Initial Stages of Cd-Electrodeposition on Au(111)***

Author(s): S. Maupai, Y. Zhang, P. Schmuki

Source: Surface Science, 527 (2003), 1-3 (March 10), L165-L170

***Chemical Force Microscopy: Applications in Surface Characterisation of Natural Hydroxyapatite***

Author(s): D.A. Smith, S.D. Connell, C. Robinson, J. Kirkham

Source: Analytica Chimica Acta, 479 (2003), 1 (March 05), 39-57

***Structural and Electrical Properties of c-axis Epitaxial and Polycrystalline Sr<sub>3</sub>Bi<sub>4</sub>Ti<sub>6</sub>O<sub>21</sub> Thin Films***

Author(s): S.T. Zhang, Y.F. Chen, H.P. Sun, X.Q. Pan, W.S. Tan, Z.G. Liu, N.B. Ming

Source: Journal of Physics: Condensed Matter, 15 (2003), 8 (March 05), 1223-1233

***Protective Carbon Layer for Chemical Corrosion of Stainless Steel***

Author(s): R.D. Mansano, M. Massi, A.P. Mousinho, L.S. Zambom, L.G. Neto  
Source: *Diamond and Related Materials*, 12 (2003), 3-7 (March), 749-752

***Effects of negative low self-bias on hydrogenated amorphous carbon films deposited by PECVD technique***

Author(s): N. Matre, T. Girardeau, S. Camelio, A. Barranco, D. Vouagner, E. Breelle  
Source: *Diamond and Related Materials*, 12 (2003), 3-7 (March), 988-992

***Micro-machine fabrication using diamond-like carbon films***

Author(s): A.P. Mousinho, R.D. Mansano, M. Massi, J.M. Jaramillo  
Source: *Diamond and Related Materials*, 12 (2003), 3-7 (March), 1041-1044

***A study on nano-nucleation and interface of diamond film prepared by hot filament assisted with radio frequency plasma***

Author(s): S. Liu, E. Xie, J. Sun, C. Ning, Y. Jiang  
Source: *Materials Letters*, 57 (2003), 11 (March), 1662-1669

***The structure of hematite ( $\alpha$ -Fe<sub>2</sub>O<sub>3</sub>) (001) surfaces in aqueous media: scanning tunneling microscopy and resonant tunneling calculations of coexisting O and Fe terminations***

Author(s): C.M. Eggleston, A.G. Stack, K.M. Rosso, S.R. Higgins, A.M. Bice, S.W. Boese, R.D. Pribyl, J.J. Nichols  
Source: *Geochimica et Cosmochimica Acta*, 67 (2003), 5 (March), 985-1000

***Microexplosions in tellurite glasses***

Author(s): S.K. Sundaram, C.B. Schaffer, E. Mazur  
Source: *Applied Physics A: Materials Science & Processing*, 76 (2003), 3 (March), 379-384

***Optical and mechanical properties of sol-gel silica-titania hard optical coatings derived from methyltrimethoxysilane and tetrapropylorthotitanate as precursors***

Author(s): W. Que, X. Hu  
Source: *Optical Materials*, 22 (2003), 1 (March), 31-37

***A Comparison of Corona-Treated and Flame-Treated Polypropylene Films***

Author(s): Mark Strobel, Viv Jones, Christopher S. Lyons, Michael Ulsh, Mark J. Kushner, Rajesh Dorai, Melvyn C. Branch  
Source: *Plasmas and Polymers*, 8 (2003), 1 (March), 61-95

***Influence of velocity in nanoscale friction processes***

Author(s): R. Prioli, A.M.F. Rivas, F.L. Freire Jr., A.O. Caride  
Source: *Applied Physics A: Materials Science & Processing*, 76 (2003), 4 (March), 565-569

***Ion-beam mixing in Fe/Si bilayers by singly and highly charged ions: evolution of phases, spike mechanism and possible effects of the ion-charge state***

Author(s): S. Dhar, P. Schaaf, N. Bibic, E. Hooker, M. Milosavljevic, K.P. Lieb  
Source: *Applied Physics A: Materials Science & Processing*, 76 (2003), 5 (March), 773-780

***Rutherford backscattering spectrometry analysis of TiO<sub>2</sub> thin films***

Author(s): F. Fernandez-Lima, E. Vigil, I. Zumeta, F.L. Freire, R. Prioli, E. Pedrero  
Source: *Materials Characterization*, 50 (2003), 2-3 (March), 155-160

***Cantilever's behavior in the AC mode of an AFM***

Author(s): V.B. Nunes, S.I. Zanette, A.O. Caride, R. Prioli, A.M.F. Rivas  
Source: *Materials Characterization*, 50 (2003), 2-3 (March), 173-177

***The influence of thermal treatment on the preparation of PMN and PMN-PT thin films***

Author(s): P.D. Spagnol, L.F. Valadares, J.A. Varela, M.A.Z. Bertochi  
Source: *Materials Characterization*, 50 (2003), 2-3 (March), 227-231

***Influence of thickness on crystallization and properties of LiNbO<sub>3</sub> thin films***

Author(s): A.Z. Simoes, A.H.M. Gonzalez, A. Ries, M.A. Zaghete, B.D. Stojanovic, J.A. Varela  
Source: *Materials Characterization*, 50 (2003), 2-3 (March), 239-244

***Modification of the micro- and nanotopography of several polymers by plasma treatments***

Author(s): M. Collaud Coen, R. Lehmann, P. Groening, L. Schlapbach  
Source: *Applied Surface Science*, 207 (2003), 1-4 (February 28), 276-286

***Growth of highly (001)-textured strontium barium niobate thin films on epitaxial LaNiO<sub>3</sub>/CeO<sub>2</sub>/YSZ/Si(100)***

Author(s): T.-W. Chiu, N. Wakiya, K. Shinozaki, N. Mizutani

Source: Thin Solid Films, 426 (2003), 1-2 (February 24), 62-67

***Impurity-induced resistivity of ferroelastic domain walls in doped lead phosphate***

Author(s): Melanie Bartels, Volker Hagen, Manfred Burianek, Mathias Getzlaff, Ulrich Bismayer, Roland Wiesendanger

Source: Journal of Physics: Condensed Matter, 15 (2003), 6 (February 19), 957-962

***Nanotribology of MoS<sub>x</sub> coatings investigated by oscillating lateral force microscopy***

Author(s): X. Zhang, J.-P. Celis

Source: Applied Surface Science, 206 (2003), 1-4 (February 15), 110-118

***Transparent titanium dioxide film with nanocrystalline structure by using a titanium naphthenate***

Author(s): K.S. Hwang, S.O. Lee, B.A. Kang, Y.H. Yun, Y.A. Shim, J.S. Oh, S.H. Yang

Source: Journal of Materials Science Letters, 22 (2003), 4 (February 15), 307-309

***Surface oxidation of monodisperse SnO<sub>x</sub> nanoparticles***

Author(s): R. Ramamoorthy, M.K. Kennedy, H. Nienhaus, A. Lorke, F.E. Kruis, H. Fissan

Source: Sensors and Actuators B: Chemical, 88 (2003), 3 (February 10), 281-285

***Surface step structure of Ag<sub>13</sub>OsO<sub>6</sub>, experimental evidence for Ag<sub>13</sub> cluster building blocks***

Author(s): Sascha Ahlert, Lars Diekhoner, Roman Sordan, Klaus Kern, Martin Jansen

Source: Chemical Communications, (2003), 4 (February 07), 462-463

***Chemical vapor deposition of tantalum carbide and carbonitride thin films from Me<sub>3</sub>CE=Ta(CH<sub>2</sub>CMe<sub>3</sub>)<sub>3</sub> (E = CH, N)***

Author(s): Yu-Hsu Chang, Jin-Bao Wu, Pei-Ju Chang, Hsin-Tien Chiu

Source: Journal of Materials Chemistry, 13 (2003), 2 (February 05), 365-369

***Spontaneous two-dimensional crystallization and photochemical reaction of a novel bolaamphiphilic naphthol ester in the spreading Langmuir film at the air/water interface and transferred Langmuir-Blodgett film***

Author(s): Q. Lu, M. Liu

Source: Thin Solid Films, 425 (2003), 1-2 (February 03), 248-254

***Thermal imidization of poly(pyromellitic dianhydride-4,4'-oxydianiline) precursors on fluoropolymers modified by surface graft-copolymerization with glycidyl methacrylate***

Author(s): G.H. Yang, Y. Zhang, K.S. Lee, E.T. Kang, K.G. Neoh

Source: Journal of Fluorine Chemistry, 119 (2003), 2 (February 01), 151-160

***In-situ determination of interface roughness in MOVPE-grown visible VCSELs by reflectance spectroscopy***

Author(s): K. Haberland, M. Zorn, A. Klein, A. Bhattacharya, M. Weyers, J.-T. Zettler, W. Richter

Source: Journal of Crystal Growth, 248 (2003), (February), 194-200

***A new method for low-powered laser reflectance and scattering monitoring of MOVPE growth with narrow optical access***

Author(s): C. Backstrom, S.J.C. Irvine, V. Barrioz

Source: Journal of Crystal Growth, 248 (2003), (February), 222-228

***Growth of spatially ordered InAs quantum dots on step-bunched vicinal GaAs (100) substrates***

Author(s): F. Poser, A. Bhattacharya, S. Weeke, W. Richter

Source: Journal of Crystal Growth, 248 (2003), (February), 317-321

***Photochromic behavior and luminescent properties of novel hybrid organic-inorganic film doped with Preyssler's heteropoly acid H<sub>12</sub>[EuP<sub>5</sub>W<sub>30</sub>O<sub>110</sub>] and polyvinylpyrrolidone***

Author(s): H.Y. Zhang, L. Xu, E.B. Wang, M. Jiang, A.G. Wu, Z. Li

Source: Materials Letters, 57 (2003), 8 (February), 1417-1422

***Ordered thin films of alkyloxy-substituted benzaldehydes on a graphite surface studied by scanning tunneling microscopy***

Author(s): S.L. Xu, Q.D. Zeng, P. Wu, Y.H. Qiao, C. Wang, C.L. Bai

Source: Applied Physics A: Materials Science & Processing, 76 (2003), 2 (February), 209-212

***Atomic force microscopy study of sapphire-YAG eutectic fiber***

Author(s): A. Yoshikawa, J.H. Lee, S.D. Durbin, T. Fukuda

Source: Applied Physics A: Materials Science & Processing, 76 (2003), 2 (February), 213-217

***MEASUREMENT OF CRITICAL EXPONENTS OF PLATINUM THIN FILMS***

Author(s): M.C. Salvadori, L.L. Melo, M. Cattani, O.R. Monteiro, I.G. Brown

Source: Surface Review and Letters, 10 (2003), 1 (February), 1-5

***Preparation and characterization of cobalt-based nanostructured materials***

Author(s): G. Carotenuto, L. Pasquini, E. Milella, M. Pentimalli, R. Lamanna, L. Nicolais

Source: The European Physical Journal B (EPJ B), 31 (2003), 4 (February), 545-551

***Determination of optical constants of Cd<sub>1-x</sub>Zn<sub>x</sub>Te thin films by spectroscopic ellipsometry***

Author(s): K. Prabakar, M. Sridharan, S.K. Narayandass, D. Mangalaraj, V. Gopal

Source: Thin Solid Films, 424 (2003), 1 (January 22), 66-69

***Growth and characteristics of the {111} NaCl crystal surface grown from solution***

Author(s): N. Radenovic, W. van Enckevort, P. Verwer, E. Vlieg

Source: Surface Science, 523 (2003), 3 (January 20), 307-315

***Frictional force microscopic observation of anisotropy at corrugated CaSO<sub>4</sub>(001) surface***

Author(s): Hitoshi Shindo, Yoshimichi Namai

Source: PCCP: Physical Chemistry Chemical Physics, 5 (2003), 3 (January 16), 616-619

***Formation of partially demixed two-dimensional solid solutions from binary mixtures of n-alkanes with very different lengths***

Author(s): Jacques Cousty, Laurent Pham Van

Source: PCCP: Physical Chemistry Chemical Physics, 5 (2003), 3 (January 16), 599-603

***Fabrication of titania-coated silica fibers and effect of substrate shape on coating growth rate***

Author(s): H. Okudera, Y. Yokogawa

Source: Thin Solid Films, 423 (2003), 2 (January 15), 119-124

***Preparation and characterization of sol-gel silica based neutral optical density coatings by the addition of graphite particles***

Author(s): J.L. Almaral-Sanchez, J. Alvarez-Quintana, C. Araujo-Andrade, J.A. Calderon-Guillen, H. Carrillo-Esquivel, E.A. Elizalde-Pena, N. Flores-Ramrez, F.A. Garcia-Pastor, O. Gomez-Guzman, L. Licea-Jimenez, D. Meneses-Rodriguez, A.E. Pena-Hernandez, S.A. Perez-Garca, J.C. Rubio-Avalos, A. Salazar-Flores, M. Talavera-Ortega, G. Vazquez-Garca, L.D. Vazquez-Santoyo, J. Gonzalez-Hernandez

Source: Thin Solid Films, 423 (2003), 2 (January 15), 196-200

***Oxygen-ion-induced ripple formation on silicon: evidence for phase separation and tentative model***

Author(s): Y. Homma, A. Takano, Y. Higashi

Source: Applied Surface Science, 203-204 (2003), (January 15), 35-38

***SIMS backside depth profiling of ultra shallow implants***

Author(s): K.L. Yeo, A.T.S. Wee, A. See, R. Liu, C.M. Ng

Source: Applied Surface Science, 203-204 (2003), (January 15), 335-338

***An investigation of the microstructure of a cryogenically mechanically alloyed polycarbonate-poly(aryl ether ether ketone) system***

Author(s): J.P. Martin, S.R. McCartney, R.G. Kander

Source: Journal of Materials Science (full set), 38 (2003), 2 (January 15), 195-200

***Anodic oxidation of gallium nitride***

Author(s): A. Pakes, P. Skeldon, G.E. Thompson, J.W. Fraser, S. Moisa, G.I. Sproule, M.J. Graham, S.B. Newcomb

Source: Journal of Materials Science (full set), 38 (2003), 2 (January 15), 343-349

***Examination of the electrified interfaces of Au(111) in 0.1 M HClO<sub>4</sub> containing organic iodide compounds with cyclic voltammetry and in situ scanning tunneling microscopy***

Author(s): C.-C. Chang, S.-L. Yau, J.-W. Tu, J.-S. Yang

Source: Surface Science, 523 (2003), 1-2 (January 10), 59-67

***Influence of volume and surface properties on phase contrast in tapping mode atomic force microscopy***

Author(s): A. Berquand, P.-E. Mazeran, J.-M. Laval

Source: Surface Science, 523 (2003), 1-2 (January 10), 125-130

***Adhesion and coalescence of ductile metal surfaces and nanoparticles***

Author(s): N.A. Alcantar, C. Park, J.-M. Pan, J.N. Israelachvili

Source: Acta Materialia, 51 (2003), 1 (January 08), 31-47

***Formation and observation of dimers of a metal complex with long alkyl side chains aligned on a graphite surface***

Author(s): Ichiro Sakata, Kazuo Miyamura

Source: Chemical Communications, (2003), 1 (January 07), 156-157

***Preparation and characterization of highly (111)-oriented (Pb,La)(Zr,Ti)O<sub>3</sub> thin films by sol-gel processing***

Author(s): X.G. Tang, A.L. Ding, Y. Ye, W.X. Chen

Source: Thin Solid Films, 423 (2003), 1 (January 01), 13-17

***Measurement of epitaxial misorientations and related effects in thin films of YBa<sub>2</sub>Cu<sub>3</sub>O<sub>7-d</sub> grown on nominally (001)MgO substrates by pulsed laser deposition***

Author(s): D.J. Norris, M. Aindow

Source: Thin Solid Films, 423 (2003), 1 (January 01), 33-40

***Characterization of highly hydrophobic coatings deposited onto pre-oxidized silicon from water dispersible organosilanes***

Author(s): A.M. Almanza-Workman, S. Raghavan, S. Petrovic, B. Gogoi, P. Deymier, D.J. Monk, R. Roop

Source: Thin Solid Films, 423 (2003), 1 (January 01), 77-87

***TlBa<sub>2</sub>Ca<sub>2</sub>Cu<sub>3</sub>O<sub>y</sub> superconducting films on MgO with different morphologies***

Author(s): P. Badica, A. Sundaresan, A. Crisan, J.C. Nie, M. Hirai, S. Fujiwara, H. Kito, H. Ihara

Source: Physica C: Superconductivity and its Applications, 383 (2003), 4 (January 01), 482-490

***Experimental observation of the scattering of light by planar metallic nanoparticles***

Author(s): Manuel R. Gonçalves, Othmar Marti

Source: New Journal of Physics, 5 (2003), 1 (January 01), 160

***Oxygen plasma modification of pitch-based isotropic carbon fibres***

Author(s): J.P. Boudou, J.I. Paredes, A. Cuesta, A. Martinez-Alonso, J.M.D. Tascon

Source: Carbon, 41 (2003), 1 (January), 41-56

***Patterning and optical properties rhodamine B-doped organic-inorganic silica films fabricated by sol-gel soft lithography***

Author(s): X.M. Han, J. Lin, R.B. Xing, J. Fu, S.B. Wang

Source: Materials Letters, 57 (2003), 7 (January), 1355-1360

***Polymorphic-polytypic transition induced in crystals by interaction of spirals and 2D growth mechanisms***

Author(s): D. Aquilano, Stephane Veesler, J.P. Astier, L. Pastero

Source: Journal of Crystal Growth, 247 (2003), 3-4 (January), 541-550

***Morphological characterization of the early process of soot formation by atomic force microscopy***

Author(s): A.C. Barone, A. D'Alessio, A. D'Anna

Source: Combustion and Flame, 132 (2003), 1-2 (January), 181-187

***Interface reactions in [Fe/B]<sub>n</sub> multilayers: a way to tune from crystalline/amorphous layer sequences to homogeneous amorphous Fe<sub>x</sub>B<sub>100-x</sub> films***

Author(s): R. Steiner, H.-G. Boyen, M. Krieger, A. Plettl, P. Widmayer, P. Ziemann, F. Banhart, R. Kilper, P. Oelhafen

Source: Applied Physics A: Materials Science & Processing, 76 (2003), 1 (January), 5-13

***Quantitative Depth Profiling of K-Doped Fullerene Films Using XPS and SIMS***

Author(s): Steffen Oswald, Pavel Janda, Lothar Dunsch

Source: Mikrochimica Acta, 141 (2003), 1-2 (January), 79-85

***Solid state structure-property behavior of semicrystalline poly(ether-block-amide) PEBA(X)R thermoplastic elastomers***

Author(s): J.P. Sheth, J. Xu, G.L. Wilkes  
Source: Polymer, 44 (2003), 3, 743-756

***Observation of intrinsic magnetic domains in C<sub>60</sub> polymer***

Author(s): K.-H. Han, D. Spemann, R. Hohne, A. Setzer, T. Makarova, P. Esquinazi, T. Butz  
Source: Carbon, 41 (2003), 4, 785-795

***The effect of argon on the electron field emission properties of a-C:N thin films***

Author(s): X.W. Liu, L.H. Chan, W.J. Hsieh, J.H. Lin, H.C. Shih  
Source: Carbon, 41 (2003), 6, 1143-1148

***Magnetism in photopolymerized fullerenes***

Author(s): T.L. Makarova, K.-H. Han, P. Esquinazi, R.R. da Silva, Y. Kopelevich, I.B. Zakharova, B. Sundqvist  
Source: Carbon, 41 (2003), 8, 1575-1584

***Well-dispersed single-walled carbon nanotube/polyaniline composite films***

Author(s): J.-E. Huang, X.-H. Li, J.-C. Xu, H.-L. Li  
Source: Carbon, 41 (2003), 14, 2731-2736

***Glass and metals on crystalline oxides***

Author(s): N. Ravishankar, S.R. Gilliss, C.B. Carter  
Source: Journal of the European Ceramic Society, 23 (2003), 15, 2777-2785

***Surface morphologies of MOCVD-grown GaN films on sapphire studied by scanning tunneling microscopy***

Author(s): J. Zhou, J.E. Reddic, M. Sinha, W.S. Ricker, J. Karlinsey, J.-W. Yang, M.A. Khan, D.A. Chen  
Source: Applied Surface Science, 202 (2002), 3-4 (December 30), 131-138

***Nano-dot formation using self-assembled 3-mercaptopropionic acid thin films prepared by facile atmospheric-vapor-adsorption method on Au(1 1 1)***

Author(s): T. Nakamura, R. Kimura, H. Sakai, M. Abe, H. Kondoh, T. Ohta, M. Matsumoto  
Source: Applied Surface Science, 202 (2002), 3-4 (December 30), 241-251

***Impedance analysis of CuBr films for ammonia gas detection***

Author(s): P. Lauque, J.-M. Laugier, C. Jacolin, M. Bendahan, C. Lemire, P. Knauth  
Source: Sensors and Actuators B: Chemical, 87 (2002), 3 (December 20), 431-436

***The structural transition of DNA-Tris(1,10-phenanthroline) cobalt(III) complexes in ethanol-water solution***

Author(s): Jianping Zheng, Zhuang Li, Aiguo Wu, Hualan Zhou, Hanying Bai, Yonghai Song  
Source: Biochemical and Biophysical Research Communications, 299 (2002), 5 (December 20), 910-915

***Structural studies on thin films of an unsubstituted oligo(para-phenylenevinylene)***

Author(s): S.C. Veenstra, P.F. van Hutten, A. Post, Y. Wang, G. Hadziioannou, H.T. Jonkman  
Source: Thin Solid Films, 422 (2002), 1-2 (December 20), 104-111

***Self-assembled monolayer of a Schiff base on Au(111) surface: electrochemistry and electrochemical STM study***

Author(s): D.-S. Kong, L.-J. Wan, M.-J. Han, G.-B. Pan, S.-B. Lei, C.-L. Bai, S.-H. Chen  
Source: Electrochimica Acta, 48 (2002), 4 (December 20), 303 - 309

***Formation and observation of dimers of a metal complex with long alkyl side chains aligned on a graphite surface***

Author(s): Ichiro Sakata, Kazuo Miyamura  
Source: Chemical Communications, (2002), 1 (December 19), 156-157

***Luminescent properties of rare-earth ion doped yttrium silicate thin film phosphors for a full-colour display***

Author(s): Q.Y. Zhang, K. Pita, S. Buddhudu, C.H. Kam  
Source: Journal of Physics D: Applied Physics, 35 (2002), 23 (December 07), 3085-3090

***Amorphous ITO thin films prepared by DC sputtering for electrochromic applications***

Author(s): V. Teixeira, H.N. Cui, L.J. Meng, E. Fortunato, R. Martins  
Source: Thin Solid Films, 420-421 (2002), (December 02), 70-75

***Localized deformation of multicomponent thin films***

Author(s): D.V. Shtansky, S.A. Kulinich, E.A. Levashov, A.N. Sheveiko, F.V. Kirihancev, J.J. Moore  
Source: Thin Solid Films, 420-421 (2002), (December 02), 330-337

***Flotation Chemistry of Boron Minerals***

Author(s): M.S. Celik, M. Hancer, J.D. Miller  
Source: Journal of Colloid and Interface Science, 256 (2002), 1 (December 01), 121-131

***Aggregation and Dispersion Characteristics of Calcium Oxalate Monohydrate: Effect of Urinary Species***

Author(s): Kimberly G. Christmas, Laurie B. Gower, Saeed R. Khan, Hassan El-Shall  
Source: Journal of Colloid and Interface Science, 256 (2002), 1 (December 01), 168-174

***Characterization of deformation processes in a Zn-22% Al alloy using atomic force microscopy***

Author(s): Y. Huang, T.G. Langdon  
Source: Journal of Materials Science (full set), 37 (2002), 23 (December 01), 4993-4998

***Substrate-induced freezing of alkane monolayers adsorbed on Au(111) dependant on the alkane/gold misfit***

Author(s): J. Cousty, A. Marchenko  
Source: Surface Science, 520 (2002), 3 (December 01), 128-136

***Dynamic processes occurring at the Cr<sup>III</sup><sub>aq</sub>-manganite (?-MnOOH) interface: simultaneous adsorption, microprecipitation, oxidation/reduction, and dissolution***

Author(s): R.M. Weaver, M.F. Hochella, E.S. Ilton  
Source: Geochimica et Cosmochimica Acta, 66 (2002), 23 (December 01), 4119-4132

***Directional crystallization of GaN on high-pressure solution grown substrates by growth from solution and HVPE***

Author(s): M. Bockowski, I. Grzegory, S. Krukowski, B. Lucznik, Z. Romanowski, M. Wroblewski, J. Borysiuk, J. Weyher, P. Hageman, S. Porowski  
Source: Journal of Crystal Growth, 246 (2002), 3-4 (December), 194-206

***Use of high temperature hydrogen annealing to remove sub-surface damage in bulk GaN***

Author(s): T.H. Myers, B.L. VanMil, L.J. Holbert, C.Y. Peng, C.D. Stinespring, J. Alam, J.A. Freitas, V.A. Dmitriev, A. Pechnikov, Y. Shapovalova, V. Ivantsov  
Source: Journal of Crystal Growth, 246 (2002), 3-4 (December), 244-251

***Synthesis and characterization of low pressure chemically vapor deposited titanium nitride films using TiCl<sub>4</sub> and NH<sub>3</sub>***

Author(s): N. Ramanuja, R.A. Levy, S.N. Dharmadhikari, E. Ramos, C.W. Pearce, S.C. Menasian, P.C. Schamberger, C.C. Collins  
Source: Materials Letters, 57 (2002), 2 (December), 261-269

***Surface imaging of a natural mineral surface using scanning-probe microscopy***

Author(s): D.G. Bokern, W.A.C. Ducker, K.A. Hunter, K.M. McGrath  
Source: Journal of Crystal Growth, 246 (2002), 1-2 (December), 139-149

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Author(s): M. Morstein, P.R. Willmott, H. Spillmann, M. Dobeli  
Source: Applied Physics A: Materials Science & Processing, 75 (2002), 6 (December), 647-654

***The effect of ammonia/dimethylamine ratio in deposition of hydrogenated CN<sub>x</sub> films by PE-HF-CVD***

Author(s): D. Dumitriu, P.E. Schmid, R. Sanjines, A. Karimi  
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Author(s): S.P. Ho, R.W. Carpick, T. Boland, M. LaBerge  
Source: Wear, 253 (2002), 11-12 (December), 1145-1155

***Catalytic Behaviour of Carbonate-β-CD Entrapped in PEEK-WC Membranes***

Author(s): A. Gordano, F. Trotta, C. Manfredi, E. Drioli  
Source: Journal of Inclusion Phenomena, 44 (2002), 1 (December), 433-437

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Author(s): Q.P. Wang, D.H. Zhang, Z.Y. Xue, X.T. Hao  
Source: Applied Surface Science, 201 (2002), 1-4 (November 30), 123-128

***The effect of stoichiometry on the stability of steps on TiO<sub>2</sub>(1 1 0)***

Author(s): M.J.J. Jak, A. van Kreuningen, J. Verhoeven, J.W.M. Frenken  
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Author(s): J. Xu, H. Umehara, I. Kojima  
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Author(s): G.-X. Wei, G.-B. Pan, L.-J. Wan, J.-C. Zhao, C.-L. Bai  
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Author(s): L. Zhu, O. Younes, N. Ashkenasy, Y. Shacham-Diamand, E. Gileadi  
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Author(s): M.A. Reijme, M.W.G. Ponjee, A.W. Denier van der Gon, H.H. Brongersma  
Source: Applied Surface Science, 200 (2002), 1-4 (November 15), 27-35

***Monolayers and Langmuir-Blodgett films of amphiphilic tetracyano ruthenium (II) complex: towards two-dimensional Prussian Blue analogue***

Author(s): K. Kobayashi, T. Mitoma, K. Okamoto, A. Yamagishi  
Source: Thin Solid Films, 419 (2002), 1-2 (November 01), 40-45

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Author(s): L.G. Jacobsohn, G. Capote, N.C. Cruz, A.R. Zanatta, F.L. Freire Jr.  
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Author(s): A. Podesta, G. Fantoni, P. Milani, C. Guida, S. Volponi  
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Author(s): X. Chen, C.J. Roberts, J. Zhang, M.C. Davies, S.J.B. Tendler  
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Author(s): Y.D. Yan, J.L. Burns, G.J. Jameson, S. Biggs  
Source: Journal of Colloid and Interface Science, 255 (2002), 1 (November 01), 91-97

***AlN thin films grown by ion-beam-enhanced deposition and its application to SOI materials***

Author(s): C. Men, Z. Xu, Z. An, X. Xie, M. Zhang, C. Lin  
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Author(s): F. Ma, G. Li, H. Li, H. Ma, X. Cai  
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Author(s): H.H.P. Fang, L.-C. Xu, K.-Y. Chan  
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Author(s): H. Narayan, S.B. Samanta, H.M. Agrawal, R.P.S. Kushwaha, A. Gupta, S.K. Sharma, A.V. Narlikar, D. Kanjilal  
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Author(s): Y. Tang, Y. Liu, U. Sampathkumaran, M.Z. Hu, R. Wang, M.R. De Guire

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Author(s): M. Rasa, A.P. Philipse

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Author(s): S.S. Abdel Rehim, H.H. Hassan, M.A. Amin

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Author(s): A.C. Chang, S.P. Chum, A. Hiltner, E. Baer

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Author(s): J.D. Miller, R. Du Plessis, D.G. Kotylar, X. Zhu, G.L. Simmons

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Author(s): S.W. Stone, C.D. Meinhart, S.T. Wereley

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Author(s): Jeong-Sun Oh, Yeon-Hum Yun, Bo-An Kang, Sang-Bok Kim, Young-Hwan Lee, Kyu-Seog Hwang

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Author(s): C.E. Caicedo-Martinez, E.V. Koroleva, G.E. Thompson, P. Skeldon, K. Shimizu, G. Hoellrigl, C. Campbell, E. McAlpine

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Author(s): W.C. Wang, E.T. Kang, K.G. Neoh

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Author(s): L. Wang, Y. Song, A. Wu, Z. Li, B. Zhang, E. Wang

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***Fabrication of SOI structure with AlN film as buried insulator by Ion-Cut process***

Author(s): C. Men, Z. Xu, Z. An, P.K. Chu, Q. Wan, X. Xie, C. Lin

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Author(s): L. Charlet, D. Bosbach, T. Peretyashko

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Author(s): Fabian Suarez-Garcia, Juan I. Paredes, Amelia Martinez-Alonso, Juan M.D. Tascon

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Author(s): M.R.L. Glew, A. Vollmer, S.L.M. Schroeder, Z.H. Barber

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Author(s): Franck P. Duval, Gregory G. Warr

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Author(s): Zbigniew Adamczyk, Elizeusz Musial, Barbara Jachimska, Lilianna Szyk-Warszynska, Andrzej Kowal  
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Author(s): D.I. Kreller, G. Gibson, G.W. vanLoon, J.H. Horton  
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Author(s): C. Legrand-Buscema, C. Malibert, S. Bach  
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Author(s): B.C. Wei, W. Loser, L. Xia, S. Roth, M.X. Pan, W.H. Wang, J. Eckert  
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Author(s): Elisabeth Pavlovic, Arjan P. Quist, Ulrik Gelius, Sven Oscarsson  
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Author(s): Q.-M. Xu, B. Zhang, L.-J. Wan, C. Wang, C.-L. Bai, D.-B. Zhu  
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Author(s): Y. Jiang, Q. Gu, L. Li, D.-Y. Shen, X.-G. Jin, Y.-G. Lei, C.-M. Chan  
Source: Polymer, 43 (2002), 21 (October 01), 5615-5621

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Author(s): K.M. Latt, H.S. Park, H.L. Seng, T. Osipowicz, Y.K. Lee  
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Author(s): A. Hoel, J. Ederth, J. Kopniczky, P. Heszler, L.B. Kish, E. Olsson, C.G. Granqvist  
Source: Smart Materials and Structures, 11 (2002), 5 (October 01), 640-644

***Passive dosimetry aboard the Mir Orbital Station: external measurements***

Author(s): E.R. Benton, E.V. Benton, A.L. Frank  
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Author(s): M. Ishikawa, M. Yoshimura, K. Ueda  
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Author(s): T. Riekkinen, J. Molarius, T. Laurila, A. Nurmela, I. Suni, J.K. Kivilahti  
Source: Microelectronic Engineering, 64 (2002), 1-4 (October), 289-297

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Author(s): F. Kawamura, T. Takahashi, F. Utsuno, I. Yasui  
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Author(s): S. Kirsch, A. Pfau, E. Hadicke, J. Leuninger  
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Author(s): M. Procop, M. Radtke, M. Krumrey, K. Hasche, S. Schadlich, W. Frank

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Author(s): M. Manso, S. Ogueta, P. Herrero-Fernandez, L. Vazquez, M. Langlet, J.P. Garca-Ruiz  
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Author(s): S.S.A. Oliveira, S.J. Marshall, J.F. Hilton, G.W. Marshall  
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Author(s): M. Chiba, M. Seo  
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Author(s): R. Mukhopadhyay, J.H. Hoh  
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Author(s): H. Deng, H. Zhang, Z. Lu  
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Author(s): P. Falaras, A.P. Xagas  
Source: Journal of Materials Science (full set), 37 (2002), 18 (September 15), 3855-3860

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Author(s): J.I. Paredes, A. Martinez-Alonso, J.M.D. Tascon  
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***Structural features of non-granular spherulitic maize starch***

Author(s): T.S. Nordmark, G.R. Ziegler  
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Author(s): T. Yamada, N. Takano, K. Yamada, S. Yoshitomi, T. Inoue, T. Osaka  
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***The structure of a coronene adlayer formed in a benzene solution: studies by in situ STM and ex situ LEED***

Author(s): S. Yoshimoto, R. Narita, M. Wakisaka, K. Itaya  
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Author(s): M. Li, M.L. Palacio, C. Barry Carter, W.W. Gerberich  
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Author(s): M.L. Schlegel, K.L. Nagy, P. Fenter, N.C. Sturchio  
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Author(s): A. Aneja, G.L. Wilkes  
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Author(s): V.M. De Cupere, P.G. Rouxhet  
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***Effects of substrate defect density and annealing temperature on the nature of Pt clusters vapor deposited on the basal plane of highly oriented pyrolytic graphite***

Author(s): A.R. Howells, L. Hung, G.S. Chottiner, D.A. Scherson  
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***Optical Observation of Gas Bridging between Hydrophobic Surfaces in Water***

Author(s): Naoyuki Ishida, Masanobu Sakamoto, Minoru Miyahara, Ko Higashitani  
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Author(s): Christoph Kleber, Martin Rosner, Herbert Hutter, Manfred Schreiner  
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***Two-dimensional ordered array of poly(2-methoxy,5-(n-hexadecyloxy)-p-phenylene vinylene) in monolayer by Langmuir-Blodgett technique***

Author(s): Z.K. Wu, S.X. Wu, J.H. Liao, D.G. Fu, Y.Q. Liang  
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Author(s): K. Ichikawa, M. Tarnai, M.K. Uddin, K. Nakata, S. Sato  
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Author(s): Gregory S. Watson, Bradley P. Dinte, Jolanta A. Blach, Sverre Myhra  
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***SEM, STM/STS and heavy ion irradiation studies on magnesium diboride superconductor***

Author(s): H. Narayan, S.B. Samanta, A. Gupta, A.V. Narlikar, R. Kishore, K.N. Sood, D. Kanjilal, T. Muranaka, J. Akimitsu  
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Author(s): Arayik Hambarzumyan, Stephane Biltresse, Yves Dufrene, Jacqueline Marchand-Brynaert  
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Author(s): W. Peukert, C. Mehler, M. Gotzinger  
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Author(s): M. Ito, M. Nakamura  
Source: Faraday Discussions, 121 (2002), (August 06), 71-84

***Novel method for the investigation of single nanoparticle reactivity***

Author(s): J. Meier, K.A. Friedrich, U. Stimming  
Source: Faraday Discussions, 121 (2002), (August 06), 365-372

***Scanning tunneling microscopy of Sn coadsorbed with Cu and CO on Pt(111) electrodes***

Author(s): Xiao-Yin Xiao, Stefan Tillmann, Helmut Baltruschat  
Source: PCCP: Physical Chemistry Chemical Physics, 4 (2002), 16 (August 01), 4044-4050

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Author(s): Marcel Giesbers, J. Mieke Kleijn, Martien A. Cohen Stuart  
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Author(s): S.K. Bera, S. Chaudhuri, A.K. Pal  
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Author(s): G. Alcalá, P. Skeldon, G.E. Thompson, A.B. Mann, H. Habazaki, K. Shimizu

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Author(s): Z. Wang, Q. Zeng, L. Wan, C. Wang, S. Yin, C. Bai, X. Wu, J. Yang

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Author(s): X. Wang, S. Yang, X. Yang, D. Liu, Y. Zhang, J. Wang, J. Yin, D. Liu, H.C. Ong, G. Du

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Author(s): R. Viitala, M. Jokinen, T. Peltola, K. Gunnelius, J.B. Rosenholm

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***Structure of blown film from blends of polyethylene and high melt strength polypropylene***

Author(s): A.C. Chang, L. Tau, A. Hiltner, E. Baer

Source: Polymer, 43 (2002), 18 (August), 4923-4933

***Effect of laser fluence on outgrowth formation and interfacial reaction in YBCO/CeO<sub>2</sub>/Al<sub>2</sub>O<sub>3</sub> films***

Author(s): K.D. Develos, H. Yamasaki, Y. Nakagawa, A. Sawa

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***Role of Nd/Ba substitution on the growth mode and on the structural properties of Nd-rich Re<sub>1</sub>(Nd<sub>x</sub>Ba<sub>2-x</sub>)Cu<sub>3</sub>O<sub>7-d</sub> (Re=Nd, Y) thin films***

Author(s): M. Salluzzo, C. Aruta, G. Ausanio, S. Bals, A. D'Agostino, M.G. Maglione

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Author(s): Stephane Daniele, Dmitry Tcheboukov, Liliane G. Hubert Pfalzgraf

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Author(s): J.-Y. Li, M.-L. Peng, L.-P. Zhang, L.-Z. Wu, B.-J. Wang, C.-H. Tung

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Author(s): M.L. Occelli, J.P. Olivier, A. Auroux

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Author(s): D. Liu, S. Yu, Y. Liu, C. Ren, J. Zhang, T. Ma

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Author(s): E. Kunnen, S. Mangin, V.V. Moshchalkov, Y. Bruynseraede, A. Vantomme, A. Hoser, K. Temst

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Author(s): Andreas Bund, Oliver Schneider, Volker Dehnke

Source: PCCP: Physical Chemistry Chemical Physics, 4 (2002), 15 (July 19), 3552-3554

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Author(s): D. Grujicic, B. Pesic

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***Imaging of crystal growth-induced fine surface features in zeolite A by atomic force microscopy***

Author(s): S. Dumrul, S. Bazzana, J. Warzywoda, R.R. Biederman, A. Sacco  
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Author(s): W.Q. Wang, Y. Gong, Z. Liang, F.L. Sun, D.X. Shi, H.J. Gao, X. Lin, P. Jiang, Z.M. Wang  
Source: Surface Science, 512 (2002), 3 (July 01), L379-L384

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Author(s): R. O'Hayre, S.-J. Lee, S.-W. Cha, F.B. Prinz  
Source: Journal of Power Sources, 109 (2002), 2 (July 01), 483-493

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Author(s): M.U. Guruz, V.P. Dravid, Y.W. Chung  
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Author(s): Zhongkui Wu, Sanxie Wu, Zhuhong Lu, Yingqiu Liang  
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Author(s): Frederic J. Doucet, David T. Goddard, Carol M. Taylor, Iain S. Dennis, Sheila M. Hutchison, Nicholas D. Bryan  
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***Lateral organization of  $G_{MI}$  in phase-separated monolayers visualized by scanning force microscopy***

Author(s): Manuela Menke, Stephanie Kunneke, Andreas Janshoff  
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***Study on microstructure and magnetic domain structure in sputtered  $(Ni_{66}Fe_{22}Co_{12})_x C_{1-x}$  nanocomposite films***

Author(s): H. Wang, S.P. Wong, W.Y. Cheung, N. Ke, J.B. Xu, W.Q. Li  
Source: Journal of Materials Science: Materials in Electronics, 13 (2002), 7 (July), 419-424

***Highly sensitive sensors based on the immobilization of tyrosinase in chitosan***

Author(s): G. Wang, J.-J. Xu, L.-H. Ye, J.-J. Zhu, H.-Y. Chen  
Source: Bioelectrochemistry, 57 (2002), 1 (July), 33-38

***Morphology, thermal relaxations and mechanical properties of layered silicate nanocomposites based upon high[hyphen]functionality epoxy resins***

Author(s): O. Becker, R. Varley, G. Simon  
Source: Polymer, 43 (2002), 16 (July), 4365-4373

***Structural heterogeneities and mechanical properties of vinyl/dimethacrylate networks synthesized by thermal free radical polymerisation***

Author(s): L. Rey, J. Duchet, J. Galy, H. Sautereau, D. Vouagner, L. Carrion  
Source: Polymer, 43 (2002), 16 (July), 4375-4384

***Maskless nanofabrication using the electrostatic attachment of gold particles to electrically patterned surfaces***

Author(s): P. Mesquida, A. Stemmer  
Source: Microelectronic Engineering, 61-62 (2002), (July), 671-674

***Intercomparison of scanning probe microscopes***

Author(s): R. Breil, T. Fries, J. Garnæs, J. Haycocks, D. Huser, J. Joergensen, W. Kautek, L. Koenders, N. Kofod, K.R. Koops, R. Korntner, B. Lindner, W. Mirande, A. Neubauer, J. Peltonen, G.B. Picotto, M. Pisani, H. Rothe, M. Sahre, M. Stedman, G. Wilkening  
Source: Precision Engineering, 26 (2002), 3 (July), 296-305

***Terraces and ledges on (001) spinel surfaces***

Author(s): S.V. Yanina, C. Barry Carter  
Source: Surface Science, 513 (2002), 2 (July), L402-L412

***Scanning force microscopy investigations of (semi)conductive surfaces coated with Langmuir-Blodgett dye layers***

Author(s): A. Boguta, D. Wrobel, A. Bartczak, R.M. Ion, R. Ries, A. Richter

Source: Surface Science, 513 (2002), 2 (July), 295-307

***Epitaxial growth of AlN on sapphire (0001) by sputtering: a structural, morphological and optical study***

Author(s): Y. Huttel, H. Gomez, A. Cebollada, G. Armelles, M.I. Alonso

Source: Journal of Crystal Growth, 242 (2002), 1-2 (July), 116-123

***STM/STS studies of Bi-O layers of Pb doped Bi-2223 superconductors irradiated by 100MeV oxygen ion***

Author(s): T. Banerjee, S.B. Samanta, A. Gupta, D. Kanjilal, R. Kumar, S. Ramasamy, A.V. Narlikar

Source: Solid State Communications, 123 (2002), 3-4 (July), 117-122

***Electroless plating of copper on polyimide films modified by surface grafting of tertiary and quaternary amines polymers***

Author(s): Z.J. Yu, E.T. Kang, K.G. Neoh

Source: Polymer, 43 (2002), 15 (July), 4137-4146

***Preparation, characterization and photocatalytic activity of nanocrystalline thin film TiO<sub>2</sub> catalysts towards 3,5-dichlorophenol degradation***

Author(s): I.M. Arabatzis, S. Antonaraki, T. Stergiopoulos, A. Hiskia, E. Papaconstantinou, M.C. Bernard, P. Falaras

Source: Journal of Photochemistry and Photobiology A: Chemistry, 149 (2002), 1-3 (June 28), 237-245

***Fluorescence quenching and lifetime distributions of single molecules on glass surfaces***

Author(s): M. Lee, J. Kim, J. Tang, R.M. Hochstrasser

Source: Chemical Physics Letters, 359 (2002), 5-6 (June 27), 412-419

***Covalent attachment of polymer thin layers to self-assembled monolayers on gold surface by graft polymerization***

Author(s): J. Zhang, X. Xu, J. Chen, E.-t. Kang

Source: Thin Solid Films, 413 (2002), 1-2 (June 24), 76-84

***Surface modification of p-Si by a polyethylenimine coating: influence of the surface pre-treatment. Application to a potentiometric transducer as pH sensor***

Author(s): M. Herlem, B. Fahys, G. Herlem, B. Lakard, K. Reybier, A. Trokourey, T. Diaco, S. Zairi, N. Jaffrezic-Renault

Source: Electrochimica Acta, 47 (2002), 16 (June 21), 2597 - 2602

***Electrochemical and in situ STM studies of anomalous phosphate adsorption induced on Zn UPD at Au(111) in the presence of halide ions in aqueous phosphate solutions***

Author(s): S. Takahashi, A. Aramata, M. Nakamura, K. Hasebe, M. Taniguchi, S. Taguchi, A. Yamagishi

Source: Surface Science, 512 (2002), 1-2 (June 20), 37-47

***A novel 1,5-naphthylenediamine derivative as potential organic blue light-emitting material***

Author(s): Y. Qiu, J. Qiao, Y. Gao, D. Zhang, L. Wang

Source: Synthetic Metals, 129 (2002), 1 (June 17), 25-28

***Self-organized arrays of calix[4]arene and calix[4]arene diquinone disulfide on Au(111)***

Author(s): G.-B. Pan, L.-J. Wan, Q.-Y. Zheng, C.-L. Bai, K. Itaya

Source: Chemical Physics Letters, 359 (2002), 1-2 (June 13), 83-88

***Structure and electrochemical properties of the mechanically alloyed La(Ni,M)<sub>5</sub> materials***

Author(s): M. Jurczyk, M. Nowak, E. Jankowska, J. Jakubowicz

Source: Journal of Alloys and Compounds, 339 (2002), 1-2 (June 13), 339-343

***Study of Surface Forces Dependence on pH by Atomic Force Microscopy***

Author(s): J. Gavaille, J. Takadoum

Source: Journal of Colloid and Interface Science, 250 (2002), 1 (June 01), 104-107

***Properties of Ferrofluid Nanoparticles Prepared by Coprecipitation and Acid Treatment***

Author(s): Jian Li, Dalin Dai, Baogang Zhao, Yueqiang Lin, Cenye Liu

Source: Journal of Nanoparticle Research, 4 (2002), 3 (June), 261-264

***Adsorption of polyampholytes on charged surfaces***

Author(s): F. Ozon, J.-M. di Meglio, J.-F. Joanny  
Source: The European Physical Journal E (EPJ E), 8 (2002), 3 (June), 321-330

***Sampling the conformational space of membrane protein surfaces with the AFM***

Author(s): Simon Scheuring, Daniel J. Muller, Henning Stahlberg, Hans-Andreas Engel, Andreas Engel  
Source: European Biophysics Journal, 31 (2002), 3 (June), 172-178

***Critical exponent measurement of poor quality diamond films***

Author(s): M.C. Salvadori, L.L. Melo, D.R. Martins, A.R. Vaz, M. Cattani  
Source: Surface Review and Letters, 9 (2002), 3&4 (June), 1409-1412

***Preparation and characterization of polyvinylidene fluoride hollow fiber membranes for ultrafiltration***

Author(s): M. Khayet, C.Y. Feng, K.C. Khulbe, T. Matsuura  
Source: Polymer, 43 (2002), 14 (June), 3879-3890

***Investigation of etch pits on KDP crystals with porous sol-gel coatings***

Author(s): E.K. Wheeler, P.K. Whitman, T.A. Land, J. De Yoreo, C.B. Thorsness, J.H. McWhirter, M.L. Hanna, E.L. Miller  
Source: Applied Physics A: Materials Science & Processing, 74 (2002), 6 (June), 813-823

***Metal surface swelling by heavy charged particle irradiation***

Author(s): M. Terasawa, T. Mitamura, L. Liu, H. Tsubakino, M. Niibe  
Source: Nuclear Instruments and Methods in Physics Research Section B: Beam Interactions with Materials and Atoms, 193 (2002), 1-4 (June), 329-335

***Desorption of nanoclusters (2-40 nm) from nanodispersed metal and semiconductor layers by swift heavy ions***

Author(s): I. Baranov, P. Hakansson, S. Kirillov, J. Kopniczky, A. Novikov, V. Obnorskii, A. Pchelintsev, A.P. Quist, G. Torzo, S. Yarmiychuk, L. Zennaro  
Source: Nuclear Instruments and Methods in Physics Research Section B: Beam Interactions with Materials and Atoms, 193 (2002), 1-4 (June), 798-803

***Roughening aspects of room temperature vapor deposited oligomer thin films onto Si substrates***

Author(s): G. Palasantzas, D. Tsamouras, J.T.M. De Hosson  
Source: Surface Science, 507-510 (2002), (June), 357-361

***Combined XPS, AFM, TEM and ellipsometric studies on nanoscale layers in organic light emitting diodes***

Author(s): C. Suess, F.P. Wenzl, G. Jakopic, M. Wuchse, S. Muellegger, N. Koch, A. Haase, K. Lamprecht, M. Schatzmayr, C. Mitterbauer, F. Hofer, G. Leising  
Source: Surface Science, 507-510 (2002), (June), 473-479

***Corrosion of epitaxial Fe(001) films studied with CEMS and AFM***

Author(s): I. Flis-Kabulska, B. Handke, N. Spiridis, J. Haber, J. Korecki  
Source: Surface Science, 507-510 (2002), (June), 865-871

***Dislocations at spinel surfaces***

Author(s): S.V. Yanina, C. Barry Carter  
Source: Surface Science, 511 (2002), 1-3 (June), 133-146

***Subcritical debonding of polymer/silica interfaces under monotonic and cyclic loading***

Author(s): J.M. Snodgrass, D. Pantelidis, M.L. Jenkins, J.C. Bravman, R.H. Dauskardt  
Source: Acta Materialia, 50 (2002), 9 (May 24), 2395-2411

***Cerium dioxide buffer layers at low temperature by atomic layer deposition***

Author(s): J. Paivasaari, M. Putkonen and Lauri Niinisto  
Source: Journal of Materials Chemistry, 12 (2002), 6 (May 24), 1828-1832

***The importance of being knotted: effects of the C-terminal knot structure on enzymatic and mechanical properties of bovine carbonic anhydrase II<sup>1</sup>***

Author(s): M.T. Alam, T. Yamada, U. Carlsson, A. Ikai  
Source: FEBS Letters, 519 (2002), 1-3 (May 22), 35-40

***A spectroscopic study of the fluorination and defluorination reactions on single-walled carbon nanotubes***

Author(s): Pierre R. Marcoux, Joachim Schreiber, Patrick Batail, Serge Lefrant, Joel Renouard, Guy Jacob, David Albertini, Jean-Yves Mevellec  
Source: PCCP: Physical Chemistry Chemical Physics, 4 (2002), 11 (May 21), 2278-2285

***A comparison of fractal dimensions determined from atomic force microscopy and impedance spectroscopy of anodic oxides on Zr-2.5Nb***

Author(s): G.A. McRae, M.A. Maguire, C.A. Jeffrey, D.A. Guzonas, C.A. Brown  
Source: Applied Surface Science, 191 (2002), 1-4 (May 17), 94-105

***Multifractal spectra of atomic force microscope images of amorphous electroless Ni-Cu-P alloy***

Author(s): H.-S. Yu, X. Sun, S.-F. Luo, Y.-R. Wang, Z.-Q. Wu  
Source: Applied Surface Science, 191 (2002), 1-4 (May 17), 123-127

***The combining analysis of height and phase images in tapping-mode atomic force microscopy: a new route for the characterization of thiol-coated gold nanoparticle film on solid substrate***

Author(s): P. Jiang, S.-s. Xie, S.-j. Pang, H.-j. Gao  
Source: Applied Surface Science, 191 (2002), 1-4 (May 17), 240-246

***Characterisation of polysilicon gate microstructures for 0.5  $\mu\text{m}$  CMOS devices using transmission electron microscopy and atomic force microscopy images***

Author(s): I. Ahmad, A. Omar, A. Hussain, A. Mikdad  
Source: Applied Surface Science, 191 (2002), 1-4 (May 17), 362-367

***Devitrification and microstructural coarsening of a fluoride-containing barium aluminosilicate glass***

Author(s): J.A. Griggs, K.J. Anusavice, J.J. Mlecholsky, Jr.  
Source: Journal of Materials Science (full set), 37 (2002), 10 (May 15), 2017-2022

***Surface morphologies of composites based on unsaturated polyester pre-polymer***

Author(s): M. Vayer, C. Serre, N. Boyard, C. Sinturel, R. Erre  
Source: Journal of Materials Science (full set), 37 (2002), 10 (May 15), 2043-2051

***Molecular beam epitaxy synthesis of  $\text{Si}_{1-y}\text{C}_y$  and  $\text{Si}_{1-x-y}\text{Ge}_x\text{C}_y$  alloys and Ge islands using an electron cyclotron resonance argon/methane plasma***

Author(s): J.-M. Baribeau, D.J. Lockwood, J. Balle, S.J. Rolfe, G.I. Sproule, S. Moisa  
Source: Thin Solid Films, 410 (2002), 1-2 (May 01), 61-71

***Study of the formation of chromate conversion coatings on Alclad 2024 aluminum alloy using spectroscopic ellipsometry***

Author(s): P. Campestrini, S. Bohm, T. Schram, H. Terryn, J.H.W. de Wit  
Source: Thin Solid Films, 410 (2002), 1-2 (May 01), 76-85

***Surface tracks on polymers: A means to probe material properties at the nanometer scale?***

Author(s): R.M. Papaleo  
Source: Nuclear Instruments and Methods in Physics Research Section B: Beam Interactions with Materials and Atoms, 191 (2002), 1-4 (May), 669-674

***Structure dependent electronic sputtering of a-C:H films by swift heavy ions***

Author(s): S. Ghosh, D.K. Avasthi, T. Som, A. Tripathi, D. Kabiraj, A. Ingale, S. Mishra, V. Ganesan, S. Zhang, X. Hong  
Source: Nuclear Instruments and Methods in Physics Research Section B: Beam Interactions with Materials and Atoms, 190 (2002), 1-4 (May), 164-168

***Isolated cluster ion impact on solid surfaces HOPG, Si and Cu(TiO<sub>2</sub>)/Si surfaces***

Author(s): J.-H. Song, W.-K. Choi  
Source: Nuclear Instruments and Methods in Physics Research Section B: Beam Interactions with Materials and Atoms, 190 (2002), 1-4 (May), 792-796

***The interactions of amphiphilic latexes with surfaces: the effect of surface modifications and ionic strength***

Author(s): S.W. Prescott, C.M. Fellows, R.F. Considine, C.J. Drummond, R.G. Gilbert  
Source: Polymer, 43 (2002), 11 (May), 3191-3198

***Electrospinning of polyurethane fibers***

Author(s): M.M. Demir, I. Yilgor, E. Yilgor, B. Erman

Source: Polymer, 43 (2002), 11 (May), 3303-3309

***STM observation of 1,3,5-triazines bearing rod-like benzeneazaphthalene moieties monolayers self-assembled on graphite surface***

Author(s): Yinghong Qiao, Qingdao Zeng, Zhongyin Tan, Shandong Xu, Chen Wang and Chunli Bai

Source: Journal of Materials Chemistry, 12 (2002), 5 (April 19), 1239-1241

***A scanning probe study of some short chain self-assembled alkylsilane films***

Author(s): Jingxin Li and J. Hugh Horton

Source: Journal of Materials Chemistry, 12 (2002), 5 (April 19), 1268-1273

***Nanocrystalline titanium-type metal hydride electrodes prepared by mechanical alloying***

Author(s): M. Jurczyk, E. Jankowska, M. Nowak, J. Jakubowicz

Source: Journal of Alloys and Compounds, 336 (2002), 1-2 (April 18), 265-269

***Nanohardness and elastic modulus at the interface of TiC<sub>x</sub>/Ni<sub>3</sub>Al composites determined by the nanoindentation technique***

Author(s): W. Hua, X. Wu, D. Shen, H. Lu, M. Polak

Source: Applied Surface Science, 189 (2002), 1-2 (April 14), 72-77

***Detection of plasma-induced, nanoscale dielectric constant variations in carbon-doped CVD oxides by electrostatic force microscopy***

Author(s): Todd S. Gross, Kevin G. Soucy, Ebrahim Andideh, Kent Chamberlin

Source: Journal of Physics D: Applied Physics, 35 (2002), 7 (April 07), 723-728

***Self-motion of a camphoric acid boat sensitive to the chemical environment***

Author(s): Yuko Hayashima, Masaharu Nagayama, Yukie Doi, Satoshi Nakata, Maya Kimura, Masayasu Iida

Source: PCCP: Physical Chemistry Chemical Physics, 4 (2002), 8 (April 05), 1386-1392

***Influence of reconstruction on the structure of self-assembled normal-alkane monolayers on Au(111) surfaces***

Author(s): Zhao-Xiong Xie, Zhi-Feng Huang, Xin Xu

Source: PCCP: Physical Chemistry Chemical Physics, 4 (2002), 8 (April 05), 1486-1489

***Characterization of carbon nitride layers deposited by IR laser ablation of graphite target in a remote nitrogen plasma atmosphere: nanoparticle evidence***

Author(s): A. Al Khawwam, C. Jama, P. Goudmand, O. Dessaux, A. El Achari, P. Dhamelincourt, G. Patrat

Source: Thin Solid Films, 408 (2002), 1-2 (April 03), 15-25

***Porous thin films for the characterization of atomic force microscope tip morphology***

Author(s): D. Vick, M.J. Brett, K. Westra

Source: Thin Solid Films, 408 (2002), 1-2 (April 03), 79-86

***Organic light-emitting diode on indium zinc oxide film prepared by ion assisted deposition dc sputtering system***

Author(s): W.J. Lee, Y.-K. Fang, J.-J. Ho, C.-Y. Chen, L.-H. Chiou, S.-J. Wang, F. Dai, T. Hsieh, R.-Y. Tsai, D.

Huang, F.C. Ho

Source: Solid-State Electronics, 46 (2002), 4 (April), 477-480

***Multianalytical in situ investigation of the initial atmospheric corrosion of bronze***

Author(s): M. Wadsak, T. Aastrup, I. Odnevall Wallinder, C. Leygraf, M. Schreiner

Source: Corrosion Science, 44 (2002), 4 (April), 791-802

***Crystal growth of macromolecular crystals: correlation between crystal symmetry and growth mechanisms***

Author(s): M. Plomp, A. McPherson, A.J. Malkin

Source: Journal of Crystal Growth, 237-239 (2002), (April), 306-311

***Crystal growth of sodium oxalate from aqueous solution***

Author(s): J. Lowe, M. Ogden, A. McKinnon, G. Parkinson

Source: Journal of Crystal Growth, 237-239 (2002), (April), 408-413

***Monolayer and bilayer formation of 17,19-dotetracontadiyne at a liquid/solid interface***

Author(s): D. Takajo, E. Fujiwara, S. Irie, T. Nemoto, S. Isoda, H. Ozaki, N. Toda, S. Tomii, T. Magara, Y. Mazaki, G. Yamamoto

Source: Journal of Crystal Growth, 237-239 (2002), (April), 2071-2075

***Study of roughness in  $Ti_{0.4}Al_{0.6}N/Mo$  multilayer structures***

Author(s): C.J. Tavares, L. Rebouta, E. Alves, N.P. Barradas, J. Pacaud, J.P. Riviere  
Source: Nuclear Instruments and Methods in Physics Research Section B: Beam Interactions with Materials and Atoms, 188 (2002), 1-4 (April), 90-95

***SiC film growth on Si(111) by supersonic beams of  $C_{60}$***

Author(s): R. Verucchi, L. Aversa, G. Ciullo, A. Podesta, P. Milani, S. Iannotta  
Source: The European Physical Journal B (EPJ B), 26 (2002), 4 (April), 509-514

***Magnetic force microscopy study of domain structures in magnetoresistance  $(Ni_{74}Fe_{16}Co_{10})_xAg_{1-x}$  granular films***

Author(s): H. Wang, W.Q. Li, S.P. Wong, W.Y. Cheung, N. Ke, J.B. Xu, X. Lu, X. Yan  
Source: Materials Characterization, 48 (2002), 2-3 (April), 153-158

***Studying the high-field electron conduction of tetrahedral amorphous carbon thin films by conducting atomic force microscopy***

Author(s): E.Z. Luo, S. Lin, Z. Xie, J.B. Xu, I.H. Wilson, Y.H. Yu, L.J. Yu, X. Wang  
Source: Materials Characterization, 48 (2002), 2-3 (April), 205-210

***Ferroelectric domain configuration and piezoelectric responses in (001)-oriented PMN-PT films***

Author(s): J. Wang, E.Z. Luo, K.H. Wong, H.L.W. Chan, J.B. Xu, I.H. Wilson, C.L. Choy  
Source: Materials Characterization, 48 (2002), 2-3 (April), 215-220

***Nanotube-like structures naturally formed on HOPG surface***

Author(s): J. Sun, X. Xiao, C. Chen, J. Hu, M. Li, Z. Wang, F. Gan  
Source: Materials Characterization, 48 (2002), 2-3 (April), 237-240

***Scaling analysis of Fe-implanted Ge surfaces using atomic force microscopy***

Author(s): R. Venugopal, B. Sundaravel, I.H. Wilson, J.B. Xu  
Source: Materials Characterization, 48 (2002), 2-3 (April), 241-247

***Formation of the first monolayers of CdTe on Au(111) by electrochemical atomic layer epitaxy (EC-ALE): studied by LEED, Auger, XPS, and in-situ STM***

Author(s): K. Varazo, M.D. Lay, T.A. Sorenson, J.L. Stickney  
Source: Journal of Electroanalytical Chemistry, 522 (2002), 1 (March 22), 104 - 114

***Surface morphology of NiO layers on MgO(0 0 1), MgO(1 1 0) and MgO(1 1 1)***

Author(s): B. Warot, E. Snoeck, J.C. Ousset, M.J. Casanove, S. Dubourg, J.F. Bobo  
Source: Applied Surface Science, 188 (2002), 1-2 (March 13), 151-155

***Thermal decomposition kinetics of amorphous carbon nitride and carbon films***

Author(s): Li Hong Zhang, Hao Gong, Jian Ping Wang  
Source: Journal of Physics: Condensed Matter, 14 (2002), 8 (March 04), 1697-1708

***Temperature dependence of the surface morphology of sputtered  $YBa_2Cu_3O_7$  films***

Author(s): B. Stauble-Pumpin, G.A. Mendoza, P. Prieto, B. Dam  
Source: Superconductor Science and Technology, 15 (2002), 3 (March 01), 296-301

***Vortex pinning by natural defects in thin films of  $YBa_2Cu_3O_{7-d}$***

Author(s): J.M. Huijbregtse, F.C. Klaassen, A. Szepielow, J.H. Rector, B. Dam, R. Griessen, B.J. Kooi, J. Th M. de Hosson  
Source: Superconductor Science and Technology, 15 (2002), 3 (March 01), 395-404

***The study of martensitic transformation and nanoscale surface relief in zirconia***

Author(s): X.Y. Chen, X.H. Zheng, H.S. Fang, H.Z. Shi, X.F. Wang, H.M. Chen  
Source: Journal of Materials Science Letters, 21 (2002), 5 (March 01), 415-418

***A comparison of Ti/Pt and TiN/Pt electrodes used with ferroelectric  $SrBi_2Ta_2O_9$  films***

Author(s): B.E. Watts, F. Leccabue, S. Guerri, M. Severi, M. Fanciulli, S. Ferrari, G. Tallarida, C. Morandi  
Source: Thin Solid Films, 406 (2002), 1-2 (March 01), 23-29

***Effect of polymerization conditions of pyrrole on formation, structure and properties of high gas separation thin polypyrrole films***

Author(s): D.V. Andreeva, Z. Pientka, L. Brozova, M. Bleha, G.A. Polotskaya, G.K. Elyashevich  
Source: Thin Solid Films, 406 (2002), 1-2 (March 01), 54-63

***Atomic structures of adsorbed sulfur on Cu(111) in perchloric acid solution by in situ ECSTM***

Author(s): D. Wang, Q.-M. Xu, L.-J. Wan, C. Wang, C.-L. Bai  
Source: Surface Science, 499 (2002), 2-3 (March 01), L159-L163

***Effects of annealing and quenching treatments on reconstruction of rutile thin films on sapphire substrates***

Author(s): Y. Choi, S. Yamamoto, H. Abe, H. Itoh  
Source: Surface Science, 499 (2002), 2-3 (March 01), 203-209

***Electron field emission properties of microcrystalline and nanocrystalline carbon thin films deposited by S-assisted hot filament CVD***

Author(s): S. Gupta, B.R. Weiner, G. Morell  
Source: Diamond and Related Materials, 11 (2002), 3-6 (March), 799-803

***Ion beam etching of CVD diamond film in Ar, Ar/O<sub>2</sub> and Ar/CF<sub>4</sub> gas mixtures***

Author(s): P.W. Leech, G.K. Reeves, A.S. Holland, F. Shanks  
Source: Diamond and Related Materials, 11 (2002), 3-6 (March), 833-836

***Friction coefficient measurements By LFM on DLC films as function of sputtering deposition parameters***

Author(s): L.V. Santos, V.J. Trava-Airoldi, E.J. Corat, K. Iha, M. Massi, R. Prioli, R. Landers  
Source: Diamond and Related Materials, 11 (2002), 3-6 (March), 1135-1138

***Crack path selection in adhesively bonded joints: the roles of external loads and specimen geometry***

Author(s): Buo Chen, David A. Dillard, John G. Dillard, Richard L. Clark, Jr.  
Source: International Journal of Fracture, 114 (2002), 2 (March), 167-190

***Ester-functionalized soluble single-walled carbon nanotubes***

Author(s): M.A. Hamon, H. Hui, P. Bhowmik, H.M.E. Itkis, R.C. Haddon  
Source: Applied Physics A: Materials Science & Processing, 74 (2002), 3 (March), 333-338

***Role of hydroxy-aluminosilicate ions (proto-imogolite sol) in the formation of humic substances***

Author(s): C. Liu, P.M. Huang  
Source: Organic Geochemistry, 33 (2002), 3 (March), 295-305

***Effect of excessive amount of Cd(II) cations on surface morphology of prismatic {110} faces of cadmium mercury thiocyanate crystals***

Author(s): X.N. Jiang, D. Xu, D.R. Yuan, D.L. Sun, M.K. Lu  
Source: Journal of Crystal Growth, 236 (2002), 1-3 (March), 267-272

***Indentation creep of Ge-Se chalcogenide glasses below T<sub>g</sub>: elastic recovery and non-Newtonian flow***

Author(s): J.-P. Guin, T. Rouxel, V. Keryvin, J.-C. Sangleboeuf, I. Serre, J. Lucas  
Source: Journal of Non-Crystalline Solids, 298 (2002), 2-3 (March), 260-269

***Effect of implantation voltage on phase composition and surface roughness of  $\alpha$ -Fe surface layer implanted by nitrogen ion***

Author(s): W.L. Li, Y. Sun, W.D. Fei  
Source: Applied Surface Science, 187 (2002), 3-4 (February 28), 192-198

***Surface investigation of plasma HMDSO membranes post-treated by CF<sub>4</sub>/Ar plasma***

Author(s): E. Finot, S. Roualdes, M. Kirchner, V. Rouessac, R. Berjoan, J. Durand, J.-P. Goudonnet, L. Cot  
Source: Applied Surface Science, 187 (2002), 3-4 (February 28), 326-338

***Light-assisted chemical deposition of highly (0001) oriented zinc oxide film***

Author(s): Masanobu Izaki  
Source: Chemical Communications, (2002), 5 (February 28), 476-477

***Chemical sensors of monocyclic aromatic hydrocarbons based on sol-gel materials: synthesis, structural characterization and molecular interactions***

Author(s): Maria-Luisa Calvo-Munoz, Cecile Roux, Francine Brunet, Jean-Philippe Bourgoin, Andre Ayrat, Abdeslam El-Mansouri and Thu-Hoa Tran-Thi  
Source: Journal of Materials Chemistry, 12 (2002), 3 (February 22), 461-467

***Plasma polymerization of allylpentafluorobenzene on copper surfaces***

Author(s): G. H. Yang, Yan Zhang, E. T. Kang, K. G. Neoh, A. C. H. Huan and D. M. Y. Lai

Source: Journal of Materials Chemistry, 12 (2002), 3 (February 22), 426-431

***Deposition of yttria-stabilized zirconia thin films by atomic layer epitaxy from b-diketonate and organometallic precursors***

Author(s): Matti Putkonen, Timo Sajavaara, Jaakko Niinisto, Leena-Sisko Johansson and Lauri Niinisto

Source: Journal of Materials Chemistry, 12 (2002), 3 (February 22), 442-448

***Chemical vapor deposition of 6CuO·Cu<sub>2</sub>O films on fiberglass***

Author(s): J. Medina-Valtierra, J. Ramirez-Ortiz, V.M. Arroyo-Rojas, P. Bosch, J.A. de los Reyes

Source: Thin Solid Films, 405 (2002), 1-2 (February 22), 23-28

***Morpholinoethanesulfonic acid-based buffer system for improved detection limit and stability of the fluoride ion selective electrode***

Author(s): M. Fouskaki, S. Sotiropoulou, M. Koc, N.A. Chaniotakis

Source: Analytica Chimica Acta, 478 (2002), 1 (February 12), 77-84

***The effects of drying time and relative humidity on the stability of sol-gel derived silicate films in solution***

Author(s): M.M. Collinson, H. Wang, R. Makote, A. Khramov

Source: Journal of Electroanalytical Chemistry, 519 (2002), 1-2 (February 08), 65 - 71

***Poisoning the catalytic reduction of peroxide on Pb underpotential deposition modified Au surfaces with iodine***

Author(s): S.-J. Hsieh, A.A. Gewirth

Source: Surface Science, 498 (2002), 1-2 (February 01), 147-160

***Electrochemical interface modification of CuInS<sub>2</sub> thin films***

Author(s): M. Aggour, U. Storkel, C. Murrell, S.A. Campbell, H. Jungblut, P. Hoffmann, R. Mikalo, D. Schmeiszer, H.J. Lewerenz

Source: Thin Solid Films, 403-404 (2002), (February 01), 57-61

***Thin ZnS:Cu,Ga and ZnO:Cu,Ga film phosphors***

Author(s): T.G. Kryshchuk, V.S. Khomchenko, V.P. Papusha, M.O. Mazin, Y.A. Tzyrkunov

Source: Thin Solid Films, 403-404 (2002), (February 01), 76-80

***Structural, optical and electrical properties of b-In<sub>2</sub>S<sub>3-3x</sub>O<sub>3x</sub> thin films obtained by PVD***

Author(s): N. Barreau, S. Marsillac, D. Albertini, J.C. Bernede

Source: Thin Solid Films, 403-404 (2002), (February 01), 331-334

***Highly ordered anisotropic nano-needles in para-sexiphenyl films***

Author(s): A. Andreev, H. Sitter, N.S. Saricifci, C.J. Brabec, G. Springholz, P. Hinterdorfer, H. Plank, R. Resel, A. Thierry, B. Lotz

Source: Thin Solid Films, 403-404 (2002), (February 01), 444-448

***Effects of implantation conditions on the roughness of N-implanted a-Fe***

Author(s): W.L. Li, W.D. Fei, Y. Sun

Source: Journal of Materials Science Letters, 21 (2002), 3 (February 01), 239-241

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Author(s): B. Warot, E. Snoeck, P. Baules, J.C. Ousset, M.J. Casanove, S. Dubourg, J.F. Bobo

Source: Journal of Crystal Growth, 234 (2002), 4 (February), 704-710

***Isoelectronic surfactant-induced surface step structure and correlation with ordering in GaInP***

Author(s): S.W. Jun, G.B. Stringfellow, J.K. Shurtleff, R.-T. Lee

Source: Journal of Crystal Growth, 235 (2002), 1-4 (February), 15-24

***Dissolution kinetics of dicalcium phosphate dihydrate under pseudophysiological conditions***

Author(s): N. Kanzaki, K. Onuma, G. Treboux, A. Ito

Source: Journal of Crystal Growth, 235 (2002), 1-4 (February), 465-470

***The characterization of microporosity in carbons with molecular sieve effects***

Author(s): F. Stoeckli, A. Slasli, D. Hugi-Cleary, A. Guillot

Source: Microporous and Mesoporous Materials, 51 (2002), 3 (February), 197-202

***c*-Axis oriented epitaxial  $Ba_{0.25}Sr_{0.75}TiO_3$  films display Curie-Weiss behavior**

Author(s): Y.A. Boikov, T. Claeson

Source: Physica B: Condensed Matter, 311 (2002), 3-4 (February), 250-262

***MF*M observation of perpendicular magnetization and antiferromagnetically coupled domains in Co/Ru superlattices**

Author(s): S. Hamada, K. Himi, T. Okuno, K. Takanashi

Source: Journal of Magnetism and Magnetic Materials, 240 (2002), 1-3 (February), 539-542

***Surface morphology and crystallinity control in the atomic layer deposition (ALD) of hafnium and zirconium oxide thin films***

Author(s): D.M. Hausmann, R.G. Gordon

Source: Journal of Crystal Growth, 249 (2002), 1-2 (February), 251-261

***Effect of a magnetic field on the surface topography of l-alanine crystals***

Author(s): L.A. Guzman, K. Ogawa, E. Suzuki, K. Shimizu

Source: Journal of Crystal Growth, 249 (2002), 1-2 (February), 335-340

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Author(s): A. Rar, M. Curry, J.A. Barnard, S.C. Street

Source: Tribology Letters, 12 (2002), 2 (February), 87-94

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Author(s): S. Garcia-Vergara, P. Skeldon, G.E. Thompson, P. Bailey, T.C.Q. Noakes, H. Habazaki, K. Shimizu

Source: Applied Surface Science, 205 (2002), 1-4 (January 31), 121-127

***Development of an ion-beam sputtering system for depositing thin films and multilayers of alloys and compounds***

Author(s): M. Gupta, A. Gupta, D.M. Phase, S.M. Chaudhari, B.A. Dasannacharya

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Author(s): S. Takahashi, M. Taniguchi, K. Omote, N. Wakabayashi, R. Tanaka, A. Yamagishi

Source: Chemical Physics Letters, 352 (2002), 3-4 (January 30), 213-219

***In situ monitoring of optical and structural switching in epitaxial  $YH_x$  switchable mirrors***

Author(s): J.W.J. Kerssemakers, S.J. van der Molen, R. Gunther, B. Dam, R. Griessen

Source: Journal of Alloys and Compounds, 330-332 (2002), (January 17), 342-347

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Author(s): J. Szanyi

Source: Applied Surface Science, 185 (2002), 3-4 (January 15), 161-171

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Author(s): P. Campestrini, E.P.M. van Westing, A. Hovestad, J.H.W. de Wit

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***Cyclohexane oxidation over  $Cu_2O$ -CuO and CuO thin films deposited by CVD process on fiberglass***

Author(s): J. Medina-Valtierra, J. Ramirez-Ortiz, V.M. Arroyo-Rojas, F. Ruiz

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Author(s): K. Wohnrath, J.R. Garcia, F.C. Nart, A.A. Batista, O.N. Oliveira

Source: Thin Solid Films, 402 (2002), 1-2 (January 01), 272-279

***Fabrication and superconducting properties of ternary  $REBa_2Cu_3O_x$  thin films***

Author(s): E.S. Reddy, P.V. Patanjali, E.V. Sampathkumaran, R. Pinto

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Author(s): X.N. Jiang, D. Xu, D.L. Sun, D.R. Yuan, M.K. Lu, S.Y. Guo, G.H. Zhang

Source: Journal of Crystal Growth, 234 (2002), 2-3 (January), 480-486

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Author(s): Jue Wang, Ping Xu, Xiaoli Li, Jun Shen, Guangming Wu, Bin Zhou

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***Experimental methods of determining the activity depth distribution of implanted  $^{210}\text{Pb}$  in glass***

Author(s): B. Roos, C. Samuelsson

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Author(s): H. Okudera, Y. Yokogawa

Source: Thin Solid Films, 401 (2001), 1-2 (December 17), 124-130

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Author(s): T. Lindstrom, J. Isidorsson, G.A. Niklasson

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***Effect of molecular adsorption at the liquid-metal interface on electronic conductivity: the role of surface morphology***

Author(s): G.A. Fried, Y. Zhang, P.W. Bohn

Source: Thin Solid Films, 401 (2001), 1-2 (December 17), 171-178

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Author(s): K. Vels Jensen, S. Primdahl, I. Chorkendorff, M. Mogensen

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***Controlled growth of layered silver stearate on patterned organic monolayers***

Author(s): Seung Joon Lee, Sang Woo Han and Kwan Kim

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Author(s): K. Wagner, J.W. Strojek, K. Koziel

Source: Analytica Chimica Acta, 447 (2001), 1-2 (November 26), 11-21

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Author(s): E. Bourelle, M. Inagaki, Y. Kaburagi, Y. Tanabe, Y. Hishiyama, E. Yasuda, S. Kimura

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Author(s): E. Gagoudakis, M. Bender, E. Douloufakis, N. Katsarakis, E. Natsakou, V. Cimalla, G. Kiriakidis

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Author(s): N.D. Nikolic, Z. Rakocevic, K.I. Popov

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Author(s): U. Hoffmann, S.L.S. Stipp

Source: Geochimica et Cosmochimica Acta, 65 (2001), 22 (November 15), 4131-4139

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Author(s): S.B. Basame, D. Habel-Rodriguez, D.J. Keller

Source: Applied Surface Science, 183 (2001), 1-2 (November 12), 62-67

***Coating and active surface of Ni-Zn alloys studied by atomic force microscopy***

Author(s): J. Ebothe, M. Hiane

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Author(s): M.W. Anderson, J.R. Agger, N. Hanif, O. Terasaki

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Author(s): S.S. Ono, O. Matsuoka, S. Yamamoto

Source: Microporous and Mesoporous Materials, 48 (2001), 1-3 (November 01), 103-110

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Author(s): N. Hirai, K.-i. Watanabe, S. Hara

Source: Surface Science, 493 (2001), 1-3 (November 01), 568-574

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Author(s): Anurag Gupta, Sukalpa Chaudhuri, V. Ganesan, I. Das, H. Narayan, Anil Kumar, A.J. Zaleski, A.V. Narlikar

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Author(s): E. Bourelle, Y. Kaburagi, Y. Hishiyama, M. Inagaki

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***Spectroscopic ellipsometry studies of nanocrystalline carbon thin films deposited by HFCVD***

Author(s): S. Gupta, B.R. Weiner, G. Morell

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***Magnetic behavior and role of the antiphase boundaries in Fe<sub>3</sub>O<sub>4</sub> epitaxial films sputtered on MgO (001)***

Author(s): J.F. Bobo, D. Basso, E. Snoeck, C. Gatel, D. Hrabovsky, J.L. Gauffier, L. Ressler, R. Mamy, S. Visnovsky, J. Hamrle, J. Teillet, A.R. Fert

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Author(s): C.F. Windisch, G.J. Exarhos, K.F. Ferris, M.H. Engelhard, D.C. Stewart

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***Structural and optical properties of ZnO thin films produced by filtered cathodic vacuum arc***

Author(s): X.L. Xu, S.P. Lau, B.K. Tay

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Author(s): S. Kirsch, A. Pfau, T. Frechen, W. Schrof, P. Pfohler, D. Francke

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Author(s): A. Pakes, F. Echeverria, P. Skeldon, G.E. Thompson, J.W. Fraser, J.P. McCaffrey, S. Moisa, M.J. Graham, H. Habazaki, K. Shimizu

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***Influence of buffer layer and 6H-SiC substrate polarity on the nucleation of AlN grown by the sublimation sandwich technique***

Author(s): Y. Shi, Z.Y. Xie, L.H. Liu, B. Liu, J.H. Edgar, M. Kuball

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Author(s): X.N. Jiang, D. Xu, D.L. Sun, D.R. Yuan, M.K. Lu, G.H. Zhang, Q. Fang

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Author(s): Kiyoshi Kanie, Masayuki Nishii, Takayasu Yasuda, Takashi Taki, Seiji Ujiie, Takashi Kato

Source: Journal of Materials Chemistry, 11 (2001), 11 (October 24), 2875-2886

***Realization of different carbon nanostructures by a microwave plasma enhanced chemical vapor deposition technique***

Author(s): S. Kumar, C.M.S. Rauthan, K.M.K. Srivatsa, P.N. Dixit, R. Bhattacharyya  
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***The mechanism of self-reversal of thermoremanence in natural hemoilmenite crystals: new experimental data and model***

Author(s): M. Prevot, K.A. Hoffman, A. Goguitchaichvili, J.-C. Doukhan, V. Shcherbakov, M. Bina  
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***Resolving orthoclase dissolution processes with atomic force microscopy and X-ray reflectivity***

Author(s): H.H. Teng, P. Fenter, L. Cheng, N.C. Sturchio  
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Author(s): Adrian C. Stevenson, Hireen M. Mehta, Rajinder S. Sethi, Larisa-Emilia Cheran, Michael Thompson, Ian Davies, Christopher R. Lowe  
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Author(s): G.N. Phillips, K. O'Grady, J.C. Lodder  
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***Influence of tip size on AFM roughness measurements***

Author(s): D.L. Sedin, K.L. Rowlen  
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***Effect of water content in solvent on the critical temperature in the formation of self-assembled hexadecyltrichlorosilane monolayers on mica***

Author(s): L.-J. Chen, Y.-H. Tsai, C.-S. Liu, D.-R. Chiou, M.-C. Yeh  
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Author(s): R.M. Metzger  
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Author(s): X.-P. Luo, N. Silikas, M. Allaf, N.H.F. Wilson, D.C. Watts  
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Author(s): P.A. Maurice, M.A. Vierkorn, L.E. Hersman, J.E. Fulghum  
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Author(s): F.A. Harding, N.A. Alarcon, P.G. Toledo  
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Author(s): B. Bhushan  
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Author(s): D.N. Hanlon, I. Todd, E. Peekstok, W.M. Rainforth, S. van der Zwaag  
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Author(s): Mohamed Mohamedi, Yasunari Hisamitsu, Takashi Kudo, Takashi Itoh, Isamu Uchida  
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Author(s): K. Darcovich, F.N. Toll, A. Meurk  
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Author(s): X.Q. Pan, L. Fu

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***Improvement of signal to noise ratio for Co/Pd multilayer perpendicular magnetic recording media by the addition of an underlayer***

Author(s): T. Onoue, T. Asahi, K. Kuramochi, J. Kawaji, T. Homma, T. Osaka

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Author(s): H. Okuo, T. Onoue, T. Asahi, T. Osaka

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Author(s): H. Spillmann, P.R. Willmott, M. Morstein, P.J. Uggowitzer

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Author(s): L. Hong, X. Chen, Z. Cao

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Author(s): Y. Zhang, W. Li, B. Tang, S. Ge, X. Hu, M.H. Rafailovich, J.C. Sokolov, D. Gersappe, D.G. Peiffer, Z.

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Author(s): T. Senna, N. Ikemiya, M. Ito

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Author(s): B. Balamurugan, B.R. Mehta

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Author(s): R.J. Zhang, S.P. Zheng, M.Q. Wang, K.Z. Yang, J.B. Li, J.F. Hu

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Author(s): M. Hu, S. Noda, T. Okubo, Y. Yamaguchi, H. Komiyama

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Author(s): L. Jiang, A.G. Fitzgerald, M.J. Rose

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Author(s): M.J. Shenton, G.C. Stevens

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Author(s): A.G. Stack, S.R. Higgins, C.M. Eggleston

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Author(s): Gillian L.G. Goring, R. Stephen Brown, J. Hugh Horton

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Author(s): Minna Nieminen, Timo Sajavaara, Eero Rauhala, Matti Putkonen, Lauri Niinisto  
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Author(s): Paul A. Williams, Anthony C. Jones, Jamie F. Bickley, Alexander Steiner, Hywel O. Davies, Timothy J. Leedham, Susan A. Impey, Joanne Garcia, Stephen Allen, Aline Rougier, Alexandra Blyr  
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Author(s): I. Gouzman, E. Grossman, G. Lempert, Y. Noter, Y. Altshuler, Y. Lifshitz  
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Author(s): T. Nishino, P. Buhmann, T. Ito, Y. Umezawa  
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Author(s): M. Seo, M. Chiba  
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Author(s): E. Ammann, C. Beuret, P.-F. Indermuhle, R. Kotz, N.F. de Rooij, H. Siegenthaler  
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Author(s): J.M. Guilemany, J.M. Miguel, S. Armada, S. Vizcaino, F. Climent  
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Author(s): G. Kuri, G. Materlik, V. Hagen, R. Wiesendanger  
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Author(s): A. Mannelqvist, M. Ring Groth  
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Author(s): Franz L. Dickert, Paul Achatz, Konstantin Halikias  
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Author(s): U. Becker, B. Gasharova  
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Author(s): Valeria Mollica, Alberto Borassi, Annalisa Relini, Ornella Cavalleri, Martino Bolognesi, Ranieri Rolandi, Alessandra Gliozzi  
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Author(s): C.M. Ng, A.T.S. Wee, C.H.A. Huan, A. See  
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Author(s): J.-H. Song, S.N. Kwon, D.-K. Choi, W.-K. Choi

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Author(s): W. Yu, T.-M. Ko

Source: European Polymer Journal, 37 (2001), 9 (September), 1791-1799

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Author(s): V.M. Nagirnyi, R.D. Apostolova, A.S. Baskevich, P.M. Litvin, E.M. Shembel'

Source: Russian Journal of Applied Chemistry, 74 (2001), 9 (September), 1474-1478

***Adsorbate-induced disorder-to-order surface reconstruction: iodine on Pd(111) revisited by EC-STM***

Author(s): Y.-G. Kim, J.H. Baricuatro, M.P. Soriaga, D. Wayne Suggs

Source: Journal of Electroanalytical Chemistry, 509 (2001), 2 (August 24), 170 - 174

***Bulk- and surface-initiated chemical in situ polymerisation of 2,5-dimethoxyaniline and 2-methoxyaniline on thiol-coated gold electrodes***

Author(s): M. Mazur, P. Krysinski

Source: Electrochimica Acta, 46 (2001), 26-27 (August 24), 3963 - 3971

***Effects of the redox state on the morphology of the regioregular sexi-3-alkylthiophene***

Author(s): M. Lapkowski, J. Zak, M. Kolodziej-Sadlok, S. Guillerez, G. Bidan

Source: Electrochimica Acta, 46 (2001), 26-27 (August 24), 4001 - 4006

***Electroless plating of palladium and copper on polypyrrole films***

Author(s): V.W.L. Lim, E.T. Kang, K.G. Neoh

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***Comparative kinetic study of Cd diffusion into Au(100) and Ag(100) during electrodeposition***

Author(s): Ruxandra Vidu, Nobumitsu Hirai, Shigeta Hara

Source: PCCP: Physical Chemistry Chemical Physics, 003 (2001), 016 (August 21), 3320-3324

***Underpotential and bulk deposition of copper on Pd(111) in sulfuric acid solution studied by in situ scanning tunneling microscopy***

Author(s): Jun Okada, Junji Inukai, Kingo Itaya

Source: PCCP: Physical Chemistry Chemical Physics, 003 (2001), 016 (August 21), 3297-3302

***Scanning tunneling microscopy investigations of ruthenium- and osmium-modified Pt(100) and Pt(110) single crystal substrates***

Author(s): Alechia Crown, Andrzej Wieckowski

Source: PCCP: Physical Chemistry Chemical Physics, 003 (2001), 016 (August 21), 3290-3296

***Complex formation between halogens and sulfoxides on metal surfaces***

Author(s): Siv K. Si, Andrew A. Gewirth

Source: PCCP: Physical Chemistry Chemical Physics, 003 (2001), 016 (August 21), 3325-3329

***Electrochemical, spectroscopic and SPM evidence for the controlled formation of self-assembled monolayers and organised multilayers of ferrocenyl alkyl thiols on Au(111)***

Author(s): A.S. Viana, L.M. Abrantes, G. Jin, S. Floate, R.J. Nichols, M. Kalaji

Source: PCCP: Physical Chemistry Chemical Physics, 003 (2001), 016 (August 21), 3411-3419

***Immobilization of horseradish peroxidase on nanometre-scale domains of binary self-assembled monolayers formed from dithiobis-N-succinimidyl propionate and 1-tetradecanethiol on Au(111)***

Author(s): Daisuke Hobara, Yusuke Uno, Takashi Kakiuchi

Source: PCCP: Physical Chemistry Chemical Physics, 003 (2001), 016 (August 21), 3437-3441

***Structure of ordered electrified interfaces: EC-STM of hydroquinone sulfonate at well-defined Pd(111) electrodes***

Author(s): Youn-Geun Kim, Manuel P. Soriaga

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***Ordered structures of self-assembled monolayers of 3-mercaptopropionic acid on Au(111): in situ scanning tunneling microscopy study***

Author(s): Takahiro Sawaguchi, Yukari Sato, Fumio Mizutani

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***In situ scanning tunneling microscopy study of adsorption of diaza-15-crown-5 on Cu(111)***

Author(s): D. Wang, Q.-M. Xu, L.-J. Wan, C. Wang, C.-L. Bai

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Author(s): J. Borc, K. Sangwal, A. Richter, R. Ries, E. Mielniczek-Brzoska

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Author(s): L. Sziraki, E. Szocs, Z. Pilbath, K. Papp, E. Kalman

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Author(s): H.-H. Strehblow, V. Maurice, P. Marcus

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Author(s): J. Telegdi, M.M. Shaglouf, A. Shaban, F.H. Karman, I. Betroti, M. Mohai, E. Kalman

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Author(s): F.J. Doucet, C. Schneider, S.J. Bones, A. Kretchmer, I. Moss, P. Tekely, C. Exley

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Author(s): K. Komatsu, H. Nanjo, Y. Yamagishi, T. Kaino

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Author(s): T. Yaji, K. Yoshida, S. Isoda, T. Kobayashi, N. Sato, I. Shirotani

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Author(s): G.H. Yang, E.T. Kang, K.G. Neoh, Y. Zhang, K.L. Tan

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Author(s): M. Hiane, J. Ebothe

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Author(s): D.C. Crew, J. Kim, L.H. Lewis, K. Barmak

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Author(s): E.N. Coker, J.C. Jansen, F. DiRenzo, F. Fajula, J.A. Martens, P.A. Jacobs, A. Sacco

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Author(s): D.S.L. Pontes, E.R. Leite, F.M. Pontes, E. Longo, J.A. Varela

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Author(s): M.S. Castro, M.P. Suarez, C.M. Aldao

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Author(s): M. Avramov-Ivic, S. Strbac, V. Mitrovic  
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Author(s): Z. Wang, X. Hu  
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Author(s): B. Nelles, K.F. Heidemann, B. Kleemann  
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Author(s): E. Fujiwara, S. Isoda, T. Ogawa, T. Kobayashi, Y. Yamashita  
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***Preparation and properties of ferroelectric Pb1 - xCaxTiO3 thin films produced by the polymeric precursor method***

Author(s): D.S.L. Pontes, E.R. Leite, F.M. Pontes, E. Longo, J.A. Varela  
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Author(s): Yong Yee Lim, M. Munawar Chaudhri  
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Author(s): M. Deleu, K. Nott, R. Brasseur, P. Jacques, P. Thonart, Y.F. Dufrene  
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Author(s): J. Shieh, M.H. Hon  
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Author(s): I. Yamaguchi, T. Terayama, S. Ohnishi, T. Manabe, T. Shimizu, T. Kumagai, S. Mizuta  
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Author(s): D. Gan, S. Lu, C. Song, Z. Wang  
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Author(s): B.D. Beake, G.J. Leggett, P.H. Shipway  
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Author(s): X. Wallart, D. Deresmes, F. Mollot  
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Author(s): M. Sadeghi, S. Wang  
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Author(s): C. Bourgognon, S. Tatarenko, J. Cibert, H. Boukari, V.H. Etgens, L. Carbonell, B. Gilles, A. Marty, Y. Samson  
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Author(s): P. Fons, K. Iwata, A. Yamada, K. Matsubara, S. Niki, K. Nakahara, T. Tanabe, H. Takasu

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Author(s): H. Y. Liu, B. Xu, D. Ding, Y.H. Chen, J.F. Zhang, J. Wu, Z.G. Wang

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Author(s): M.J. da Silva, A.A. Quivy, P.P. Gonzalez-Borrero, N.T. Moshegov, E. Marega

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Author(s): Z. Niu, X. Wang, Z. Miao, S. Feng

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Author(s): J. Kang, S. Tsunekawa, B. Shen, Z. Mai, C. Wang, T. Tsuru, A. Kasuya

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Author(s): S. Isoda, T. Nemoto, E. Fujiwara, Y. Adachi, T. Kobayashi

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Author(s): M.S.J. Nunes, E.R. Leite, F.M. Pontes, N.M. Duboc, E. Longo, J.A. Varela

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Author(s): J.F. Bresse, S. Blayac

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Author(s): R. Jansson, S. Zangoie, T. Kugler, H. Arwin

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Author(s): S. Baba, K. Numata, H. Saito, M. Kumagai, T. Ueno, B. Kyoh, S. Miyake

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Author(s): S.J. Yu, Z.F. Ding, J. Xu, J.L. Zhang, T.C. Ma

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Author(s): B. Warot, E. Snoeck, P. Baules, J.C. Ousset, M.J. Casanove, S. Dubourg, J.F. Bobo

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Author(s): M.E. Rincon, O. Gomez-Daza, C. Corripio, A. Orihuela

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Author(s): A. Inberg, Y. Shacham-Diamand, E. Rabinovich, G. Golan, N. Croitoru

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***The growth of MgO buffer layers on sapphire for the epitaxy of  $BaTiO_3$  optical thin films***

Author(s): J.G. Lisoni, M. Siegert, C.H. Lei, W. Biegel, J. Schubert, W. Zander, C. Buchal

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Author(s): P. Merel, M. Chaker, M. Tabbal, H. Pepin  
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Author(s): S.S. Ono, S. Yamamoto, H. Yao, O. Matsuoka, N. Kitamura  
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Author(s): G.W. Ho, A.T.S. Wee, J. Lin, W.C. Tjui  
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Author(s): Thomas Ponnuswamy, Jin-Jian Chen, Fei Xu, Oliver Chyan  
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Author(s): F. Balzer, H-G Rubahn  
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Author(s): C. Nunes de Carvalho, A. Luis, G. Lavareda, A. Amaral, P. Brogueira, M.H. Godinho  
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Author(s): A. Amaral, P. Brogueira, C. Nunes de Carvalho, G. Lavareda  
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Author(s): O. Groning, L.-O. Nilsson, P. Groning, L. Schlapbach  
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Author(s): R. Mishra, S.P. Tripathy, K.K. Dwivedi, D.T. Khathing, S. Ghosh, M. Muller, D. Fink  
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Author(s): K. Oberg, B. Eliasson  
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Author(s): S. Biggs, C.A. Lukey, G.M. Spinks, S.-T. Yau  
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Author(s): J.P. Singh, R. Singh, N.C. Mishra, V. Ganesan, D. Kanjilal  
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Author(s): B. Du, J. Liu, Q. Zhang, T. He  
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Author(s): M. Engelmann, B.E. McCandless, R.W. Birkmire  
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Author(s): Tomoaki Nishino, Philippe Buhlmann, Takashi Ito, Yoshio Umezawa  
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Author(s): M. Manimaran, P.R. Vaya, S. Basu, T. Sato, T. Kanayama  
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Author(s): I. Doudevski, D.K. Schwartz  
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Author(s): A.G. Fitzgerald, L. Jiang, M.J. Rose, T.J. Dines  
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Author(s): X. Wang, Z. Wang, Y.q. Liu, C. Wang, C. Bai, D. Zhu  
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Author(s): P. Campestrini, E.P.M. van Westing, J.H.W. de Wit  
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Author(s): E. Finot, E. Lesniewska, J.-P. Goudonnet, J.-C. Mutin, M. Domenech, A. At Kadi  
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Author(s): S. Perrin, M. Pijolat, F. Valdivieso, M. Soustelle  
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Author(s): D. Wang, L.-J. Wan, Q.-M. Xu, C. Wang, C.-L. Bai  
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Author(s): Patricia M. McGuiggan, Jun Zhang, Stephen M. Hsu  
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Author(s): A. Hirohata, Y.B. Xu, C.C. Yao, H.T. Leung, W.Y. Lee, S.M. Gardiner, D.G. Hasko, J.A.C. Bland, S.N. Holmes

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Author(s): H.V. Kuo, C.A. Merton, E. Dan Dahlberg

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Author(s): E. Rocca, G. Bertrand, C. Rapin, J.C. Labrune

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Author(s): H.B. Lu, J. Homola, C.T. Campbell, G.G. Nenninger, S.S. Yee, B.D. Ratner

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Author(s): E. Riedo, J. Chevrier, F. Comin, H. Brune

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Author(s): C.A. Zell, W. Freyland

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Author(s): Z. Tang, S. Liu, S. Dong, E. Wang

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Author(s): L. Henke, P.A.E. Piuñno, N. Nagy, C.C. Wust, U.J. Krull

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Author(s): F.M. Pontes, E.R. Leite, E.J.H. Lee, E. Longo, J.A. Varela

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Author(s): Haiyan Zhang, Chunyan Wu, Lizheng Liang, Yiming Chen, Yanyang He, Yanjuan Zhu, Ning Ke, J.B. Xu, S.P. Wong, Aixiang Wei, Shaoqi Peng

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Author(s): K. Namjesnik-Dejanovic, P.A. Maurice

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Author(s): N. Stanford, M. Ferry

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Author(s): J.M. Huijbregtse, J.H. Rector, B. Dam

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Author(s): G. Zhang, Y. Kuwahara, J. Wu, M. Akai-Kasaya, A. Saito, M. Aono

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Author(s): A. Martinez-Ruiz, J. Valenzuela-Benavides, L. Morales de la Garza, N. Batina

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Author(s): J. Lahann, D. Klee, W. Pluester, H. Hoecker

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Author(s): Z.-G. Yang, C. Zhang, B.-Z. Bai, H.-S. Fang

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Author(s): C.-H. Xu, W. Gao, S. Li

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Author(s): J.D. Tong, P. Leclere, C. Doneux, J.L. Bredas, R. Lazzaroni, R. Jerome

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Author(s): G. Bar, L. Delineau, A. Hafele, M.-H. Whangbo

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Author(s): T. Kawachi, M. Isshiki, M. Takeda, M. Shibayama

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Author(s): B. Warot, E. Snoeck, P. Baules, J.C. Ousset, M.J. Casanove, S. Dubourg, J.F. Bobo

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Author(s): S.I. Castaneda, V.A.A. Espinoza, F.L. Freire, D.F. Franceschini, L.G. Jacobsen

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Author(s): P. Nagy, J. Miklosi, P. Poczik, K. Papp, Z. Konya, I. Kiricsi, G. Palinkas, E. Kalman

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Author(s): T.M. Nabi, H. Sambe, D.E. Ramaker

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Author(s): J. Zhang, L.-J. Wan, K. Itaya

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Author(s): A. Crown, I.R. Moraes, A. Wieckowski

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Author(s): J.E. Soto, Y.-G. Kim, X. Chen, Y.-S. Park, M.P. Soriaga

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Author(s): I. Markovich, D. Mandler

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Author(s): G. Hemakanthi, A. Dhathathreyan, T. Ramasami, D. Mobius

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Author(s): W. Gulbinski, D. Pailharey, T. Suszko, Y. Mathey

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Author(s): K. Gotoh, M. Tagawa, N. Ohmae, H. Kinoshita, M. Tagawa

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Author(s): S.R. Brankovic, J.X. Wang, R.R. Adzic

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Author(s): F. Echeverria, P. Skeldon, G. E. Thompson, H. Habazaki, K. Shimizu

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Author(s): S. Guessab, L. Boyer, F. Houze, S. Noel, O. Schneegans

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Author(s): M. Higo, X. Lu, U. Mazur, K.W. Hipps

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Author(s): A.Z. Simoes, A.H.M. Gonzalez, M.A. Zaghete, J.A. Varela, B.D. Stojanovic

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Author(s): S.F. Durrant, V. Baranauskas, A.C. Peterlevitz, S.G. Castro, R. Landers, M.A. Bica de Moraes

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Author(s): J.D. Carey, S.R.P. Silva

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Author(s): J.M. Jaramillo, R.D. Mansano, L.S. Zambom, M. Massi, H.S. Maciel

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Author(s): L.V. Santos, V.J. Trava-Airoldi, K. Iha, E.J. Corat, M.C. Salvadori

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Author(s): P.J. de Lange, E. Mader, K. Mai, R.J. Young, I. Ahmad

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***Effects of plasma oxidation on the surface and interfacial properties of ultra-high modulus carbon fibres***

Author(s): M.A. Montes-Moran, A. Martinez-Alonso, J.M.D. Tascon, R.J. Young

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Author(s): F.M. Pontes, E.R. Leite, E.J.H. Lee, E. Longo, J.A. Varela

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Author(s): J.I. Paredes, A. Martinez-Alonso, J.M.D. Tascon

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Author(s): B.D. Beake, G.J. Leggett, M.R. Alexander

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Author(s): S. Hirsekorn, U. Rabe, W. Arnold

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Author(s): A. Kuhle, J. Garnæs

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Author(s): Y. Henry, K. Ounadjela, L. Piraux, S. Dubois, J.-M. George, J.-L. Duvail

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Author(s): Mandana Veisheh, Yong Zhang, Karen Hinkley, Miqin Zhang

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Author(s): M.D. Groner, C.A. Koval

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Author(s): M. Ormaetxea, J. Forcada, F. Mugika, A. Valea, M. D. Martin, C. Marieta, S. Goyanes, I. Mondragon

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Author(s): J.P. Kleider, C. Longeaud, R. Bruggemann, F. Houze

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Author(s): M.B. Ali, M. Lemiti, N. Jaffrezic-Renault, C. Martelet, J.M. Chovelon, H.B. Ouada

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Author(s): J.C. Arnault, A. Knoll, E. Smigiel, A. Cornet

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Author(s): B. Basnar, G. Friedbacher, H. Brunner, T. Vallant, U. Mayer, H. Hoffmann

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Author(s): M. Levlín, A. Laakso

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Author(s): Y. Kuwahara

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Author(s): G. Hemakanthi, A. Dhathathreyan  
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Author(s): D. Oyamatsu, H. Kanemoto, S. Kuwabata, H. Yoneyama  
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Author(s): A.S. Lea, J.E. Amonette, D.R. Baer, Y. Liang, N.G. Colton  
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Author(s): R. Caminiti, A. Capobianchi, P. Marovino, A.M. Paoletti, G. Padeletti, G. Pennesi, G. Rossi  
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Author(s): H. Wang, S.P. Wong, W.F. Lau, X. Yan, X. Lu, W.Y. Cheung, N. Ke  
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Author(s): N. Hellgren, M.P. Johansson, E. Broitman, P. Sandstrom, L. Hultman, J.-E. Sundgren  
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Author(s): Y. Masuda, T. Sugiyama, H. Lin, W.S. Seo, K. Koumoto  
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***Two-dimensional arrangement of fine silica spheres on self-assembled monolayers***

Author(s): Y. Masuda, W.S. Seo, K. Koumoto  
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Author(s): M.P. Pileni  
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Author(s): W. Sun, D. G. Ivey  
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Author(s): F.L. Freire, M.E.H. Maia da Costa, L.G. Jacobsohn, D.F. Franceschini  
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***Study of the mechanical properties of tetrahedral amorphous carbon films by nanoindentation and nanowear measurements***

Author(s): E. Martnez, J.L. Andujar, M.C. Polo, J. Esteve, J. Robertson, W.I. Milne  
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Author(s): P.D. Maguire, D.P. Magill, A.A. Ogwu, J.A. McLaughlin  
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Author(s): P. Milani, A. Podesta, P. Piseri, E. Barborini, C. Lenardi, C. Castelnovo  
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Author(s): S. Santucci, A.V. la Cecilia, A. DiGiacomo, R.A. Phani, L. Lozzi  
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Author(s): M. Aktary, M.T. McDermott, J. Torkelson

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Author(s): F. Lin, J. Wu, W.-h. Jiang, H. Cui, Z.-g. Wang

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Author(s): S. Marais, M. Metayer, F. Poncin-Epaillard

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Author(s): M. Kono, X. Sun, R. Li, K.C. Wong, K.A.R. Mitchell, T. Foster

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Author(s): Paul F. van Hutten, Georges Hadziioannou

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Author(s): Hitoshi Shindo, Akihiro Seo, Tatsuhiro Watabe

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Author(s): H. Munakata, S. Kuwabata, Y. Ohko, H. Yoneyama

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Author(s): T. Sawaguchi, Y. Sato, F. Mizutani

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Author(s): Z. Tang, E. Wang

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Author(s): G. Eltanany, R.J. Tipton, D. Teeters

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Author(s): Q. Ouyang, K. Ishida, K. Okada

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Author(s): V. Maurice, S. Cadot, P. Marcus

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Author(s): T.A. Sorenson, K. Varazo, D.W. Suggs, J.L. Stickney

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Author(s): E. Mahe, D. Devilliers

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Author(s): T. Huser, M. Yan

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Author(s): A.R. Burns, R.W. Carpick, D.Y. Sasaki, J.A. Shelnutt, R. Haddad  
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Author(s): I.G. Marino, D. Bersani, P.P. Lottici  
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Author(s): M. Cartier, S. Auffret, Y. Samson, P. Bayle-Guillemaud, B. Dieny  
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Author(s): H.F. Liu, H. Chen, M. Xu, L. Wan, Z.H. Mai, Q. Huang, J.M. Zhou  
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Author(s): R. Tucker, P. Compston, P.-Y.B. Jar  
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Author(s): J.J. Yu, J.Y. Zhang, I.W. Boyd, Y.F. Lu  
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Author(s): Ning Chi, Kwong-Yu Chan, David Lee Phillips  
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Author(s): A. Dekanski, J. Stevanovic, R. Stevanovic, B.Z. Nikolic, V.M. Jovanovic  
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Author(s): A. Dekanski, J. Stevanovic, R. Stevanovic, V.M. Jovanovic  
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Author(s): J. Lappalainen, V. Lantto, J. Frantti, S.A. Ivanov  
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Author(s): A. Dias, V.S.T. Ciminelli  
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Author(s): Y.A. Kim, T. Matusita, T. Hayashi, M. Endo, M.S. Dresselhaus  
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Author(s): E. Bourelle, Y. Tanabe, E. Yasuda, S. Kimura  
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Author(s): J.I. Paredes, A. Martinez-Alonso, J.M.D. Tascon  
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Author(s): J. Ravier, F. Houze, F. Carmona, O. Schneegans, H. Saadaoui

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Author(s): S. Colis, G. Schmerber, A. Dinia

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Author(s): Adam Feiler, Paul Jenkins, John Ralston

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Author(s): S. Zangoie, J. A. Woollam

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Author(s): H.X. Qin, J.S. Zhu, Z.Q. Jin, Y. Wang

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Author(s): A.H. Schafer, C. Seidel, H. Fuchs

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Author(s): Zhai Jiwei, Yao Xi, Zhang Liangying

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Author(s): Frank Endres, Alexia Schweizer

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Author(s): C. Perruchot, M.M. Chehimi, M. Delamar, E. Cabet-Deliry, B. Miksa, S. Slomkowski, M.A. Khan, S.P. Armes

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Author(s): C.J. Tavares, L. Rebouta, E. Alves, A. Cavaleiro, P. Goudeau, J.P. Riviere, A. Declémy

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Author(s): B. Heck, T. Hugel, M. Iijima, G. Strobl

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Author(s): J. Luo, Y.-M. Chiang

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Author(s): M.P. de Boer, J.A. Knapp, T.A. Michalske, U. Srinivasan, R. Maboudian

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Author(s): S. Shibata, K. Miyajima, H. Yoshikawa, T. Yano, M. Yamane

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Author(s): L. Dreeskornfeld, R. Segler, G. Haindl, O. Wehmeyer, S. Rahn, E. Majkova, U. Kleineberg, U. Heinzmann, P. Hudek, I. Kostic

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Author(s): G.B. Stringfellow, J.K. Shurtleff, R.T. Lee, C.M. Fetzer, S.W. Jun  
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***MOVPE strain layers - growth and application***

Author(s): W. Strupinski, L. Dillner, J. Sass, K. Kosiel, J. Stake, M. Ingvarson, R. Jakiela  
Source: Journal of Crystal Growth, 221 (2000), 1-4 (December), 20-25

***AFM study and optical properties of GaAsN/GaAs epilayers grown by MOVPE***

Author(s): L. Auvray, H. Dumont, J. Dazord, Y. Monteil, J. Bouix, C. Bru-Chevalier  
Source: Journal of Crystal Growth, 221 (2000), 1-4 (December), 475-480

***MOVPE fabrication of continuous transitions between GaAs/AlGaAs quantum wells and V-groove quantum wires***

Author(s): F. Lelarge, D. Kaufman, B. Dwir, S. Mautino, A. Rudra, E. Kapon  
Source: Journal of Crystal Growth, 221 (2000), 1-4 (December), 540-545

***Emulsification, drying and film formation of alkyd emulsions***

Author(s): P.K. Weissenborn, A. Motiejauskaite  
Source: Progress in Organic Coatings, 40 (2000), 1-4 (December), 253-266

***Silane-Based Coatings on Polypropylene, Deposited by Atmospheric Pressure Glow Discharge Plasmas***

Author(s): Francoise Massines, Nicolas Gherardi, Francoise Sommer  
Source: Plasmas and Polymers, 5 (2000), 3/4 (December), 151-172

***Silver ions adsorbed to self-assembled monolayers of alkanedithiols on gold surfaces form Ag-dithiol-Au multilayer structures***

Author(s): W. Deng, L. Yang, D. Fujita, H. Nejoh, C. Bai  
Source: Applied Physics A: Materials Science & Processing, 71 (2000), 6 (December), 639-642

***Micropatterned solid-supported membranes formed by micromolding in capillaries***

Author(s): Andreas Janshoff, Stephanie Kunneke  
Source: European Biophysics Journal, 29 (2000), 7 (December), 549-554

***Characterization of zeolites A and X grown in low earth orbit***

Author(s): J. Warzywoda, M. Valcheva-Traykova, G.A. Rossetti, N. Bac, R. Joesten, S.L. Suib, A. Sacco  
Source: Journal of Crystal Growth, 220 (2000), 1-2 (November 15), 150-160

***Surface imaging of fragile materials with hydrophobic atomic force microscope tips***

Author(s): Z.Q. Wei, C. Wang, C.L. Bai  
Source: Surface Science, 467 (2000), 1-3 (November 10), 185-190

***Surface morphology determined by (001) single-crystal SrTiO<sub>3</sub> termination***

Author(s): G. Koster, G. Rijnders, D.H.A. Blank, H. Rogalla  
Source: Physica C: Superconductivity and its Applications, 339 (2000), 4 (November 01), 215-230

***Critical exponents of diamond films: possible influence of spatially correlated noise***

Author(s): M. Cattani, M.C. Salvadori  
Source: Thin Solid Films, 376 (2000), 1-2 (November 01), 264-266

***Adlayer structures of CO adsorbed on Ni(111) electrode surfaces studied by in situ STM combined with IRAS***

Author(s): N. Ikemiya, T. Suzuki, M. Ito  
Source: Surface Science, 466 (2000), 1-3 (November 01), 119-126

***Polarity effects of substrate surface in homoepitaxial ZnO film growth***

Author(s): S. Zhu, C.-H. Su, S.L. Lehoczky, M.T. Harris, M.J. Callahan, P. McCarty, M.A. George  
Source: Journal of Crystal Growth, 219 (2000), 4 (November 01), 361-367

***Changes in surface stress at the liquid/solid interface measured with a microcantilever***

Author(s): R. Raiteri, H.-J. Butt, M. Grattarola  
Source: Electrochimica Acta, 46 (2000), 2-3 (November 01), 157 - 163

***Atomic force microscopy with a conducting tip : correlation studies between microstructure and electrical properties of YBaCuO thin films***

Author(s): A.F. Degardin, O. Schneegans, F. Houze, E. Caristan, A. De Luca, P. Chretien, L. Boyer, A.J. Kreisler  
Source: Physica C: Superconductivity and its Applications, 341-348 (2000), (November), 1965-1968

***Controlling the natural strong pinning sites in laser ablated YBa<sub>2</sub>Cu<sub>3</sub>O<sub>7-d</sub> thin films***

Author(s): B. Dam, J.M. Huijbregtse, R.C.F. Van der Geest, F.C. Klaassen, J.H. Rector, R. Elberse, R. Griessen  
Source: Physica C: Superconductivity and its Applications, 341-348 (2000), (November), 2327-2330

***Structure and activity of lipid membrane biosensor surfaces studied with atomic force microscopy and a resonant mirror***

Author(s): M.I. Fisher, T. Tjarnhage  
Source: Biosensors and Bioelectronics, 15 (2000), 9-10 (November), 463 - 471

***Relation between microstructural aspects of AA2024 and its corrosion behaviour investigated using AFM scanning potential technique***

Author(s): P. Campestrini, E.P.M. van Westing, H.W. van Rooijen, J.H.W. de Wit  
Source: Corrosion Science, 42 (2000), 11 (November), 1853-1861

***Evaluation of structural and adhesive properties of nylon 6 and PTFE alignment films by means of atomic force microscopy***

Author(s): G. Padeletti, S. Pergolini, G. Montesperelli, A. D'Alessandro, F. Campoli, P. Maltese  
Source: Applied Physics A: Materials Science & Processing, 71 (2000), 5 (November), 571-576

***Investigations of the corrosion behaviour of nanocrystalline Nd-Fe-B hot pressed magnets***

Author(s): A.M. El-Aziz, A. Kirchner, O. Gutfleisch, A. Gebert, L. Schultz  
Source: Journal of Alloys and Compounds, 311 (2000), 2 (October 26), 299-304

***Structural and optical characterization of InAs nanostructures grown on (001) and high index InP substrates***

Author(s): Y.F. Li, X.L. Ye, F.Q. Liu, B. Xu, D. Ding, W.H. Jiang, Z.Z. Sun, H.Y. Liu, Y.C. Zhang, Z.G. Wang  
Source: Applied Surface Science, 167 (2000), 3-4 (October 23), 191-196

***Scanning tunneling microscopy of plasma-solid surface interface***

Author(s): H. Kawasaki, K. Ara, K. Terashima  
Source: Thin Solid Films, 374 (2000), 2 (October 17), 162-166

***Characterisation of cubic boron nitride films at different stages of deposition***

Author(s): L. Jiang, A.G. Fitzgerald, M.J. Rose, A. Lousa, S. Gimeno  
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***Phase structures, transition behavior and surface alignment in polymers containing rigid-rod backbones with flexible side chains Part VI Novel band structures in a combined main-chain/side-chain liquid crystalline polyester: From liquid crystal to crystalline states***

Author(s): J. J. Ge, J. Z. Zhang, Wensheng Zhou, C. Y. Li, Shi Jin, B. H. Calhoun, Shy-Yeu Wang, F. W. Harris, S. Z. D. Cheng  
Source: Journal of Materials Science (full set), 35 (2000), 20 (October 15), 5215-5223

***Chiral molecular patterns of self-assembled ion pairs composed of (R,S), (S)-16-methyloctadecanoic acid and 4,4'-bipyridine***

Author(s): Pu Qian, Hiroshi Nanjo, Toshiro Yokoyama, Toshishige M. Suzuki, Kazuaki Akasaka, Hiroshi Orhui  
Source: Chemical Communications, (2000), 20 (October 15), 2021-2022

***The relationship between squaraine dye surface morphology and sensitization behavior on SnS<sub>2</sub> electrodes***

Author(s): N. Takeda, B.A. Parkinson  
Source: Electrochimica Acta, 45 (2000), 28 (October 13), 4559 - 4564

***Investigations of the surface morphology of La<sub>2</sub>CuO<sub>4</sub> MBE-grown thin films before and after electrochemical oxidation***

Author(s): A. Daridon, J. Fompeyrine, J.-P. Locquet, C. Musil, H. Siegenthaler  
Source: Surface Science, 465 (2000), 1-2 (October 10), 149-162

***Formation, geometric and electronic properties of microrelief Au-GaAs interfaces***

Author(s): N.L. Dmitruk, S.V. Mamykin, O.V. Rengevyeh

Source: Applied Surface Science, 166 (2000), 1-4 (October 09), 97-102

***Strain mapping of V-groove InGaAs/GaAs strained quantum wires using cross-sectional Atomic Force Microscopy***

Author(s): F. Lelarge, C. Priester, C. Constantin, A. Rudra, K. Leifer, E. Kapon

Source: Applied Surface Science, 166 (2000), 1-4 (October 09), 290-294

***Effect of adsorption and desorption processes on photoluminescence excitation spectra of porous silicon***

Author(s): N.E. Korsunskaya, E.B. Kaganovich, L.Y. Khomenkova, B.M. Bulakh, B.R. Dzhumaev, G.V. Beketov, E.G. Manoilov

Source: Applied Surface Science, 166 (2000), 1-4 (October 09), 349-353

***Diffusion of Ga on the GaAs (113) surface in the [110] direction during MOVPE growth***

Author(s): M. Pristovsek, H. Menhal, J.-T. Zettler, W. Richter

Source: Applied Surface Science, 166 (2000), 1-4 (October 09), 433-436

***A new approach to SiO<sub>2</sub> deposit using a N<sub>2</sub>-SiH<sub>4</sub>-N<sub>2</sub>O glow dielectric barrier-controlled discharge at atmospheric pressure***

Author(s): Nicolas Gherardi, Steve Martin, Françoise Massines

Source: Journal of Physics D: Applied Physics, 33 (2000), 19 (October 07), L104-L108

***Preparation of (Ba<sub>0.5</sub>Sr<sub>0.5</sub>)TiO<sub>3</sub> thin films by sol-gel method with rapid thermal annealing***

Author(s): D. Wu, A. Li, H. Ling, X. Yin, C. Ge, M. Wang, N. Ming

Source: Applied Surface Science, 165 (2000), 4 (October 02), 309-314

***High dielectric constant of SrTiO<sub>3</sub> thin films prepared by chemical process***

Author(s): F. M. Pontes, E. J. H. Lee, E. R. Leite, E. Longo, J. A. Varela

Source: Journal of Materials Science (full set), 35 (2000), 19 (October 01), 4783-4787

***Two-dimensional ordering of self-assembled InAs quantum dots grown on (311)B InP substrate***

Author(s): Y.F. Li, F.Q. Liu, B. Xu, X.L. Ye, D. Ding, Z.Z. Sun, W.H. Jiang, H.Y. Liu, Y.C. Zhang, Z.G. Wang

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Author(s): L.S. Pinheiro, M.L.A. Temperini

Source: Surface Science, 464 (2000), 2-3 (October 01), 176-182

***MOVPE growth of GaAsN: surface study by AFM and optical properties***

Author(s): L. Auvray, H. Dumont, J. Dazord, Y. Monteil, J. Bouix, C. Bru-Chevallier, L. Grenouillet

Source: Materials Science in Semiconductor Processing, 3 (2000), 5-6 (October 01), 505-509

***Cation sensing by patterned self-assembled monolayers on gold***

Author(s): Simon Flink, Holger Schonherr, G. Julius Vancso, Frank A.J. Geurts, Kees G.C. van Leerdam, Frank C.J.M. van Veggel, David N. Reinhoudt

Source: Journal of the Chemical Society, Perkin Transactions 2 (Physical Organic Chemistry), 000 (2000), 010 (October 01), 2141-2146

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Author(s): H. Simburger, W. Kern, K. Hummel, C. Hagg

Source: Polymer, 41 (2000), 22 (October), 7883-7897

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Author(s): A. Podesta, T. Toccoli, P. Milani, A. Boschetti, S. Innotta

Source: Surface Science, 464 (2000), 1 (September 20), L673-L680

***Adlayer structures of CO adsorbed on Ru(0001) electrode studied by in-situ STM combined with IRAS***

Author(s): N. Ikemiya, T. Senna, M. Ito

Source: Surface Science, 464 (2000), 1 (September 20), L681-L685

***Fracture of a fatty acid multilayer film***

Author(s): D.S. Martin, P. Weightman

Source: Surface Science, 464 (2000), 1 (September 20), 23-33

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Author(s): K. Ueda, H. Saeki, H. Tabata, T. Kawai

Source: Solid State Communications, 116 (2000), 4 (September 15), 221-224

***Effects of the methane content on the characteristics of diamond-like carbon films produced by sputtering***

Author(s): R.D. Mansano, M. Massi, L.S. Zambom, P. Verdonck, P.M. Nogueira, H.S. Maciel, C. Otani

Source: Thin Solid Films, 373 (2000), 1-2 (September 03), 243-246

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Author(s): G. Kaupp, J. Schmeyers, J. Boy

Source: Tetrahedron, 56 (2000), 36 (September 01), 6899-6911

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Author(s): L. Rolland, C. Vallee, M.-C. Peignon, C. Cardinaud

Source: Applied Surface Science, 164 (2000), 1-4 (September 01), 147-155

***Formation of thin TiN<sub>x</sub>O<sub>y</sub> films by using a hollow cathode reactive DC sputtering system***

Author(s): M.H. Kazemeini, A.A. Berezin, N. Fukuhara

Source: Thin Solid Films, 372 (2000), 1-2 (September 01), 70-77

***Influence of the mesa size on Ge island electroluminescence properties***

Author(s): O. Chr?tien, T. Stoica, D. Dentel, E. Mateeva, L. Vescan

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Author(s): Michael Thompson, Rozalia Nisman, Gordon L. Hayward, Hayat Sindi, Adrian C. Stevenson, Christopher R. Lowe

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***Crystallization of SiO<sub>2</sub>-TiO<sub>2</sub> glassy films studied by atomic force microscopy***

Author(s): A. Karthikeyan, R.M. Almeida

Source: Journal of Non-Crystalline Solids, 274 (2000), 1-3 (September), 169-174

***Kelvin probe microscopy measurements of surface potential change under wear at low loads***

Author(s): B. Bhushan, A.V. Goldade

Source: Wear, 244 (2000), 1-2 (August 20), 104-117

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Author(s): J.M. Brenan, D.J. Cherniak, L.A. Rose

Source: Earth and Planetary Science Letters, 180 (2000), 3-4 (August 15), 399-413

***Preparation and properties of ferroelectric BaTiO<sub>3</sub> thin films produced by the polymeric precursor method***

Author(s): E. J. H. Lee, F. M. Pontes, E. R. Leite, E. Longo, J. A. Varela, E. B. Araujo, J. A. Eiras

Source: Journal of Materials Science Letters, 19 (2000), 16 (August 15), 1457-1459

***Preparation and properties of ferroelectric BaTiO<sub>3</sub> thin films produced by the polymeric precursor method***

Author(s): E. J. H. Lee, F. M. Pontes, E. R. Leite, E. Longo, J. A. Varela, E. B. Araujo, J. A. Eiras

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***Dynamic phenomena and catalytic reactivities of oxide surfaces***

Author(s): E.M. Gaigneaux, H.M. Abdel Dayem, E. Godard, P. Ruiz

Source: Applied Catalysis A: General, 202 (2000), 2 (August 14), 265-283

***Photoluminescence at 1.54 μm in sol-gel-derived, Er-doped BaTiO<sub>3</sub> films***

Author(s): H.X. Zhang, C.H. Kam, Y. Zhou, X.Q. Han, Q. Xiang, S. Buddhudu, Y.L. Lam, Y.C. Chan

Source: Journal of Alloys and Compounds, 308 (2000), 1-2 (August 10), 134-138

***Enhanced growth rate in atomic layer epitaxy deposition of magnesium oxide thin films***

Author(s): Matti Putkonen, Timo Sajavaara, Lauri Niinisto

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***Synthesis of high-silica ZSM-5 in microgravity***

Author(s): J. Warzywoda, N. Bac, G.A. Rossetti, N. van der Puil, J.C. Jansen, H.v. Bekkum, A. Sacco  
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***A chemical and morphological study of fullerene derivatives Langmuir-Blodgett films***

Author(s): L. Giovanelli, G. Le Lay  
Source: Applied Surface Science, 162-163 (2000), (August 01), 513-518

***Influence of the substrate on the self-assemblies of silver sulfide nanocrystals***

Author(s): L. Motte, E. Lacaze, M. Maillard, M.P. Pileni  
Source: Applied Surface Science, 162-163 (2000), (August 01), 604-612

***A novel STM-based depth profiling technique for the electronic characterisation of thin film materials***

Author(s): Y. Fan, A.G. Fitzgerald, J.A. Cairns, P. John, C.E. Troupe, J.I.B. Wilson  
Source: Applied Surface Science, 162-163 (2000), (August 01), 630-637

***The study of the attachment of a single-walled carbon nanotube to a self-assembled monolayer using X-ray photoelectron spectroscopy***

Author(s): X. Yu, T. Mu, H. Huang, Z. Liu, N. Wu  
Source: Surface Science, 461 (2000), 1-3 (August 01), 199-207

***Characterization of laterally structured Pb/Ge multilayers***

Author(s): M.J. Van Bael, V.V. Moshchalkov, Y. Bruynseraede, K. Temst  
Source: Thin Solid Films, 371 (2000), 1-2 (August 01), 80-85

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Author(s): C.M. Pina, M. Enders, A. Putnis  
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Author(s): E.A.T. Dirani, A.M. Andrade, L.K. Noda, F.J. Fonseca, P.S. Santos  
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Author(s): R. Prioli, C.R. Ponciano, F.L. Freire Jr.  
Source: Applied Physics A: Materials Science & Processing, 71 (2000), 2 (August), 233-236

***In-situ electrochemical atomic force microscopy studies of aqueous corrosion and inhibition of copper***

Author(s): G. Bertrand, E. Rocca, C. Savall, C. Rapin, J.-C. Labrune, P. Steinmetz  
Source: Journal of Electroanalytical Chemistry, 489 (2000), 1-2 (July 28), 38 - 45

***Effect of solution pH on the structure of a 4-mercaptopyridine monolayer self-assembled on Au(111)***

Author(s): L.-J. Wan, H. Noda, Y. Hara, M. Osawa  
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***Towards mapping of functional group distributions in functional polymers by AFM force titration measurements***

Author(s): Holger Schonherr, Menno T. van Os, G. Julius Vancso, Renate Forch, Wolfgang Knoll, Zdenek Hruska, Jamal Kurdi, Farzaneh Arefi-Khonsari  
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***Nano-size stripes of self-assembled bolaform amphiphiles***

Author(s): Song Gao, Bo Zou, Lifeng Chi, Junqi Sun, Xi Zhang, Jiacong Shen, Harald Fuchs  
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***Optical properties of Er<sup>3+</sup>-doped SiO<sub>2</sub>-GeO<sub>2</sub>-Al<sub>2</sub>O<sub>3</sub> planar waveguide fabricated by sol-gel processes***

Author(s): Q. Xiang, Y. Zhou, B.S. Ooi, Y.L. Lam, Y.C. Chan, C.H. Kam  
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Author(s): J.N. Barisci, G.G. Wallace, R.H. Baughman  
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Author(s): E. Fujiwara, S. Irie, T. Nemoto, S. Isoda, T. Kobayashi  
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Author(s): Z.Q. Wei, C. Wang, C.F. Zhu, C.Q. Zhou, B. Xu, C.L. Bai  
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***Surface segregation and interdiffusion of Ge on Si(001) studied by medium-energy ion scattering***

Author(s): K. Sumitomo, K. Shiraishi, Y. Kobayashi, T. Ito, T. Ogino  
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***Correlation between surface forces and surface reactivity in the setting of plaster by atomic force microscopy***

Author(s): E. Finot, E. Lesniewska, J.-P. Goudonnet, J.C. Mutin  
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***Atomic force and magnetic force microscopies applied to duplex stainless steels***

Author(s): A. Dias, M.S. Andrade  
Source: Applied Surface Science, 161 (2000), 1-2 (July 01), 109-114

***Self-affine nature of thin film surface***

Author(s): J.M. Li, L. Lu, Y. Su, M.O. Lai  
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***Energy barrier for the growth transition step-flow/step-bunching during epitaxy of InP/InP***

Author(s): H. Dumont, Y. Monteil, J. Bouix  
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***The rational design, synthesis and demonstration of the recognition and binding of a diaza-dioxa-12-crown-4 diphosphonate macrocycle to all crystal growth faces of barium sulfate***

Author(s): Dirk Bosbach, Peter V. Coveney, Jonathan L.W. Griffin, Andrew Putnis, Peter Risthaus, Stephen Stackhouse, Andrew Whiting  
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Author(s): M. Noda, Y. Adachi, H. Sugiyama, T. Nakaiso, M. Okuyama  
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Author(s): X.W. Liu, C.H. Lin, L.T. Chao, H.C. Shih  
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Author(s): H.H. Teng, P.M. Dove, J.J. De Yoreo  
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***Conductive and transparent ZnO:Al thin films obtained by chemical spray***

Author(s): M. de la L. Olvera, A. Maldonado, R. Asomoza, R. Castanedo-Perez, G. Torres-Delgado, J. Canetas-Ortega  
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Author(s): R. Hiesgen, M. Krause, D. Meissner  
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***In situ STM study of the initial stages of oxidation of Cu(111) in aqueous solution***

Author(s): V. Maurice, H.-H. Strehblow, P. Marcus  
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***XPS, LEED and STM study of thin oxide films formed on Cr(110)***

Author(s): V. Maurice, S. Cadot, P. Marcus  
Source: Surface Science, 458 (2000), 1-3 (June 20), 195-215

***Atomic Force Microscopy Studies of SnO<sub>2</sub> Thin Film Microstructures Deposited by Atomic Layer Epitaxy***

Author(s): Mikko Utriainen, Hanna Lattu, Heli Viirola, Lauri Niinisto, Roland Resch, Gernot Friedbacher  
Source: Mikrochimica Acta, 133 (2000), 1-4 (June 19), 119-123

***Investigations of the Growth of Self-Assembled Octadecylsiloxane Monolayers with Atomic Force Microscopy***

Author(s): Thomas Leitner, Gernot Friedbacher, Thomas Vallant, Helmuth Brunner, Ulrich Mayer, Helmuth Hoffmann  
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Author(s): Z.X. Xie, X. Xu, J. Tang, B.W. Mao  
Source: Chemical Physics Letters, 323 (2000), 3-4 (June 16), 209-216

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Author(s): D.R. Giese, F.J. Lamelas, H.A. Owen, R. Plass, M. Gajdardziska-Josifovska  
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Author(s): H. Maki, N. Ichinose, N. Ohashi, H. Haneda, J. Tanaka  
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Author(s): T. Sawaguchi, F. Mizutani, S. Yoshimoto, I. Taniguchi  
Source: Electrochimica Acta, 45 (2000), 18 (June 09), 2861 - 2867

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Author(s): Y. Hirata, F. Mizutani, H. Yokoyama  
Source: Electrochimica Acta, 45 (2000), 18 (June 09), 2953 - 2959

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Author(s): Matthew L. Fielden, Robert A. Hayes, John Ralston  
Source: PCCP: Physical Chemistry Chemical Physics, 002 (2000), 011 (June 07), 2623-2628

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Author(s): R. A. Andrievski, G. V. Kalinnikov, J. Jauberteau, J. Bates  
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Author(s): R.I. Viitala, M. Langlet, J. Simola, M. Linden, J.B. Rosenholm  
Source: Thin Solid Films, 368 (2000), 1 (June 01), 35-40

***Deposition and structural characterization of high quality textured C<sub>60</sub> thin films***

Author(s): E.A. Katz, D. Faiman, S. Shtutina, A. Isakina  
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Author(s): H. Liu, S. Fujisawa, A. Tanaka, Y. Enomoto  
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Author(s): V. Vignal, J.C. Roux, S. Flandrois, A. Fevrier  
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Author(s): A. Ramesh, J.A. Kozinski

Source: Combustion and Flame, 121 (2000), 4 (June), 695-698

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Author(s): R. Seebock, H. Esrom, M. Charbonnier, M. Romand

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Author(s): J. Zak, M. Kolodziej-Sadlok

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Author(s): M. Wadsak, M. Schreiner, T. Aastrup, C. Leygraf

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***Atomic force microscopy study on the anatase crystallization of long term stored Al<sub>2</sub>O<sub>3</sub>-TiO<sub>2</sub>-SiO<sub>2</sub> coatings on glass***

Author(s): Yongjuan Du, G. H. Frischat

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***Origin of the multiple voltammetric desorption waves of long-chain alkanethiolate monolayers chemisorbed on annealed gold electrodes***

Author(s): S.-S. Wong, M.D. Porter

Source: Journal of Electroanalytical Chemistry, 485 (2000), 2 (May 12), 135 - 143

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Author(s): R. Singh, S.B. Samanta, A.V. Narlikar, G.C. Trigunayat

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Author(s): C.H. Shi, X.W. Cai, Y.A. Chen, Y.X. Chen, Z.Q. Tian, B.W. Mao

Source: Applied Surface Science, 158 (2000), 1-2 (May 01), 11-15

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Author(s): G. Gladyszewski, K. Temst, K. Mae, R. Schad, F. Belien, E. Kunnen, G. Verbanck, Y. Bruynseraede, R. Moons, A. Vantomme, S. Blasser, G. Langouche

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***Low temperature synthesis and electrical properties of PbTiO<sub>3</sub> thin films prepared by the polymeric precursor method***

Author(s): F.M. Pontes, J.H.G. Rangel, E.R. Leite, E. Longo, J.A. Varela, E.B. Araujo, J.A. Eiras

Source: Thin Solid Films, 366 (2000), 1-2 (May 01), 232-236

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Author(s): S. Zou, X. Gao, M.J. Weaver

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Author(s): R. Vidu, S. Hara

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Author(s): K. Azumi, M. Seo, N. Yasui

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***Characterization and tribological evaluation of duplex treatment by depositing carbon nitride films on plasma nitrified Ti-6Al-4V***

Author(s): Yongqing Fu, Jun Wei, Bibo Yan, Nee Lam Loh

Source: Journal of Materials Science (full set), 35 (2000), 9 (May 01), 2215-2227

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Author(s): Herbert H.P. Fang, Li-Chong Xu, Kwong-Yu Chan  
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Author(s): M. Dundar, O.T. Inal, J. Stringer  
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Author(s): D.K. Sarkar, S. Dhara, A. Gupta, K.G.M. Nair, S. Chaudhury  
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Author(s): M.J. Van Bael, L. Van Look, K. Temst, M. Lange, J. Bekaert, U. May, G. Guntherodt, V.V. Moshchalkov, Y. Bruynseraede  
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Author(s): Carine Ponticaud, Annie Guillou, Pierre Lefort  
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Author(s): L.-J. Wan, T. Suzuki, K. Sashikata, J. Okada, J. Inukai, K. Itaya  
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Author(s): D.S. Martin, P. Weightman  
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Author(s): J. Rodriguez, M. Gomez, J. Ederth, G.A. Niklasson, C.G. Granqvist  
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Author(s): I.Y. Sokolov, G.S. Henderson  
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Author(s): A. Nakasa, U. Akiba, M. Fujihira  
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Author(s): B. Bhushan, A.V. Goldade  
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Author(s): J.W. Elam, C.E. Nelson, M.A. Tolbert, S.M. George  
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Author(s): C.H. Marrows, B.J. Hickey, E.W. Hill, I. Zoller, F.E. Stanley  
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Author(s): V.M. Ayres, T.R. Bieler, M.G. Kanatzidis, J. Spano, S. Hagopian, H. Balhareth, B.F. Wright, M. Farhan, J. Abdul Majeed, D. Spach, B.L. Wright, J. Asmussen  
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Author(s): D.C. Reigada, R. Prioli, L.G. Jacobsohn, F.L. Freire  
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Author(s): L.G. Jacobsohn, R. Prioli, F.L. Freire, G. Mariotto, M.M. Lacerda, Y.W. Chung  
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Author(s): G.L. Bertrand, G. Caboche, L.-C. Dufour  
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Author(s): M. Moseler, O. Rattunde, J. Nordiek, H. Haberland  
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Author(s): M. Gadenne, P. Gadenne, O. Schneegans, F. Houze, P. Chretien, C. Desmarest, J. Sztern  
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Author(s): L. Roue, M.-E. Bonneau, D. Guay, M. Blouin, R. Schulz  
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Author(s): F. Czerwinski, J. A. Szpunar, U. Erb  
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Author(s): J. Hong, A. Gouillet, G. Turban  
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Author(s): R.J. Nichols, J.H. Ye, S.F.Y. Li, W.H. Li  
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Author(s): Jie-Bin Pang, Kun-Yuan Qiu, Yen Wei, Xiao-Jun Lei, Zhong-Fan Liu  
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Author(s): J. Cousty, C. Mioskowski, C. Le Poulennec, Z.X. Xie  
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Author(s): T. Ehara, H. Kobayashi, M. Kotani, H. Hirose  
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Author(s): John W. Connell

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Author(s): H. Klein, W. Blanc, R. Pierrisnard, C. Fauquet, Ph. Dumas

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Author(s): Cheng-Chung Lee, Jin-Cherng Hsu, Daw-Heng Wong

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Author(s): S. Yoshida, T. Ide, H. Okumura, G. Ferro

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Author(s): T. Fujimoto, N. Ohtani, M. Katsuno, H. Yashiro, M. Kanaya, H. Tsuge, T. Aigo

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Author(s): H. Nakagawa, M. Umeno, M. Tagawa, N. Ohmae, S. Kibi

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Author(s): M. Wadsak, M. Schreiner, T. Aastrup, C. Leygraf

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Author(s): K. Arstila, J. Keinonen, T. Sajavaara, A. Laakso

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Author(s): C. Sommerhalter, M.C. Lux-Steiner, A. Jager-Waldau, A. Rumberg, M. Toplak

Source: Thin Solid Films, 361-362 (2000), 1 (February 21), 172-176

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Author(s): J.W. Klaus, S.M. George

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Author(s): M. Rabisch, R. Hiesgen, D. Meissner, H. Bottcher

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Author(s): S. Xu, S. Kumar, Y.A. Li, N. Jiang, S. Lee

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Author(s): K. Sangwal, P. Gorostiza, F. Sanz

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Author(s): S.-Z. Yang, J. Jagielski, T. Vilaithong, A. Zalar, A.S. Khanna, J. Kucinski, D.S. Mishra, P. Racolta, P. Sioshansi, E. Tobin, J. Thereska, V. Uglov, J. Viviente

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Author(s): G. Friedbacher, L. Niinisto, T. Tenno, K. Tammeveski, J. Niinisto, T. Leitner

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Author(s): J. Lin, K. Barner, D.U. Sanger, M. Mennig

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Author(s): J.W. Klaus, S.M. George, S.J. Ferro

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Author(s): X. Wang, P. Sandstrom, S. Olafsson, U. Helmersson

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Author(s): M.J. Weaver, S. Zou

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Author(s): M. Mehmood, E. Akiyama, A. Kawashima, K. Asami, K. Hashimoto, H. Habazaki

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Author(s): A. L. Volynskii, S. Bazhenov, O. V. Lebedeva, N. F. Bakeev

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Author(s): B. Wolf, M. Swain, M. Kempf, P. Paufler

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Author(s): J. B. Campbell, J. Lankford

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Author(s): Rafael Diaz, Ma. Fernanda Lazo

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Author(s): L.X. Ye, B.-M. Chen, H.-P.D. Shieh, J.C. Wu, Y.W. Huang, T.-H.T.-H. Wu

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Author(s): C.-R. Chang, H.-N.H.-N. Lin, Y.-H. Chiou

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Author(s): M.L. Occelli, J.A. Bertrand, S.A.C. Gould, J.M. Dominguez

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Author(s): G.A. Niklasson, H. Nilsson, L. Kullman, M. Stromme Mattsson, D. Ronnow, A. Roos

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Author(s): G.K. Mor, L.K. Malhotra

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Author(s): G.K. Zhavnerko, V.E. Agabekov, V.N. Staroverov, M.O. Gallyamov, I.V. Yaminsky

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Author(s): W. Que, Y. Zhou, Y.L. Lam, C.H. Kam, Y.C. Chan  
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Author(s): K.Y. Simon Ng, H. Li, G. Mao  
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Author(s): M. Shojiya, A. Konishi, Y. Kawamoto, H. Wakabayashi  
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Author(s): R. Hiesgen, H. Ringsdorf, S. Kumar, D. Meissner, H. Schonherr  
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Author(s): David I. Gittins, Donald Bethell, Richard J. Nichols, David J. Schiffrin  
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Author(s): Shueh-Lin Yau, Takahiro Moriyama, Hiroyuki Uchida, Masahiro Watanabe  
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Author(s): H. Maruta, S. Hayakawa, R. Matsuo, H. Fujioka, M. Oshima, T. Ikeda, M. Yoshimoto, H. Koinuma, K. Inaba, K. Ono  
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Author(s): A. Mauri, M. Moret  
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Author(s): X.-Y.X.-Y. Liu, D.-W. Li, C.S. Strom, N.-b. Ming, M. Wang  
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Author(s): E. Rudnik, L. Burzynska  
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Author(s): N. Batina, M. Morales, I. Gonzalez, E. Sosa, G. Carreno, C. Ponce-de-Leon, M.T. Oropeza  
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Author(s): S. Fendorf, B.C. Bostick, M. Fendorf  
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Author(s): S. Hara, Y. Nakayama, Y. Yamaguchi, N. Hirai, M. Shiota  
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Author(s): Stephen J. Sowerby, Peter A. Stockwell, Wolfgang M. Heckl, George B. Petersen  
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Author(s): N. Vukadinovic, H. Le Gall, J. Ben Youssef V. Gehanno, A. Marty, Y. Samson, B. Gilles  
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Author(s): D.H. Chen, A.X. Wei, S.P. Wong, J.B. Xu, M.M. Wu, S.Q. Peng  
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Author(s): Ryoji Shiraki, Peter A. Rock, William H. Casey  
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Author(s): Y. Gao, S. Thevuthasan, D.E. McCready, M. Engelhard  
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Author(s): J.I. Paredes, A. Martinez-Alonso, J.M.D. Tascon  
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Author(s): C.L. Li, O. Novaro, X. Bokhimi, E. Munoz, J.L. Boldu, J.A. Wang, T. Lopez, R. Gomez, N. Batina  
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Author(s): Eleni Dokou, Eric E. Stangland, Ronald P. Andres, W. Nicholas Delgass, Mark A. Barteau  
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Author(s): E.E. Wolf  
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Author(s): Anders Meurk  
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Author(s): F.J. Doucet, M.E. Rotov, C. Exley  
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Author(s): A. Taj, P.V. Ashrit  
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Author(s): S.D. Sartale, C.D. Lokhande, M. Giersig, V. Ganesan  
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***Excitonic properties of the polar faces of bulk ZnO after wet etching***

Author(s): J. Fryar, E. McGlynn, M.O. Henry, A.A. Cafolla, C.J. Hanson  
Source: *Physica B: Condensed Matter*, 340-342 (2003), (December 31), 210-215

***Investigations on the monolayer structure of thiol SAMs and the influence of conjugated p-bonds on the electronic molecular conductivity***

Author(s): N. Krings, H.-H. Strehblow, J. Kohnert, H.-D. Martin  
Source: *Electrochimica Acta*, 49 (2003), 1 (December 30), 167-174

***Preparation, structural and optical characterization of BaWO<sub>4</sub> and PbWO<sub>4</sub> thin films prepared by a chemical route***

Author(s): F.M. Pontes, M.A.M.A. Maurera, A.G. Souza, E. Longo, E.R. Leite, R. Magnani, M.A.C. Machado, P.S. Pizani, J.A. Varela

Source: Journal of the European Ceramic Society, 23 (2003), 16 (December), 3001-3007

***Photoinduced structural changes in antimony polyphosphate based glasses***

Author(s): F.S. De Vicente, M. Siu Li, M. Nalin, Y. Messaddeq

Source: Journal of Non-Crystalline Solids, 330 (2003), 1-3 (November 15), 168-173

***Sol-Gel Derived Titania/?-Glycidoxypropyltrimethoxysilane and Methyltrimethoxysilane Hybrid Materials for Optical Waveguides***

Author(s): Wenxiu Que, X. Hu

Source: Journal of Sol-Gel Science and Technology, 28 (2003), 3 (November), 319-325

***Photonic bandgap materials and structures by sol-gel processing***

Author(s): R.M. Almeida, A.S. Rodrigues

Source: Journal of Non-Crystalline Solids, 326-327 (2003), (October 01), 405-409

***To what extent is the structure of a random composite compatible with a percolation model?***

Author(s): F. Carmona, J. Ravier

Source: Physica B: Condensed Matter, 338 (2003), 1-4 (October), 247-251

***Microstructured metallization of insulating polymers***

Author(s): T.T. Mai, J.W. Schultze, G. Staikov

Source: Electrochimica Acta, 48 (2003), 20-22 (September 30), 3021 - 3027

***Structural, morphological and acoustic properties of AlN thick films sputtered on Si(001) and Si(111) substrates at low temperature***

Author(s): C. Caliendo, P. Imperatori, E. Cianci

Source: Thin Solid Films, 441 (2003), 1-2 (September 22), 32-37

***Fabrication of silica-anatase multilayer coating on a K-Ca-Zn-Si glass substrate***

Author(s): H. Okudera, T. Nonami

Source: Thin Solid Films, 441 (2003), 1-2 (September 22), 50-55

***The optimization of Ta buffer layer in magnetron sputtering IrMn top spinvalve***

Author(s): H.-R. Liu, T.-L. Ren, B.-J. Qu, L.-T. Liu, W.-J. Ku, W. Li

Source: Thin Solid Films, 441 (2003), 1-2 (September 22), 111-114

***Evaluation of HfO<sub>2</sub> film structures deposited by metal-organic chemical vapor deposition using Hf(N(C<sub>2</sub>H<sub>5</sub>)<sub>2</sub>)<sub>4</sub>/O<sub>2</sub> gas system***

Author(s): A. Ogura, K. Ito, Y. Ohshita, M. Ishikawa, H. Machida

Source: Thin Solid Films, 441 (2003), 1-2 (September 22), 161-164

***The design of ZnS/Ag/ZnS transparent conductive multilayer films***

Author(s): X. Liu, X. Cai, J. Qiao, J. Mao, N. Jiang

Source: Thin Solid Films, 441 (2003), 1-2 (September 22), 200-206

***Electrochemical and surface characterization of platinum silicide electrodes and their use as stable platforms for electrogenerated chemiluminescence assays***

Author(s): E.F. Fabrizio, T.M. McEvoy, P. Jassel, J. Lozano, K.J. Stevenson, A.J. Bard

Source: Journal of Electroanalytical Chemistry, 554-555 (2003), (September 15), 99 - 111

***Magnetization reversal in elliptical-ring nanomagnets***

Author(s): F.J. Castano, C.A. Ross, A. Eilez

Source: Journal of Physics D: Applied Physics, 36 (2003), 17 (September 07), 2031-2035

***Surface modification and characterization of photodefinable epoxy/copper systems***

Author(s): J. Ge, M.P.K. Turunen, J.K. Kivilahti

Source: Thin Solid Films, 440 (2003), 1-2 (September 01), 198-207

***Novel barium strontium titanate  $Ba_{0.5}Sr_{0.5}TiO_3/MgO$  thin film composites for tunable microwave devices***

Author(s): M. Jain, S.B. Majumder, R.S. Katiyar, A.S. Bhalla

Source: Materials Letters, 57 (2003), 26-27 (September), 4232-4236

***Influences of reactor pressure of GaN buffer layers on morphological evolution of GaN grown by MOCVD***

Author(s): J. Chen, S.M. Zhang, B.S. Zhang, J.J. Zhu, X.M. Shen, G. Feng, J.P. Liu, Y.T. Wang, H. Yang, W.C. Zheng

Source: Journal of Crystal Growth, 256 (2003), 3-4 (September), 248-253

***Consistency between morphology and magnetization data in studying the effect of production parameters in  $Nd_{90-x}Fe_xAl_{10}$  ( $x=35-50$ ) melt spun ribbons***

Author(s): G. Ausanio, H. Chiriac, V. Iannotti, C. Hison, L. Lanotte, N. Lupu

Source: Journal of Magnetism and Magnetic Materials, 265 (2003), 2 (September), 138-141

***Electrooxidation of 2-chlorophenol on polyNiTSPc-modified glassy carbon electrodes***

Author(s): M.S. Ureta-Zanartu, C. Berrios, J. Pavez, J. Zagal, C. Gutierrez, J.F. Marco

Source: Journal of Electroanalytical Chemistry, 553 (2003), (August 30), 147 - 156

***Layer-by-layer self-assembly replication technique: application to photoelectrode of dye-sensitized solar cell***

Author(s): S. Takenaka, Y. Maehara, H. Imai, M. Yoshikawa, S. Shiratori

Source: Thin Solid Films, 438-439 (2003), (August 22), 346-351

***Dispersion strengthened and highly cube textured Ni alloy tapes as possible substrates for coated conductors***

Author(s): V.S. Sarma, B. de Boer, J. Eickemeyer, B. Holzapfel

Source: Acta Materialia, 51 (2003), 13 (August 01), 3769-3777

***Phase contrast imaging of nanocomposites and molecularly thick lubricant films in magnetic media***

Author(s): Bharat Bhushan, Jun Qi

Source: Nanotechnology, 14 (2003), 8 (August 01), 886-895

***Characterization of zinc phthalocyanine (ZnPc) for photovoltaic applications***

Author(s): S. Senthilarasu, S. Velumani, R. Sathyamoorthy, A. Subbarayan, J.A. Ascencio, G. Canizal, P.J. Sebastian, J.A. Chavez, R. Perez

Source: Applied Physics A: Materials Science & Processing, 77 (2003), 3-4 (August), 383-389

***Growth of beryllium nitride films by pulsed laser deposition; dielectric function determination***

Author(s): G. Soto, R. Machorro, J.A. Daz, W. de la Cruz, A. Reyes

Source: Thin Solid Films, 434 (2003), 1-2 (June 23), 7-13

***Molecular rectification: asymmetric current-voltage curves from self-assembled monolayers of a donor-(p-bridge)-acceptor dye***

Author(s): Geoffrey J. Ashwell, Richard Hamilton, L.R. Hermann High

Source: Journal of Materials Chemistry, 13 (2003), 7 (June 20), 1501-1503

***Crystal structure of polycrystalline films of quaterthiophene grown by organic molecular beam deposition***

Author(s): A. Sassella, D. Besana, A. Borghesi, M. Campione, S. Tavazzi, B. Lotz, A. Thierry

Source: Synthetic Metals, 138 (2003), 1-2 (June 02), 125-130

***Stable multilayer ultrathin film containing covalently attached colloidal Ag nanoparticles***

Author(s): Conghua Lu, Shuo Bai, Dongbai Zhang, Lan Huang, Jiming Ma, Chuanqiou Luo, Weixiao Cao

Source: Nanotechnology, 14 (2003), 6 (June 01), 680-683

***Grain refinement in electrogalvanized coatings***

Author(s): N.M. Martyak

Source: Materials Characterization, 50 (2003), 4-5 (June), 269-274

***In situ STM study of the effect of chlorides on the initial stages of anodic oxidation of Cu(111) in alkaline solutions***

Author(s): J. Kunze, V. Maurice, L.H. Klein, H.-H. Strehblow, P. Marcus

Source: Electrochimica Acta, 48 (2003), 9 (April 20), 1157 - 1167

***STM tip-induced local electrochemical dissolution of silver***

Author(s): S.G. Garca, D.R. Salinas, C.E. Mayer, W.J. Lorenz, G. Staikov

Source: *Electrochimica Acta*, 48 (2003), 9 (April 20), 1279 - 1285

***Atomic force microscope observations of domains in fine-grained bulk lead zirconate titanate ceramics***

Author(s): Zuoyi Wang, John E. Blendell, Grady S. White, Qing Jiang  
Source: *Smart Materials and Structures*, 12 (2003), 2 (April 01), 217-222

***Surface roughness and resistivity of Au film on Si-(111) substrate***

Author(s): W. Tang, K. Xu, P. Wang, X. Li  
Source: *Microelectronic Engineering*, 66 (2003), 1-4 (April), 445-450

***Comparison study on sol-gel  $Pb(Zr_{0.3}Ti_{0.7})O_3$  and  $Pb(Zr_{0.3}Ti_{0.7})O_3/PbTiO_3$  multilayer thin films for pyroelectric infrared detectors***

Author(s): L.L. Sun, O.K. Tan, W.G. Liu, X.F. Chen, W. Zhu  
Source: *Microelectronic Engineering*, 66 (2003), 1-4 (April), 738-744

***Fabrication and fluorescence properties of perylene bisimide dye aggregates bound to gold surfaces and nanopatterns***

Author(s): Ulrike Haas, Christoph Thalacker, Jorg Adams, Jurgen Fuhrmann, Silke Riethmuller, Uwe Beginn, Ulrich Ziener, Martin Moller, Rainer Dobrawa, Frank Wurthner  
Source: *Journal of Materials Chemistry*, 13 (2003), 4 (March 19), 767-772

***A robust ultrathin, transparent gold electrode tailored for hole injection into organic light-emitting diodes***

Author(s): Ross A. Hatton, Martin R. Willis, Michael A. Chesters, David Briggs  
Source: *Journal of Materials Chemistry*, 13 (2003), 4 (March 19), 722-726

***PZT films grown by RF sputtering at high oxygen pressure***

Author(s): O. Blanco, J. Heiras, J.M. Siqueiros, E. Martinez, A.G. Castellanos-Guzman  
Source: *Journal of Materials Science Letters*, 22 (2003), 6 (March 15), 449-453

***High resolution surface analysis of Si roughening in dilute ammonium fluoride solution***

Author(s): H.J. Lewerenz, M. Aggour, C. Murrell, J. Jakubowicz, M. Kanis, S.A. Campbell, P.A. Cox, P. Hoffmann, H. Jungblut, D. Schmeiszer  
Source: *Journal of Electroanalytical Chemistry*, 540 (2003), (January 02), 3 - 6

***Epitaxial  $LiNb_{0.5}Ta_{0.5}O_3$  films on  $LiTaO_3$  and  $LiNbO_3$  substrates grown by thermal plasma***

Author(s): S.A. Kulinich, T. Yamaki, S. Bysakh, H. Yamamoto, K. Mitsuishi, M. Song, K. Terashima, K. Furuya  
Source: *Journal of Crystal Growth*, 247 (2003), 3-4 (January), 408-418

***Characterization of epitaxial thin films of  $Bi_2VO_{5.5}$  on La-doped  $SrTiO_3$  substrates prepared by coating-pyrolysis process***

Author(s): K. Tsukada, T. Nagahama, M. Sohma, I. Yamaguchi, T. Manabe, T. Tsuchiya, S. Suzuki, T. Shimizu, S. Mizuta, T. Kumagai  
Source: *Thin Solid Films*, 422 (2002), 1-2 (December 20), 73-79

***Room-temperature deposition of Al-doped ZnO films by oxygen radical-assisted pulsed laser deposition***

Author(s): K. Matsubara, P. Fons, K. Iwata, A. Yamada, S. Niki  
Source: *Thin Solid Films*, 422 (2002), 1-2 (December 20), 176-179

***Influence of partial matrix fluorination on morphology and performance of HPDLC transmission gratings***

Author(s): M. De Sarkar, J. Qi, G.P. Crawford  
Source: *Polymer*, 43 (2002), 26 (December), 7335-7344

***Probing Si and Ti Based Sol-Gel Matrices by Fluorescence Techniques***

Author(s): Graham Hungerford, Mario Rui Pereira, Joao A. Ferreira, Teresa M.R. Viseu, Anabela F. Coelho, M. Isabel, C. Ferreira, Klaus Suhling  
Source: *Journal of Fluorescence*, 12 (2002), 3 (December), 397-417

***Investigation of interfacial microstructures of MBE-grown  $NdF_3/Si(111)$  heterostructures***

Author(s): N.T. Cho, J.M. Ko, K.B. Shim, T. Fukuda  
Source: *Journal of Crystal Growth*, 246 (2002), 1-2 (December), 127-132

***The growth and characterization of epitaxial  $Ba_2NdTaO_6$  dielectric ceramic thin films on (100)  $SrTiO_3$***

Author(s): J. Kurian, Y. Takahashi, T. Amemura, T. Suzuki, T. Morishita

Source: Journal of Physics D: Applied Physics, 35 (2002), 22 (November 21), 3002-3006

***Synthesis and highly ordered thin films of optically active 2'-methoxy-1,1'-binaphthyl substituted phthalocyanines***

Author(s): H. Liu, Y. Liu, C. Zhu, M. Liu, C. Wang, C. Chen, F. Xi  
Source: Synthetic Metals, 131 (2002), 1-3 (November 20), 135-139

***Formation and Structure of Polyelectrolyte and Nanoparticle Multilayers: Effect of Particle Characteristics***

Author(s): Goran Bogdanovic, Therese Sennerfors, Boris Zhmud, Fredrik Tiberg  
Source: Journal of Colloid and Interface Science, 255 (2002), 1 (November 01), 44-51

***Synthesis and characterization of lead strontium titanate thin films by sol-gel technique***

Author(s): M. Jain, S.B. Majumder, R. Guo, A.S. Bhalla, R.S. Katiyar  
Source: Materials Letters, 56 (2002), 5 (November), 692-697

***Investigations on the sol-gel-derived barium zirconium titanate thin films***

Author(s): A. Dixit, S.B. Majumder, A. Savvinov, R.S. Katiyar, R. Guo, A.S. Bhalla  
Source: Materials Letters, 56 (2002), 6 (November), 933-940

***Scanning tunneling microscopy and in situ spectroscopy of ultra thin Ti films and nano sized TiO<sub>x</sub> dots induced by STM***

Author(s): Y. Yin, J. Jiang, Q. Cai, B. Cai  
Source: Applied Surface Science, 199 (2002), 1-4 (October 30), 319-327

***X-Ray scattering study of crystallization behavior in homoepitaxial growth of SrTiO<sub>3</sub> films***

Author(s): H.-Y. Lee, W.-D. Chang, C.-H. Hsu, K.S. Liang, J.Y. Lee, J.Y. Juang, K.H. Wu, T.M. Uen, Y.S. Gou  
Source: Thin Solid Films, 418 (2002), 2 (October 15), 163-168

***Critical thickness for cracking of Pb(Zr<sub>0.53</sub>Ti<sub>0.47</sub>)O<sub>3</sub> thin films deposited on Pt/Ti/Si(100) substrates***

Author(s): M.-H. Zhao, R. Fu, D. Lu, T.-Y. Zhang  
Source: Acta Materialia, 50 (2002), 17 (October 09), 4241-4254

***Production and characterization of zinc oxide thin films for room temperature ozone sensing***

Author(s): M. Bender, E. Gagaoudakis, E. Douloufakis, E. Natsakou, N. Katsarakis, V. Cimalla, G. Kiriakidis, E. Fortunato, P. Nunes, A. Marques, R. Martins  
Source: Thin Solid Films, 418 (2002), 1 (October 01), 45-50

***Study of platinum thin films deposited by MOCVD as electrodes for oxide applications***

Author(s): O. Valet, P. Doppelt, P.K. Baumann, M. Schumacher, E. Balnois, F. Bonnet, H. Guillon  
Source: Microelectronic Engineering, 64 (2002), 1-4 (October), 457-463

***Pulsed laser deposition of ferroelectric Sr<sub>4</sub>Bi<sub>4</sub>Ti<sub>7</sub>O<sub>24</sub> thin films***

Author(s): S.-T. Zhang, B. Yang, X.-J. Zhang, Y.-F. Chen, Z.-G. Liu, N.-B. Ming  
Source: Materials Letters, 56 (2002), 3 (October), 221-225

***Growth morphology of {100} faces of zinc cadmium thiocyanate crystal investigated by atomic force microscopy***

Author(s): X.N. Jiang, D. Xu, D.R. Yuan, D.L. Sun, M.K. Lu, X.Q. Wang, G.H. Zhang  
Source: Journal of Crystal Growth, 244 (2002), 3-4 (October), 281-286

***Growth and characterisation of NdBa<sub>2</sub>Cu<sub>3</sub>O<sub>7-d</sub>/NdBa<sub>2</sub>TaO<sub>6</sub>/NdBa<sub>2</sub>Cu<sub>3</sub>O<sub>7-d</sub> multilayer films on (100) SrTiO<sub>3</sub>***

Author(s): J. Kurian, T. Amemura, T. Suzuki, T. Morishita  
Source: Physica C: Superconductivity and its Applications, 378-381 (2002), (October), 1318-1321

***Preparation of double layer film of boron and carbon by pulsed laser deposition***

Author(s): Y. Suda, Y. Suganuma, Y. Sakai, K. Suzuki, J. Tsujino, N. Homma  
Source: Applied Surface Science, 197-198 (2002), (September 30), 603-606

***Observation of initial deposition process of electroless nickel plating by quartz crystal microbalance method and microscopy***

Author(s): H. Matsubara, T. Yonekawa, Y. Ishino, H. Nishiyama, N. Saito, Y. Inoue  
Source: Electrochimica Acta, 47 (2002), 25 (September 25), 4011 - 4018

***Direct deposition of YBCO on polished Ag substrates by pulsed laser deposition***

Author(s): B. Ma, M. Li, R.E. Koritala, B.L. Fisher, S.E. Dorris, V.A. Maroni, D.J. Miller, U. Balachandran  
Source: *Physica C: Superconductivity and its Applications*, 377 (2002), 4 (September 15), 501-506

***Texture and strain in CoPt/Ag nanocomposite films***

Author(s): V. Karanasos, I. Panagiotopoulos, D. Niarchos  
Source: *Journal of Magnetism and Magnetic Materials*, 249 (2002), 3 (September), 471-474

***Structural and optical properties of ZnO film by plasma-assisted MOCVD***

Author(s): X. Wang, S. Yang, J. Wang, M. Li, X. Jiang, G. Du, X. Liu, R.P.H. Chang  
Source: *Optical and Quantum Electronics*, 34 (2002), 9 (September), 883-891

***Micropatterning of anatase TiO<sub>2</sub> thin films from an aqueous solution by a site-selective immersion method***

Author(s): Yoshitake Masuda, Tsutomu Sugiyama, Kunihiro Koumoto  
Source: *Journal of Materials Chemistry*, 12 (2002), 9 (August 30), 2643-2647

***Hydrothermal deposition and characterization of heteroepitaxial BaTiO<sub>3</sub> films on SrTiO<sub>3</sub> and LaAlO<sub>3</sub> single crystals***

Author(s): E. Ciftci, M.N. Rahaman, F.D. Blum  
Source: *Journal of Materials Science (full set)*, 37 (2002), 16 (August 15), 3361-3367

***The structural transformation of the Pt(110) electrode during the Cu underpotential deposition process***

Author(s): O. Endo, N. Ikemiya, M. Ito  
Source: *Surface Science*, 514 (2002), 1-3 (August 10), 234-240

***The growth and annealing of single crystalline ZnO films by low-pressure MOCVD***

Author(s): J. Ye, S. Gu, S. Zhu, T. Chen, L. Hu, F. Qin, R. Zhang, Y. Shi, Y. Zheng  
Source: *Journal of Crystal Growth*, 243 (2002), 1 (August), 151-156

***Stray-light induced artefacts in absorption spectra of crystalline oligothiophenes***

Author(s): A. Sassella, A. Borghesi, P. Spearman, S. Tavazzi  
Source: *The European Physical Journal B (EPJ B)*, 28 (2002), 4 (August), 385-388

***Atomic Force Microscopic Studies of Porous TiO<sub>2</sub> Thin Films Prepared by the Sol-Gel Method***

Author(s): Jianguo Yu, Jimmy C. Yu, Bei Cheng, Xiujian Zhao, Zhi Zheng, A.S.K. Li  
Source: *Journal of Sol-Gel Science and Technology*, 24 (2002), 3 (July), 229-240

***Low Temperature Sol-Gel Preparation of Nanocrystalline TiO<sub>2</sub> Thin Films***

Author(s): Y. Djaoued, Simona Badilescu, P.V. Ashrit, D. Bersani, P.P. Lottici, R. Bruning  
Source: *Journal of Sol-Gel Science and Technology*, 24 (2002), 3 (July), 247-254

***Formation and structural characteristics of Langmuir-Blodgett films of the endohedral metallofullerene Dy@C<sub>82</sub> mixed with cadmium arachidate***

Author(s): X. Li, S. Yang, S. Yang, Y. Xu, Y. Liu, D. Zhu  
Source: *Thin Solid Films*, 413 (2002), 1-2 (June 24), 231-236

***Photoinduced processes in fulleropyrrolidine and fulleropyrazoline derivatives substituted with an oligophenylenevinylene moiety***

Author(s): N. Armaroli, G. Accorsi, J.-P. Gisselbrecht, M. Gross, V. Krasnikov, D. Tsamouras, G. Hadziioannou, M. J. Gomez-Escalonilla, F. Langa, J.-F. Eckert and J.-F. Nierengarten  
Source: *Journal of Materials Chemistry*, 12 (2002), 7 (June 21), 2077-2087

***Unusual electrocatalytic behavior of ferrocene bound fullerene cluster films***

Author(s): S. Barazzouk, S. Hotchandani and P. V. Kamat  
Source: *Journal of Materials Chemistry*, 12 (2002), 7 (June 21), 2021-2025

***STM observation of the electro-adsorption of lithium ions onto graphite and of the ensuing solid electrolyte interphase formation***

Author(s): L. Zhu, F. Hommet, G. Salace, B. Claude-Montigny, A. Metrot  
Source: *Surface Science*, 512 (2002), 1-2 (June 20), 84-96

***Analysis of nanocrystalline coatings of tin oxides on glass by atomic force microscopy***

Author(s): V. Baranauskas, T.E.A. Santos, M.A. Schreiner, Z. Jingguo, A.P. Mammana, C.I.Z. Mammana  
Source: *Sensors and Actuators B: Chemical*, 85 (2002), 1-2 (June 20), 90-94

***Comparison of the early stages of corrosion of copper and iron investigated by in situ TM-AFM***

Author(s): C. Kleber, J. Weissenrieder, M. Schreiner, C. Leygraf  
Source: Applied Surface Science, 193 (2002), 1-4 (June 05), 245-253

***The growth modes of epitaxial Au/Co/Au sandwiches***

Author(s): A. Wawro, L.T. Baczewski, P. Pankowski, M. Kisielewski, I. Sveklo, A. Maziewski  
Source: Thin Solid Films, 412 (2002), 1-2 (June 03), 34-37

***Ultra-thin passivating film induced by vinylene carbonate on highly oriented pyrolytic graphite negative electrode in lithium-ion cell***

Author(s): O. Matsuoka, A. Hiwara, T. Omi, M. Toriida, T. Hayashi, C. Tanaka, Y. Saito, T. Ishida, H. Tan, S.S. Ono, S. Yamamoto  
Source: Journal of Power Sources, 108 (2002), 1-2 (June 01), 128-138

***Oxygen plasma modification of submicron vapor grown carbon fibers as studied by scanning tunneling microscopy***

Author(s): J.I. Paredes, A. Martinez-Alonso, J.M.D. Tascon  
Source: Carbon, 40 (2002), 7 (June), 1101-1108

***Gelatin-pretreated carbon particles for potential use in lithium ion batteries***

Author(s): M. Bele, M. Gaberscek, R. Dominko, J. Drogenik, K. Zupan, P. Komac, K. Kocevar, I. Musevic, S. Pejovnik  
Source: Carbon, 40 (2002), 7 (June), 1117-1122

***Adlayer structure of P2VB on iodine-modified Au(111) in solution***

Author(s): G.-Z. Yang, Q.-D. Zeng, L.-J. Wan, C.-L. Bai  
Source: Surface Science, 511 (2002), 1-3 (June), L298-L302

***Mechanism of initial structure formation on highly doped n-Si (111)***

Author(s): H. Jungblut, J. Jakubowicz, S. Schweizer, H.J. Lewerenz  
Source: Journal of Electroanalytical Chemistry, 527 (2002), 1-2 (May 31), 41 - 46

***Characteristics of transparent and conductive undoped ZnO thin films obtained by chemical spray using zinc pentanedionate***

Author(s): M.d.l.L. Olvera, A. Maldonado, R. Asomoza, S. Tirado-Guerra  
Source: Thin Solid Films, 411 (2002), 2 (May 31), 198-202

***RF-magnetron-sputtered heteroepitaxial YSZ and CeO<sub>2</sub>/YSZ/Si(001) thin films with improved capacitance-voltage characteristics***

Author(s): N. Wakiya, M. Yoshida, T. Kiguchi, K. Shinozaki, N. Mizutani  
Source: Thin Solid Films, 411 (2002), 2 (May 31), 268-273

***Control of surface morphology of ZnO (0001) by hydrochloric acid etching***

Author(s): H. Maki, T. Ikoma, I. Sakaguchi, N. Ohashi, H. Haneda, J. Tanaka, N. Ichinose  
Source: Thin Solid Films, 411 (2002), 1 (May 22), 91-95

***AFM surface imaging of thermally oxidized hydrogenated crystalline silicon***

Author(s): A. Szekeres, P. Lytvyn, S. Alexandrova  
Source: Applied Surface Science, 191 (2002), 1-4 (May 17), 148-152

***Behaviour of ionized metal plasma deposited Ta diffusion barrier between Cu and SiO<sub>2</sub>***

Author(s): Khin Maung Latt, H.S. Park, S. Li, Liu Rong, T. Osipowicz, W.G. Zhu, Y.K. Lee  
Source: Journal of Materials Science (full set), 37 (2002), 10 (May 15), 1941-1949

***Electrochemical and X-ray scattering study of well defined RuO<sub>2</sub> single crystal surfaces***

Author(s): T.E. Lister, Y. Chu, W. Cullen, H. You, R.M. Yonco, J.F. Mitchell, Z. Nagy  
Source: Journal of Electroanalytical Chemistry, 524-525 (2002), (May 03), 201 - 218

***Can a thin film be pinned at the surface by hollows?***

Author(s): S.M.M. Ramos, B. Canut, A. Benyagoub, M. Toulemonde  
Source: Nuclear Instruments and Methods in Physics Research Section B: Beam Interactions with Materials and Atoms, 191 (2002), 1-4 (May), 456-461

***Surface instability and associated roughness during conventional and pendeo-epitaxial growth of GaN(0001) films via MOVPE***

Author(s): A.M. Roskowski, P.Q. Miraglia, E.A. Preble, S. Einfeldt, R.F. Davis  
Source: Journal of Crystal Growth, 241 (2002), 1-2 (May), 141-150

***PIXE and RBS investigation of growth phases of ultra-thin chemical bath deposited CdS films***

Author(s): P.C. Duncan, S. Hinckley, E.A. Gluszak, N. Dytlewski  
Source: Nuclear Instruments and Methods in Physics Research Section B: Beam Interactions with Materials and Atoms, 190 (2002), 1-4 (May), 615-619

***Analysis of Laser Irradiated Organo-Platinum Films***

Author(s): Marcus R. Davidson, Yongchang Fan, Graham J. Berry, James A. Cairns, Alexander G. Fitzgerald  
Source: Mikrochimica Acta, 139 (2002), 1-4 (May), 43-48

***The effect of pressure control on a thermally stable a-C:N thin film with low dielectric constant by electron cyclotron resonance-plasma***

Author(s): X.W. Liu, J.H. Lin, W.J. Jong, H.C. Shih  
Source: Thin Solid Films, 409 (2002), 2 (April 30), 178-184

***Electrical properties of reactively sputtered WO<sub>3</sub> thin films as ozone gas sensor***

Author(s): K. Aguir, C. Lemire, D.B.B. Lollman  
Source: Sensors and Actuators B: Chemical, 84 (2002), 1 (April 30), 1-5

***Reactive R.F. magnetron sputtering deposition of WO<sub>3</sub> thin films***

Author(s): C. Lemire, D.B.B. Lollman, A. Al Mohammad, E. Gillet, K. Aguir  
Source: Sensors and Actuators B: Chemical, 84 (2002), 1 (April 30), 43-48

***Deposition of titania thin films from aqueous solution by a continuous flow technique***

Author(s): Tobias M. Fuchs, Rudolf C. Hoffmann, Thomas P. Niesen, Hannah Tew, Joachim Bill and Fritz Aldinger  
Source: Journal of Materials Chemistry, 12 (2002), 5 (April 19), 1597-1601

***Optical properties of copper phthalocyanine***

Author(s): A.B. Djuricic, C.Y. Kwong, T.W. Lau, W.L. Guo, E.H. Li, Z.T. Liu, H.S. Kwok, L.S.M. Lam, W.K. Chan  
Source: Optics Communications, 205 (2002), 1-3 (April 15), 155-162

***MFM imaging of patterned permalloy elements under an external applied field***

Author(s): J.M. Garca, A. Thiaville, J. Miltat, K.J. Kirk, J.N. Chapman  
Source: Journal of Magnetism and Magnetic Materials, 242-245 (2002), (April), 1267-1269

***Effect of Cr and Ta buffers on hard magnetic Nd<sub>2</sub>Fe<sub>14</sub>B films***

Author(s): U. Hannemann, S. Fahler, S. Oswald, B. Holzapfel, L. Schultz  
Source: Journal of Magnetism and Magnetic Materials, 242-245 (2002), (April), 1294-1296

***Spray pyrolysis growth and material properties of In<sub>2</sub>O<sub>3</sub> films***

Author(s): J. Joseph Prince, S. Ramamurthy, B. Subramanian, C. Sanjeeviraja, M. Jayachandran  
Source: Journal of Crystal Growth, 240 (2002), 1-2 (April), 142-151

***Sign reversal of the magnetic anisotropy in La<sub>0.7</sub>A<sub>0.3</sub>MnO<sub>3</sub> (A=Ca, Sr, Ba, #) films***

Author(s): M. Ziese, H.C. Semmelhack, P. Busch  
Source: Journal of Magnetism and Magnetic Materials, 246 (2002), 1-2 (April), 327-334

***Crystallographic orientation dependence of impurity incorporation during epitaxial lateral overgrowth of InP***

Author(s): Y.T. Sun, S. Anand, S. Lourudoss  
Source: Journal of Crystal Growth, 237-239 (2002), (April), 1418-1422

***Characterization of Ba(Zr<sub>0.2</sub>Ti<sub>0.8</sub>)O<sub>3</sub> thin films deposited by RF-magnetron sputtering***

Author(s): W.S. Choi, B.S. Jang, D.-G. Lim, J. Yi, B. Hong  
Source: Journal of Crystal Growth, 237-239 (2002), (April), 438-442

***Structural, morphology and electrical studies on ferroelectric bismuth titanate thin films prepared by sol-gel technique***

Author(s): N.V. Giridharan, S. Madeswaran, R. Jayavel  
Source: Journal of Crystal Growth, 237-239 (2002), (April), 468-472

***Preparation of superconducting epitaxial thin films of transition metal nitrides on silicon wafers by molecular beam epitaxy***

Author(s): K. Inumaru, H. Okamoto, S. Yamanaka  
Source: Journal of Crystal Growth, 237-239 (2002), (April), 2050-2054

***Magnetization reversal in micron-size negative dot arrays in permalloy film***

Author(s): P. Vavassori, G. Gubbiotti, G. Zangari, C.T. Yu, H. Yin, H. Jiang, G.J. Mankey  
Source: Journal of Magnetism and Magnetic Materials, 242-245 (2002), (April), 585-587

***Dielectric and ferroelectric response of sol-gel derived  $Pb_{0.85}La_{0.15}TiO_3$  ferroelectric thin films on different bottom electrodes***

Author(s): S. Bhaskar, S.B. Majumder, P.S. Dobal, S.B. Krupanidhi, R.S. Katiyar  
Source: Thin Solid Films, 406 (2002), 1-2 (March 01), 30-39

***Morphology and dielectric properties of  $Ba_{0.5}Sr_{0.5}TiO_3$  thin films on annealed (100) MgO***

Author(s): E.J. Cukauskas, S.W. Kirchoefer, W. Chang  
Source: Journal of Crystal Growth, 236 (2002), 1-3 (March), 239-247

***Influence of the concentration of  $Sb_2O_3$  and the viscosity of the precursor solution on the electrical and optical properties of  $SnO_2$  thin films produced by the Pechini method***

Author(s): M.I.B. Bernardi, L.E. Soledade, I.A. Santos, E.R. Leite, E. Longo, J.A. Varela  
Source: Thin Solid Films, 405 (2002), 1-2 (February 22), 228-233

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Author(s): D. Besana, A. Borghesi, M. Campione, A. Sassella, R. Tubino, M. Moret, R. Rinaldi, F. Garnier  
Source: Journal of Crystal Growth, 235 (2002), 1-4 (February), 241-247

***Electrochemical behaviour of Ni + Al alloy as an alternative material for molten carbonate fuel cell cathodes***

Author(s): T. Kudo, Y. Hisamitsu, K. Kihara, M. Mohamedi, I. Uchida  
Source: Journal of Applied Electrochemistry, 32 (2002), 2 (February), 179-184

***Influence of annealing atmosphere and temperature on photoluminescence of  $Tb^{3+}$  or  $Eu^{3+}$ -activated zinc silicate thin film phosphors via sol-gel method***

Author(s): Q.Y. Zhang, K. Pita, W. Ye, W.X. Que  
Source: Chemical Physics Letters, 351 (2002), 3-4 (January 10), 163-170

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Author(s): C.-H. Shim, D.-S. Lee, S.-I. Hwang, M.-B. Lee, J.-S. Huh, D.-D. Lee  
Source: Sensors and Actuators B: Chemical, 81 (2002), 2-3 (January 05), 176-181

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Author(s): L. Meda, R.C. Bretkopf, T.E. Haas, R.U. Kirss  
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Author(s): E.D. Mishina, N. Ohta, Q.-K. Yu, S. Nakabayashi  
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Author(s): J.-P. Zhang, S.-Y. Zhou, P. Chen, O. Tsuneki, H. Masaaki  
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***Investigation of growth modes of cadmium mercury thiocyanate crystal by atomic force microscopy***

Author(s): X.N. Jiang, D.L. Sun, D. Xu, D.R. Yuan, M.K. Lu, S.Y. Guo, Q. Fang  
Source: Journal of Crystal Growth, 233 (2001), 1-2 (November), 196-207

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Author(s): A. Rosenfeldt, M. Florsheimer  
Source: Applied Physics B: Lasers and Optics, 73 (2001), 5-6 (October), 523-529

***A successive dry-wet process for fabricating conductive thin film of bis(ethylenedithio)tetrathiafulvalene salt***

Author(s): Y.F. Miura, G.E.M. Tovar, S. Ohnishi, M. Hara, H. Sasabe, W. Knoll

Source: Thin Solid Films, 393 (2001), 1-2 (August 01), 225-230

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Author(s): P.W. Leech, G.K. Reeves, A. Holland

Source: Journal of Materials Science (full set), 36 (2001), 14 (July 15), 3453-3459

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Author(s): T. Sawaguchi, Y. Sato, F. Mizutani

Source: Journal of Electroanalytical Chemistry, 507 (2001), 1-2 (July 13), 256 - 262

***Effects of additives and chelating agents on electroless copper plating***

Author(s): Y.-M. Lin, S.-C. Yen

Source: Applied Surface Science, 178 (2001), 1-4 (July 02), 116-126

***Electrochemical scanning tunneling microscope study of irreversibly adsorbed Te on a Pt(111) single crystal electrode surface***

Author(s): C.K. Rhee, D.-K. Kim

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***Effect of surface structure on photosensitivity in chemically deposited PbS thin films***

Author(s): E.M. Larramendi, O. Calzadilla, A. Gonzalez-Arias, E. Hernandez, J. Ruiz-Garcia

Source: Thin Solid Films, 389 (2001), 1-2 (June 15), 301-306

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Author(s): C. Marliere, F. Despetis, P. Etienne, T. Woignier, P. Dieudonne, J. Phalippou

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Author(s): M. Massi, H. S. Maciel, C. Otani, R. D. Mansano, P. Verdonck

Source: Journal of Materials Science: Materials in Electronics, 12 (2001), 4/6 (June), 343-346

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Author(s): H. Kawasaki, N. Yamaguchi, K. Terashima

Source: Thin Solid Films, 386 (2001), 2 (May 15), 305-309

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Author(s): Y. Sui, X. Yu, J. Yin, X. Zhong, Q. Li, Y. Chen, Z. Zhu, Z. Wang

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***Nucleation and growth mechanism for the electropolymerization of aniline on highly oriented pyrolytic graphite at higher potentials***

Author(s): B.J. Hwang, R. Santhanam, C.R. Wu, Y.W. Tsai

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***Multiscale magnetic domains observed in die-upset melt-spun magnets using magnetic force microscopy***

Author(s): D.C. Crew, L.H. Lewis, V. Panchanathan

Source: Journal of Magnetism and Magnetic Materials, 231 (2001), 1 (May 02), 57-64

***Domain structure of (100) strontium bismuth tantalate (SBT) SrBi<sub>2</sub>Ta<sub>2</sub>O<sub>9</sub> films***

Author(s): C.E. Zybilla, H. Boubekeur, B. Li, F. Koch, G. Schindler, C. Dehm

Source: Thin Solid Films, 386 (2001), 1 (May 01), 59-67

***Study of the dielectric and ferroelectric properties of chemically processed Ba<sub>x</sub>Sr<sub>1-x</sub>TiO<sub>3</sub> thin films***

Author(s): F.M. Pontes, E. Longo, E.R. Leite, J.A. Varela

Source: Thin Solid Films, 386 (2001), 1 (May 01), 91-98

***Substrate preparations in epitaxial ZnO film growth***

Author(s): S. Zhu, C.-H. Su, S.L. Lehoczky, M.T. Harris, M.J. Callahan, P. McCarty, M.A. George

Source: Journal of Crystal Growth, 225 (2001), 2-4 (May), 190-196

***Above bandgap induced photoexpansion and photobleaching in Ga-Ge-S based glasses***

Author(s): S.H. Messaddeq, M. Siu Li, D. Lezal, S.J.L. Ribeiro, Y. Messaddeq

Source: Journal of Non-Crystalline Solids, 284 (2001), 1-3 (May), 282-287

***Formation and stability of lanthanum oxide thin films deposited from b-diketonate precursor***

Author(s): M. Nieminen, M. Putkonen, L. Niinisto

Source: Applied Surface Science, 174 (2001), 2 (April 16), 155-166

***Photoelectric response of a gold electrode modified with self-assembled monolayers of pyrrolidinofullerenes***

Author(s): Sheng Zhang, Dong Dong, Liangbing Gan, Zhongfan Liu, Chunhui Huang

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Author(s): Hiroki Hara, Ikuzo Nishiguchi, Seiki Sugi, Shigeru Tsuboi

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Author(s): S.O. Kucheyev, J.S. Williams, J. Zou, C. Jagadish, G. Li

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Author(s): L.G. Jacobsohn, F.L. Freire

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***The effects of surface treatment on metal hydride electrodes using a weak acid solution containing Ni(II)***

Author(s): J. Nan, Y. Yang, Z. Lin

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Author(s): S. Uma, A. D. McConnell, M. Asheghi, K. Kurabayashi, K. E. Goodson

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Author(s): V.H. Nguyen, A.J. Hof, H. van Kranenburg, P.H. Woerlee, F. Weimar

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***Preparation and Characterizations of TiO<sub>2</sub>/Organically Modified Silane Composite Materials Produced by the Sol-Gel Method***

Author(s): Wenxiu Que, Y. Zhou, Y.L. Lam, Y.C. Chan, C.H. Kam

Source: Journal of Sol-Gel Science and Technology, 20 (2001), 2 (February), 187-195

***Study of Si(1 0 0) surfaces etched in TMAH solution***

Author(s): K. Sakaino, S. Adachi

Source: Sensors and Actuators A: Physical, 88 (2001), 1 (January 20), 71-78

***Growth of Nb thin films on SiO<sub>2</sub>***

Author(s): B. Li, I. Kojima

Source: Applied Surface Science, 169-170 (2001), (January 15), 371-374

***High oriented epitaxial oligomer/fullerene structures grown by hot wall epitaxy***

Author(s): A.Y. Andreev, G. Matt, H. Sitter, C.J. Brabec, D. Badt, H. Neugebauer, N.S. Sariciftci

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***AFM, SEM, EDX and HRTEM study of the crystalline growth rate anisotropy-induced internal stress and surface roughness of YBaCuO thin film***

Author(s): F. Pailloux, R.J. Gaboriaud, C. Champeaux, A. Catherinot

Source: Materials Characterization, 46 (2001), 1 (January), 55-63

***Effect of V/III ratio and PH<sub>3</sub> annealing on InAs dots grown by MOVPE on InP(001) step-bunched surfaces***

Author(s): V. Souliere, H. Dumont, L. Auvray, Y. Monteil

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Author(s): Ch. Jonda, A. B. R. Mayer, U. Stolz, A. Elschner, A. Karbach

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***Single-step fabrication of diffraction gratings on hybrid sol-gel glass using holographic interference lithography***

Author(s): H.J. Jiang, X.-C. Yuan, Y. Zhou, Y.C. Chan, Y.L. Lam

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Author(s): R. Cheung, J. Hay, E. van der Drift, W. Gao

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***The formation of pyrochlore potassium tantalate thin films by soft solution processing***

Author(s): Z. Wu, M. Yoshimura

Source: Thin Solid Films, 375 (2000), 1-2 (October 31), 46-50

***Sol-gel derived nanocrystalline thin films of PbTiO<sub>3</sub> on glass substrate***

Author(s): S.D. Cheng, C.H. Kam, Y. Zhou, W.X. Que, Y.L. Lam, Y.C. Chan, W.S. Gan

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***Formation and electrical properties of LB films based on N-hexadecylpyridinium-Cd (dmit)<sub>2</sub>***

Author(s): Y. Xu, H. Li, Y. Liu, G. Tan, D. Zhu, X. Yu

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Author(s): B. Basnar, J. Schnoller, K. Föttinger, G. Friedbacher, U. Mayer, H. Hoffmann, L. Fabry

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Author(s): M. Mwamburi, E. Wackelgard, A. Roos

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***Effect of dissolved oxygen on etching process of Si(111) in 2.5% NH<sub>3</sub> solution***

Author(s): H. Fukidome, M. Matsumura

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Author(s): H. Jiang, W. Su, J. Hazel, J.T. Grant, V.V. Tsukruk, T.M. Cooper, T.J. Bunning

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Author(s): U. Memmert, A.N. Müller, U. Hartmann

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***Pattern metallization on diamond thick film substrate***

Author(s): J. Wang, H. Chen, Y. Bai, X. Lu, Z. Jin

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Author(s): J.W. Klaus, S.J. Ferro, S.M. George

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Author(s): T. Nishide, S. Honda, M. Matsuura, M. Ide

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Author(s): T. Sumiyoshi, I. Takahashi, Y. Tsuboi, H. Miyasaka, A. Itaya, T. Asahi, H. Masuhara

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***Electroless plating of palladium and copper on polyaniline films***

Author(s): Z.H. Ma, K.L. Tan, E.T. Kang

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Author(s): T. Tsubota, M. Ohta, K. Kusakabe, S. Morooka, M. Watanabe, H. Maeda

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Author(s): K. Szot, W. Speier, MPawelczyk, J. Kwapuliński, J. Hulliger, H. Hesse, U. Breuer, W. Quadackers

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Author(s): L.L. Cheng, Y.H. Yu, B. Sundaravel, E.Z. Luo, S. Lin, Y.M. Lei, C.X. Ren, W.Y. Cheung, S.P. Wong, J.B. Xu, I.H. Wilson

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Author(s): S.P. Wong, M.F. Chiah, W.Y. Cheung, N. Ke, J.B. Xu, X.X. Zhang

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Author(s): E.W. Bohannon, C.C. Jaynes, M.G. Shumsky, J.K. Barton, J.A. Switzer

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Author(s): Dave H.A. Blank, Guus J.H.M. Rijnders, Gertjan Koster, Horst Rogalla

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Author(s): R.M. Montoreali, S. Bigotta, M. Piccinini, M. Giammatteo, P. Picozzi, S. Santucci

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Author(s): M.K. Fung, K.H. Lai, H.L. Lai, C.Y. Chan, N.B. Wong, I. Bello, C.S. Lee, S.T. Lee

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Author(s): Wenxiu Que, Y. Zhou, Y.L. Lam, Y.C. Chan, S.D. Cheng, Z. Sun, C.H. Kam

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Author(s): Peikang Shen, Ning Chi, Kwong-Yu Chan

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Author(s): F. Czerwinski, J. A. Szpunar

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***Domain observation and transition from giant magneto-resistance to anisotropy magneto-resistance in  $Ag_{1-x}(Ni_{0.8}Co_{0.2})_x$  granular films***

Author(s): G. Ni, H. Sang, F. Wang, X.B. Yin, Y.W. Du

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***High-quality ZnO/GaN/Al<sub>2</sub>O<sub>3</sub> heteroepitaxial structure grown by LP-MOCVD***

Author(s): B. Zhao, H. Yang, G. Du, G. Miao, Y. Zhang, Z. Gao, T. Yang, J. Wang, W. Li, Y. Ma, X. Yang, B. Liu, D. Liu, X. Fang

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Author(s): L.L. Daz-Flores, R. Ramirez-Bon, A. Mendoza-Galvan, E. Prokhorov, J. Gonzalez-Hernandez  
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***Epitaxial growth and properties of MBE-grown ferromagnetic Co-doped TiO<sub>2</sub> anatase films on SrTiO<sub>3</sub>(001) and LaAlO<sub>3</sub>(001)***

Author(s): S.A. Chambers, C.M. Wang, S. Thevuthasan, T. Droubay, D.E. McCready, A.S. Lea, V. Shutthanandan, C.F. Windisch Jr  
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Author(s): B.H. Flowers, T.L. Wade, J.W. Garvey, M. Lay, U. Happek, J.L. Stickney  
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Author(s): B. Zhang, W. Fang, D. Wang, F. Luan, S. Xu, Y. Qian, X. Zhu, X. Ma  
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Author(s): M. Morra, C. Cassinelli, G. Cascardo, P. Cahalan, L. Cahalan, M. Fini, R. Giardino  
Source: Biomaterials, 24 (2003), 25 (November), 4639-4654

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Author(s): T. Yoshinobu, J. Suzuki, H. Kurooka, W.C. Moon, H. Iwasaki  
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Author(s): S. Sek, R. Moszynski, A. Sepiol, A. Misicka, R. Bilewicz  
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Author(s): J.-X. Liu, D.-Z. Yang, F. Shi, Y.-J. Cai  
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Author(s): M. Mondon, S. Berger, C. Ziegler  
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Author(s): Takashi Sagawa, Ryota Sueyoshi, Mikako Kawaguchi, Mayu Kudo, Hirotaka Ihara, Katsutoshi Ohkubo  
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Author(s): G.-J. Su, S.-X. Yin, L.-J. Wan, J.-C. Zhao, C.-L. Bai  
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Author(s): M. Winkelmann, J. Gold, R. Hauert, B. Kasemo, N.D. Spencer, D.M. Brunette, M. Textor  
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Author(s): Jennifer C. Hooton, Caroline S. German, Stephanie Allen, Martyn C. Davies, Clive J. Roberts, Saul J.B. Tendler, Philip M. Williams  
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Author(s): J. Fahlen, L. Salmen  
Source: Journal of Materials Science (full set), 38 (2003), 1 (January 01), 119-126

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Author(s): J. Chan, Z. Huang, M.E. Merrifield, M.T. Salgado, M.J. Stillman

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Author(s): Christoph Lohbach, Udo Bakowsky, Carsten Kneuer, Dieter Jahn, Thomas Graeter, Hans-Joachim Schafers, Claus-Michael Lehr

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Author(s): K. Tsunoda, D. Kumaki, T. Takahashi, H. Yajima, T. Ishii, H. Itoh

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Author(s): N. Maeda, T.J. Senden, J.-M. di Meglio

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Author(s): T. Miyazaki, H.-M. Kim, T. Kokubo, C. Ohtsuki, H. Kato, T. Nakamura

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Author(s): L. Henke, N. Nagy, U.J. Krull

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Author(s): A.L. Lewis, L.A. Tolhurst, P.W. Stratford

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Author(s): M. Kokkoris, C.C. Trapalis, S. Kossionides, R. Vlastou, B. Nsouli, R. Grotzschel, S. Spartalis, G. Kordas, T. Paradellis

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Author(s): P.X. Wu, Z.W. Liao, H.F. Zhang, J.G. Guo

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Author(s): G.A. Hutcheon, C. Messiou, R.M. Wyre, M.C. Davies, S. Downes

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Author(s): Robert E. Gyurcsanyi, Alessandra Cristalli, Geza Nagy, Livia Nagy, Cara Corder, Bradford D. Pendley, Stefan Ufer, H. Troy Nagle, Michael R. Neuman, E. Lindner

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Author(s): L.S. Pinheiro, M.L.A. Temperini

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Author(s): M. Hamdi, S. Hakamata, A.M. Ektessabi

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Author(s): E. Broitman, W. Macdonald, N. Hellgren, G. Radnoczi, Z. Czigany, A. Wennerberg, M. Jacobsson, L. Hultman

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Author(s): J.J. De Yoreo, T.A. Land

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Author(s): J. Huang, S.N. Jayasinghe, S.M. Best, M.J. Edirisinghe, R.A. Brooks, W. Bonfield

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Author(s): S. Han, J.H. Lin, G.H. Wang, H.C. Shih

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Author(s): T. Itoh, K. Kataoka, T. Suga

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Author(s): M.C. Salvadori, A.M.P. Passaro, M. Cattani

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Author(s): L. Guzzi, G. Peto, A. Beck, Z. Paszti

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Author(s): S. Hofmann, J. Robertson, C. Ducati, R.E. Dunin-Borkowski

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Author(s): O. Céspedes, M.S. Ferreira, S. Sanvito, M. Kociak, J.M.D. Coey

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Author(s): U. Schlecht, M. Knez, V. Duppel, L. Kienle, M. Burghard

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Author(s): Y. Xie, C. Yuan

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Author(s): B. Satpati, D.K. Goswami, U.D. Vaishnav, T. Som, B.N. Dev, P.V. Satyam

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Author(s): H.-w. Zhang, T.-y. Zhao, C.-b. Rong, S.-y. Zhang, B.-s. Han, B.-g. Shen

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Author(s): Kasper Norgaard, Markus J. Weygand, Kristian Kjaer, Mathias Brust, Thomas Bjornholm

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Author(s): Kuk Ro Yoon, Young Shik Chi, Kyung-Bok Lee, Jungkyu K. Lee, Dong Jin Kim, Young-Joo Koh, Sang-Woo Joo, Wan Soo Yun, Insung S. Choi

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Author(s): Y. Matsuura, S. Miura, H. Naito, H. Inoue, K. Matsukawa

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Author(s): J.D. Carey, L.L. Ong, S.R.P. Silva

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Author(s): A. Gutierrez-Llorente, R. Perez-Casero, B. Pajot, J. Roussel, R.M. Defourneau, D. Defourneau, J.L. Fave, E. Millon, J. Perriere

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Author(s): J.-B.D. Green

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Author(s): T. Miyagi, M. Kamei, T. Ogawa, T. Mitsuhashi, A. Yamazaki, T. Sato

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Author(s): M.D. Lay, K. Varazo, N. Srisook, J.L. Stickney

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Author(s): S.M.M. Ramos, E. Charlaix, A. Benyagoub

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Author(s): Y. Sawai, M. Suzuki, K. Murakoshi, Y. Nakato

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Author(s): Peter J. Cumpson, John Hedley, Peter Zhdan

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Author(s): A. Dereux, Ch Girard, C. Chicanne, G. Colas des Francs, T. David, E. Bourillot, Y. Lacroute, J.C. Weeber

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Author(s): J. Noh, E. Ito, T. Araki, M. Hara

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Author(s): J. Dogel, W. Freyland

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Author(s): F. Frost, B. Rauschenbach

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Author(s): E. Barborini, I.N. Kholmanov, A.M. Conti, P. Piseri, S. Vinati, P. Milani, C. Ducati

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Author(s): N.D.S. Mohallem, L.M. Seara

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Author(s): N. Bouropoulos, J. Moradian-Oldak

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Author(s): S.-L. Xu, S.-Z. Kang, J. Lu, Y.-H. Liu, C. Wang, L.-J. Wan, C.-L. Bai

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Author(s): J. Jakubowicz

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Author(s): M. Schreck, T. Bauer, S. Gsell, F. Hormann, H. Bielefeldt, B. Stritzker

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Author(s): Cullen T. Vogelson, Andrea Keys, Christopher L. Edwards, Andrew R. Barron

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Author(s): M.D. Cooke, D.A. Allwood, D. Atkinson, G. Xiong, C.C. Faulkner, R.P. Cowburn

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Author(s): M.-C. Kan, J.-L. Huang, J.C. Sung, K.-H. Chen, B.-S. Yau

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Author(s): Nobuyoshi Miyamoto, Hisao Yamamoto, Ryozi Kaito, Kazuyuki Kuroda

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Author(s): G. Schitter, A. Stemmer

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Author(s): L. Maya, C.H. Chen, K.A. Stevenson, E.A. Kenik, S.L. Allman, T.G. Thundat

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Author(s): Jun Lu, Qing-dao Zeng, Chen Wang, Qi-yu Zheng, Lijun Wan, Chunli Bai

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Author(s): Y. Suda, T. Ono, M. Akazawa, Y. Sakai, J. Tsujino, N. Homma

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Author(s): Kimberly A. Defriend, Andrew R. Barron

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Author(s): M. Rasa, B.W.M. Kuipers, A.P. Philipse  
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Author(s): Frank Hennrich, Sergei Lebedkin, Sharali Malik, Joseph Tracy, Matthias Barczewski, Harald Rosner, Manfred Kappes  
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Author(s): T. Gotoh, K. Sugawara, K. Tanaka  
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Author(s): T. Sumomogi, M. Nakamura, T. Endo, T. Goto, S. Kaji  
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Author(s): S. Lou, J. Gao, X. Xiao, X. Li, G. Li, Y. Zhang, M. Li, J. Sun, X. Li, J. Hu  
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Author(s): Mirwais Aktary, Mark T. McDermott, Gerald A. McAlpine  
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Author(s): M.J. Kramer, L.H. Lewis, L.M. Fabietti, Y. Tang, W. Miller, K.W. Dennis, R.W. McCallum  
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Author(s): C.D. Lokhande, B.R. Sankapal, R.S. Mane, H.M. Pathan, M. Muller, M. Giersig, H. Tributsch, V. Ganeshan  
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Author(s): M. Demand, M. Hehn, R.L. Stamps, C. Meny, K. Ounadjela  
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Author(s): R.S. Cataliotti, G. Compagnini, C. Crisafulli, S. Minico, B. Pignataro, P. Sassi, S. Scire  
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Author(s): A.M. Affoune, B.L.V. Prasad, H. Sato, T. Enoki, Y. Kaburagi, Y. Hishiyama  
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Author(s): M.A. Hamon, H. Hu, P. Bhowmik, S. Niyogi, B. Zhao, M.E. Itkis, R.C. Haddon  
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Author(s): Kei Murakoshi, Takahiko Kitamura, Yoshihiro Nakato  
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Author(s): C. Becker, J. Gspann, R. Kramer  
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Author(s): Chimin Du, Bo Xu, Yuliang Li, Chen Wang, Shu Wang, Zhiqiang Shi, Hongjuan Fang, Shengxiong Xiao, Daoben Zhu

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Author(s): Sushama Pethkar, M. Aslam, I.S. Mulla, P. Ganeshan, K. Vijayamohan  
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Author(s): Yang-Su Han, In Park, Jin-Ho Choy  
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Author(s): J. Feng, L.-T. Weng, C.-M. Chan, J. Xhie, L. Li  
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Author(s): C.J. Huang, Y. Tang, D.Z. Li, B.W. Cheng, L.P. Luo, J.Z. Yu, Q.M. Wang  
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Author(s): J.N. Barisci, G.G. Wallace, R.H. Baughman  
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Author(s): Long Ba, Wei Sang Li  
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Author(s): A.K. Das, S.K. Ghose, B.N. Dev, G. Kuri, T.R. Yang  
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Author(s): M. Sundermann, J. Hartwich, K. Rott, D. Meyners, E. Majkova, U. Kleineberg, M. Grunze, U. Heinzmann  
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Author(s): P. Thevenard, J.P. Dupin, V. Thien Binh, S.T. Purcell, V. Semet, D. Guillot  
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Author(s): S. Roth, M. Burghard, G. Philipp, J. Muster, G.S. Duesberg, V. Krstic  
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Author(s): P. Umek, A. Hassanien, M. Tokumoto, D. Mihailovic  
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Author(s): Qing-Min Xu, Mei-Juan Han, Li-Jun Wan, Chen Wang, Chun-Li Bai, Bing Dai, Jin-Long Yang  
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Author(s): M.-C. Kan, J.-L. Huang, J.C. Sung, D.-F. Lii, B.-S. Yau  
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Author(s): Z.Y. Zhang, P. Jin, C.M. Li, X.L. Ye, X.Q. Meng, B. Xu, F.Q. Liu, Z.G. Wang  
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Author(s): E. Gomez, A. Labarta, A. Llorente, E. Valles  
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Author(s): X. Zhou, M. Ishida, A. Imanishi, Y. Nakato  
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Author(s): Person P. Neves, Lauro J.Q. Maia, Maria I.B. Bernardi, Antonio R. Zanatta, Valmor R. Mastelaro, Sonia M. Zanetti, Edson R. Leite  
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Author(s): M. Sheffer, A. Groysman, D. Mandler  
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Author(s): R.C. Hoffmann, S. Jia, J.C. Bartolome, T.M. Fuchs, J. Bill, P.C.J. Graat, F. Aldinger  
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Author(s): F. Dubreuil, N. Elsner, A. Fery  
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Author(s): X. Lu, Q. Lu, Z. Zhu, J. Yin, Z. Wang  
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Author(s): C.L. Schauer, M.-S. Chen, M. Chatterley, K. Eisemann, E.R. Welsh, R.R. Price, P.E. Schoen, F.S. Ligler  
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Author(s): A.P. Nascimento Filho, M.L.P. da Silva, E. Galeazzo, N.R. Demarquette  
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***Nanostructured silicon surfaces via nanoporous alumina***

Author(s): Matthias Kruse, Steffen Franzka, Gunter Schmid  
Source: *Chemical Communications*, (2003), 12 (May 30), 1333-1335

***Excimer laser induced patterning of polymeric surfaces***

Author(s): K. Callewaert, Y. Martele, L. Breban, K. Naessens, P. Vandaele, R. Baets, G. Geuskens, E. Schacht  
Source: *Applied Surface Science*, 208-209 (2003), (March 15), 218-225

***Effect of preannealing on the morphology of LiTaO<sub>3</sub> thin films prepared from the polymeric precursor method***

Author(s): A.H.M. Gonzalez, A.Z. Simoes, M.A. Zaghete, J.A. Varela  
Source: *Materials Characterization*, 50 (2003), 2-3 (March), 233-238

***High refractive index thin films of ZnS/polythiourethane nanocomposites***

Author(s): Changli Lu, Zhanchen Cui, Zuo Li, Bai Yang, Jiacong Shen  
Source: *Journal of Materials Chemistry*, 13 (2003), 3 (February 20), 526-530

***Ultrathin poly(ethylene glycol) films for silicon-based microdevices***

Author(s): S. Sharma, R.W. Johnson, T.A. Desai  
Source: *Applied Surface Science*, 206 (2003), 1-4 (February 15), 218-229

***Correlated dewetting patterns in thin polystyrene films***

Author(s): Chiara Neto, Karin Jacobs, Ralf Seemann, Ralf Blossey, Jurgen Becker, Gunther Grun  
Source: *Journal of Physics: Condensed Matter*, 15 (2003), 1 (January 15), S421-S426

***Inhibition of the surface levelling of thermosetting polyester powder coatings caused by surface tension gradients***

Author(s): Y. Zhao, J.D. Carey, N. Knoops, D. Maetens, I. Hopkinson, J.N. Hay, J.L. Keddie  
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Author(s): Martin Piech, John Y. Walz  
Source: Journal of Colloid and Interface Science, 253 (2002), 1 (September 01), 117-129

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Author(s): Christian Kruger, Ulrich Jonas  
Source: Journal of Colloid and Interface Science, 252 (2002), 2 (August 15), 331-338

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Author(s): Paolo Bertonecello, Manoj Kumar Ram, Andrea Notargiacomo, Paolo Ugo, Claudio Nicolini  
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Author(s): S.C. Jain, V.K. Tanwar, V. Dixit, S.P. Verma, S.B. Samanta  
Source: Applied Surface Science, 182 (2001), 3-4 (October 22), 350-356

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Author(s): C. Mio, T. Gong, A. Terray, D.W.M. Marr  
Source: Fluid Phase Equilibria, 185 (2001), 1-2 (July 30), 157-163

***Microstructure and electrical properties of perovskite (Pb, La)TiO<sub>3</sub> thin film deposited at low temperature by the polymeric precursor method***

Author(s): F.M. Pontes, J.H.G. Rangel, E.R. Leite, E. Longo, J.A. Varela, E.B. Araujo, J.A. Eiras  
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Author(s): C. Maims, J. Hulme, P.R. Fielden, N.J. Goddard  
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Author(s): F. Lednicky, J. Hromadkova, Z. Pientka  
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Author(s): A. Ikai, Y. Alimujiang  
Source: Applied Physics A: Materials Science & Processing, 72 (2001), 7 (March), S117-S120

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Author(s): I. Grosse, K. Estel  
Source: Colloid and Polymer Science, 278 (2000), 10 (October 05), 1000-1006

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Author(s): Jinggong Wang, K.G. Neoh, E.T. Kang, K.L. Tan  
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Author(s): G. Bar, L. Delineau, R. Brandsch, M. Ganter, M.-H. Whangbo  
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Author(s): W.-X. Yu, L. Hong, B.-H. Chen, T.-M. Ko  
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Author(s): K. Teshima, Y. Inoue, H. Sugimura, O. Takai  
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Author(s): B.J. Hwang, R. Santhanam, Y.L. Lin

Source: *Electrochimica Acta*, 46 (2001), 18 (May 31), 2843 - 2853

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Author(s): A. Rar, J.N. Zhou, W.J. Liu, J.A. Barnard, A. Bennett, S.C. Street

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Author(s): Y. Sui, D. Wang, J. Yin, Z.-k. Zhu, Z.-g. Wang

Source: *Chemical Physics Letters*, 339 (2001), 3-4 (May 11), 186-190

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Author(s): M.A. Witek, G.M. Swain

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Author(s): S.-L. Xu, S.-Z. Kang, L.-B. Gan, L. Zhang, C. Wang, L.-J. Wan, C.-L. Bai

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Author(s): P.J. Thomas, G.U. Kulkarni, C.N.R. Rao

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Author(s): Kyu-Seog Hwang, Yeon-Hum Yun, Bo-An Kang, Sang-Bok Kim, Seung-Wook Jang, Chi-Kyoon Kim, Jeong-Sun Oh

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Author(s): M. Moner-Girona, A. Roig, E. Molins, J. Llibre

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Author(s): Tonglei Li, Kenneth R Morris, Kinam Park

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Author(s): W.I. Gruszecki, M. Gagos, P. Kernen

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Author(s): M. Tani, C. Liu, P.M. Huang

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Author(s): H. Yamada, H. Yamasaki, K. Develos-Bagarinao, Y. Nakagawa, Y. Mawatari, J.C. Nie, H. Obara, S. Kosaka

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Author(s): C. Cantalini

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Author(s): D.J. Smith, D. Chandrasekhar, S.A. Chaparro, P.A. Crozier, J. Drucker, M. Floyd, M.R. McCartney, Y. Zhang

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Author(s): Sergei F. Lyuksyutov, Pavel B. Paramonov, Ivan Dolog, Robert M. Ralich  
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Author(s): C. Gatel, P. Baules, E. Snoeck  
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Author(s): Bernd Huber, Hubert Gnaser, Christiane Ziegler  
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Author(s): W.X. Que, X. Hu, Q.Y. Zhang  
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Author(s): A. Benatmane, P.C. Montgomery, E. Fogarassy, D. Zahorski  
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Author(s): D. Shen, S.Y. Au, G. Han, D. Que, N. Wang, I.K. Sou  
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***Nanoindentation study of Zn<sub>1-x</sub>Be<sub>x</sub>Se heteroepitaxial layers***

Author(s): S.E. Grillo, M. Ducarroir, M. Nadal, E. Tournie, J-P Faurie  
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Author(s): J. Xu, K. Hattori, Y. Seino, I. Kojima  
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Author(s): M. Miyauuchi, N. Kieda, S. Hishita, T. Mitsuhashi, A. Nakajima, T. Watanabe, K. Hashimoto  
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Author(s): M.J. da Silva, A.A. Quivy, P.P. Gonzalez-Borrero, E. Marega, J.R. Leite  
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Author(s): S. Datta, A. Bhattacharya, M.R. Gokhale, S.P. Pai, J. John, B.M. Arora  
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***Structure and optical properties of self-assembled InAs/GaAs quantum dots with In<sub>0.15</sub>Ga<sub>0.85</sub>As underlying layer***

Author(s): J. He, B. Xu, Z.G. Wang, S.C. Qu, F.Q. Liu, T.W. Zhu, X.L. Ye, F.A. Zhao, X.Q. Meng  
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Author(s): Y. Leconte, C. Dufour, B. Garrido, R. Rizk  
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Author(s): K. Yasui, Y. Narita, T. Inubushi, T. Akahane  
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Author(s): H. Plank, R. Resel, A. Andreev, N.S. Sariciftci, H. Sitter  
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Author(s): B. Wang, K.W. Kwok, H.L.W. Chan, C.L. Choy, K.Y. Tong, E.Z. Luo, J.B. Xu, I.H. Wilson

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Author(s): Johanna Johansson, Juhana Kostamo, Maarit Karppinen and Lauri Niinisto

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Author(s): L. Nony, T. Cohen-Bouhacina, J.-P. Aime

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Author(s): P.W. Leech, G.K. Reeves, A.S. Holland, M.C. Ridgway, F. Shanks

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Author(s): J.M. Ko, K. Lebbou, C. Dujardin, C. Pedrini, S.D. Durbin, T. Fukuda

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Author(s): Boris Mahltig, Robert Jerome, Manfred Stamm

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Author(s): S.A. Mahmoud

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Author(s): R.R. Das, W. Perez, R.S. Katiyar, S.B. Krupanidhi

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Author(s): E. Vasco, C. Zaldo, L. V?zquez

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Author(s): M. Calamiotou, N. Chrysanthakopoulos, Ch. Lioutas, K. Tsagaraki, A. Georgakilas

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Author(s): R. Hiesgen, D. Meissner, W. Schmickler

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Author(s): F.-W. Yan, W.-J. Zhang, R.-G. Zhang, L.-Q. Cui, C.-G. Liang, S.-Y. Liu

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Author(s): A. Lobo, S. Gokhale, S.K. Kulkarni

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Author(s): X. Hu, X. Yao, C.A. Peterson, D. Sarid, Z. Yu, J. Wang, D.S. Marshall, J.A. Curlless, J. Ramdani, R.

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Author(s): Jean-Francois Bresse

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Author(s): I. Pepe, A. Ferreira da Silva, R.R. Rosa, L.S. Roman, E. Veje  
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Author(s): H.J. Qi, K.B.K. Teo, K.K.S. Lau, M.C. Boyce, W.I. Milne, J. Robertson, K.K. Gleason  
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Author(s): W. Seok Choi, B. Sik Jang, Y. Roh, J. Yi, B. Hong  
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Author(s): S. Ito, H. Fujioka, H. Kiwata, T. Ikeda, M. Oshima  
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Author(s): A. Mitra, R.K. Thareja, V. Ganesan, A. Gupta, P.K. Sahoo, V.N. Kulkarni  
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Author(s): F. Fabbri, G. Padeletti, T. Petrisor, G. Celentano, V. Boffa  
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Author(s): Y. Yang, D.Z. Shen, J.Y. Zhang, X.W. Fan, Z.H. Zhen, X.W. Zhao, D.X. Zhao, Y.N. Liu  
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